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THESIS

**VHDL MODELING AND SIMULATION OF A DIGITAL
IMAGE SYNTHESIZER FOR COUNTERING ISAR**

by

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June 2003

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**VHDL MODELING AND SIMULATION OF A DIGITAL IMAGE
SYNTHESIZER FOR COUNTERING ISAR**

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ABSTRACT

This thesis discusses VHDL modeling and simulation of a full custom Application Specific Integrated Circuit (ASIC) for a Digital Image Synthesizer (DIS). The DIS synthesizes the characteristic echo signature of a pre-selected target. It is mainly used against Inverse Synthetic Aperture Radars as an electronic counter measure. The VHDL description of the DIS architecture was exported from Tanner S-Edit, modified, and simulated in Aldec Active HDL™. Simulation results were compared with C++ and Matlab simulation results for verification. Main subcomponents, a single Range Bin Processor (RBP), a cascade of 4 RBP s and a cascade of 16 RBP s were tested and verified. The overhead control circuitry, including Self Test Circuitry and Phase Extractor, was tested separately. Finally, the overall DIS was tested and verified using the control circuitry and a cascade of 4 RBP s together, representing the actual 512 RBP s. As a result of this research, the majority of the DIS was functionally tested and verified.

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EXECUTIVE SUMMARY

Synthetic aperture radars (SARs) and inverse synthetic aperture radars (ISARs) are capable of generating images of target objects even under adverse conditions when other sensors are blind. With SAR and ISAR, the ability to detect and identify a contact is greatly improved. Current electronic attack systems (such as decoys and jamming) fail to counter the identification and targeting.

The Digital Image Synthesizer (DIS) is designed to perform this task. If the target platform is able to receive, modify and re-transmit the actual radar signal sent by the ISAR/SAR, the targeting platform would not be able to distinguish between the transmitted signal and the actual radar returns echoed from the target. To do so, the signal intercepted by the target platform must be carefully and precisely manipulated in phase and amplitude such that the deception is not noticeable.

Either digital or analog methods may be used to synthesize a false target radar image. The analog methods are bulky, susceptible to noise and have limited bandwidth, which makes them impractical. A digital method has many advantages over an analog method. The major advantages are its increased bandwidth capacity and its ability to delay signals as long as necessary for a given application. With such a digital method, it is possible for a small ship to appear as large as an aircraft carrier or any high value target.

This thesis discusses modeling and functional verification of the DIS. The VHDL description of the DIS architecture was exported from Tanner S-Edit, modified, and simulated in Aldec Active HDL™. Modifications to the VHDL source code included renaming of components to comply with VHDL naming conventions and adding behavioral descriptions for some components. Simulation results were compared with C++ and Matlab simulation results for verification. Main subcomponents, a single Range Bin Processor (RBP), a cascade of 4 RBP s and a cascade of 16 RBP s were tested and verified. The overhead control circuitry, including Self Test Circuitry and Phase Extractor, was tested separately. Finally, the overall DIS was tested and verified using the control circuitry and a cascade of 4 RBP s together, representing the actual 512 RBP s. As a result of this research, the majority of the DIS was functionally tested and verified.

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I. INTRODUCTION TO DIGITAL IMAGE SYNTHESIZER (DIS)

A. BACKGROUND

The Digital Image Synthesizer (DIS) is an Application Specific Integrated Circuit (ASIC) able to generate false target images to deceive an Inverse Synthetic Aperture Radar (ISAR).

1. Inverse Synthetic Aperture Radar (ISAR)

As explained in detail in [1] and [2], ISAR is a high-resolution radar technique that can develop a two-dimensional intensity image of moving targets in the range and cross-range (Doppler) domains. ISAR imaging is used in many military applications such as target classification, recognition and identification. Surveillance systems such as the U.S. Navy AN/APS-137 ISAR and the Russian Sea Dragon maritime patrol radar use an ISAR 2-D imaging mode to provide detection, classification and tracking capability against surface and surfaced submarine targets.

Figures 1 and 2 (courtesy of the Tactical Electronic Warfare Division of the U.S. Naval Research Laboratory) show a photograph of the USS Crockett and an image of the ship obtained from a U.S. Navy AN/APS-137 ISAR. [1]



Figure 1. USS Crockett (From [1])

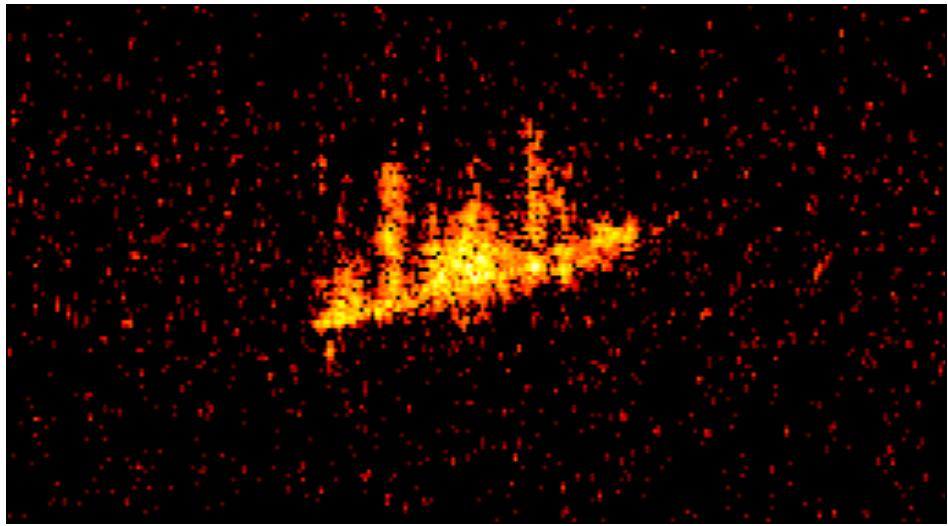


Figure 2. AN/APS-137 ISAR Image of the USS Crockett (From [1])

Explained in depth in the papers mentioned, ISAR can provide the target's range, bearing and positional data with both medium and high-resolution images for display and recording. It can also be used in launching weapon systems. For example, before a cruise missile is launched, the classification of the target may be pursued using an ISAR image. This image can be used for recognition and identification. Imaging capability is an advantage over previous technology because it improves the ability to identify the specific type of target, distinguish enemy from friend, guide the weaponry, and defeat the false target decoys. Depending on the target identification, the decision to engage the target and launch the missile is made, and only the ability to quickly confuse the ISAR targeting process will prevent the missile from being launched. [1, 2]

2. Countering ISAR and Digital Image Synthesizer (DIS)

Actions taken to confuse or deceive pre-launch weapons designation and targeting efforts are known as ‘counter targeting techniques’ and include use of low radar cross-section materials, stealth technology and pre-lock-on deception devices. Unfortunately, these techniques are ineffective against wideband imaging radars. [1]

As a result, modern wideband-imaging-ISARs create a difficult ship defense problem. [2] For example, if an adversary is using a wideband imaging ISAR, an electronic protection system cannot synthesize a false target by just transmitting a signal that emulates a radar return off a single or a few scattering surfaces. Instead, such a transmitted signal must emulate a coherent sequence of reflections with proper delay, phase, and amplitude that is similar to what would come from the multiple scattering surfaces at multiple ranges (distances from the radar) of an actual ship. Analog methods for generating false radar targets have included the use of acoustic charge transport (ACT) tapped delay lines and fiber optic tapped delay lines. ACT devices are no longer commercially available and also have limited bandwidth, making them impractical against wideband imaging radars. Optical devices are bulky and costly to manufacture, especially for the longer delay line lengths needed to synthesize a false target image of even a moderately sized ship. However, the equations and algorithms needed to digitally synthesize a false target radar image have evolved considerably over the last several years. With modern digital signal processing (DSP) techniques and advanced VLSI fabrication processes, it is now possible to digitally synthesize a realistic false target radar image of even a large warship, such as an aircraft carrier.

The digital image synthesizer reduces both the noise of the repeated signal and size of the system. [2] Compared to analog technology, it reduces the cost. The programmable design allows rapid and adaptive modifications of the system into different types of targets offering a low cost decoy capability while utilizing readily available modern digital radio frequency memories (DRFMs). Thanks to the recent advances in integrated circuit (IC) fabrication processes, such as sub micron complementary metal oxide semiconductor (CMOS) and bipolar CMOS (BiCMOS) technologies, it has become easy to achieve fast and dense custom ASICs. For these reasons, a programmable imaging architecture for countering ISARs by generating realistic false target signatures is realized with a custom digital ASIC integrated with DRFMs.

B. RELATED WORK

Many researchers have taken part in the design of the DIS chip. Initial design testing performed by Amundson [3] and Guillaume [4] is well documented in their theses. Kirin [5] designed the mask layout of the sine/cosine Lookup Table. Ozguvenc [6] created the original Range Bin Processor (RBP) design.

Le Dantec [7] evaluated the DIS performance under different parameters. Bergon [8] did the VHDL (VHSIC Hardware Description Language; VHSIC is an acronym for Very High-Speed Integrated Circuits) modeling and testing of up to 32 RBPs. Prof. Fouts provided the mask layout of the summation adder and the registers. Mattox [9] and Prof. Fouts redesigned the DIS high level architecture to use counter-clock flow pipelining. Altmeyer [10] designed the phase extraction circuit. This circuit is required to convert the ‘I’ and ‘Q’ values from the DRFM to a usable 5-bit phase value that can be processed by the RBPs. Mattox also added special clock distribution circuits to allow a daisy chain clock distribution and a self-test unit. He also created the overall mask layout in accordance with the latest technology improvements and minor modifications in the design.

For additional information regarding the background of the DIS and the theory of operation, see References [1] and [2]. For additional information regarding the original and final designs of the RBP, refer to [6] and [7], respectively.

C. PRINCIPAL CONTRIBUTIONS

Research conducted within this thesis is mainly focused on the modeling, simulation and verification of the custom ASIC DIS chip. The simulation and verification mentioned in this study and some design efforts made by other researchers were performed simultaneously. Simulations were performed with Aldec Active HDL™ versions 5.1 and 5.2. Components such as inverters, registers, pass-gates, adders, multiplexers, the single RBP, 4 RBPs, 8 RBPs, 16 RBPs, self-test and phase extraction circuitry were tested individually and a final simulation performed with all components connected together.

Figure 3 shows the task flow followed to test and to verify the DIS chip. The VHDL files were extracted directly from the schematic via Tanner Tools Pro S-Edit and

supplied by the design team. Some modifications were made in order to comply with the naming conventions of Active HDL™ and behavioral descriptions for some components were added.

The error-free VHDL code was simulated using waveform tools in Active HDL™. The data flow was traced through the pipelined structure by monitoring the values on the schematic extracted from the VHDL code. Net names in the original circuit were identified as necessary to trace any discrepancy between expected and obtained results by using Tanner Pro S-Edit.

The outputs were compared to the results obtained from Tanner T-Spice simulation results and C++ calculations of the output values, both of which were supplied by Prof. Fouts. Testing the cascade of 128 RBPs and 512 RBPs could not be conducted due to software limitations in the memory allocation process during elaboration of the simulation. Chapter V contains more information on this issue.

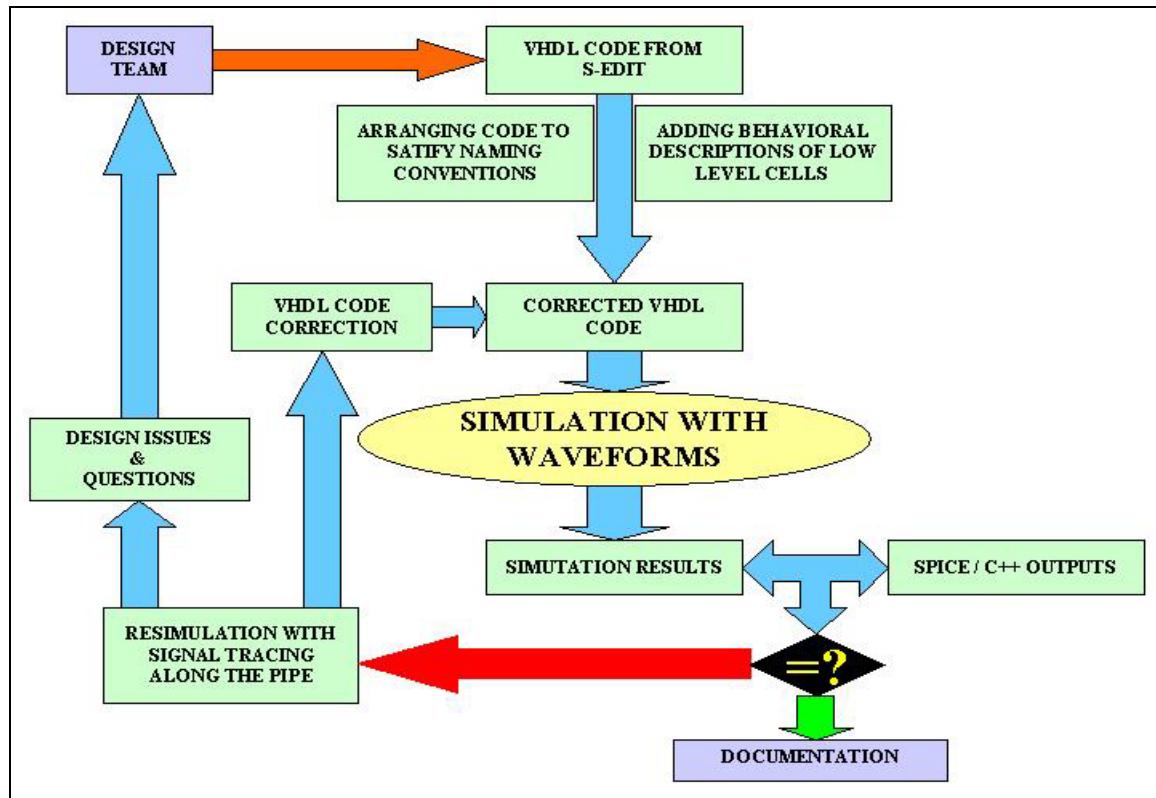


Figure 3. Testing and Verification Flow

D. THESIS OUTLINE

This thesis documents the testing and verification of the full-custom ASIC chip, including cascaded 512 range bin processors, phase extraction, self-test logic and other required circuitry.

Chapter II outlines more detailed information about the DIS chip and main components.

Chapter III presents the capabilities of VHDL as a means to design and/or verify a digital circuit design and contains some information about the software used, Aldec Active HDL™.

Chapter IV presents the simulations and the results of the low level cells used to construct the DIS chip.

Chapter V shows the simulations performed at the main functional blocks and overall DIS chip.

Chapter VI summarizes the results of the thesis, key lessons learned and recommendations for future work.

Appendix A contains the sequence of phase samples, which are generated by the Self Test Circuit to test the functionality of the DIS.

II. DIS CHIP

This chapter discusses the theory behind the idea of countering ISARs and explains the hardware implementation of the Digital Image Synthesizer (DIS). It also outlines the main functional components, such as the 512 RBP block, the Self Test Logic, the Phase Extractor and the Control Circuitry. The information on the fabrication technology is also presented.

A. THEORY

As shown in Figure 4, the DIS chip generates false target images from a series of intercepted Inverse Synthetic Aperture Radar (ISAR) chirp pulses to provide an imaging decoy capability. A Digital Radio Frequency Memory (DRFM) samples the phase and stores the intercepted ISAR pulses. An image synthesizer modulates the phase samples by synthesizing the temporal lengthening and the amplitude modulation caused by the many recessed and reflective surfaces of a target and generates a realistic Doppler profile for each surface. This digital signature is then converted into an analog signal and transmitted to the ISAR after being up-converted. [2]

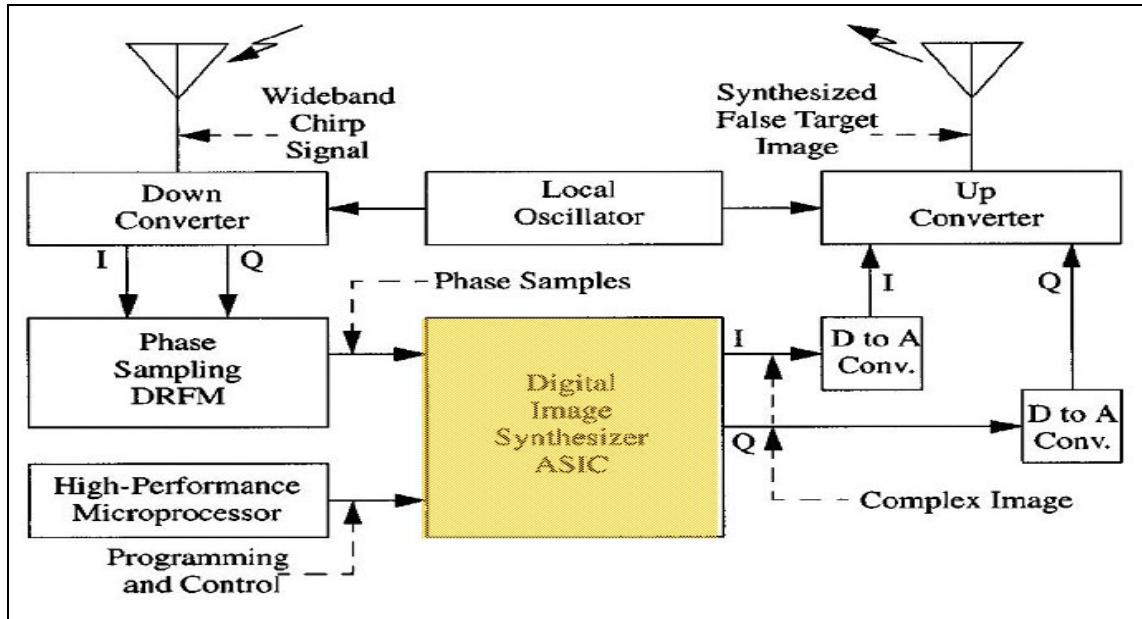


Figure 4. Overall System Block Diagram (From [2])

The DIS Application Specific Integrated Circuit (ASIC) contains a parallel array of identical complex digital modulators with one modulator for each false target range bin. Each binary phase sample is applied one at a time to the modulator array. Each range bin has a set of gain and phase coefficients that are derived from the range-Doppler description of the false target to be synthesized and a phase adder, a look-up table (LUT) and a summation adder. [2]

The single RBP data flow and implementation method are visualized in Figure 5. Each DRFM phase sample within a radar pulse is added to the phase coefficient to increment the phase and, therefore, accomplishes a phase rotation. This function is implemented with a binary adder, resulting in the desired motion profile of the range bin. In order to change the range bin's radar cross-section (RCS) characteristics, a rotated phase value is converted to a normalized complex signal (In-phase (I) and quadrature (Q)), using a lookup table (LUT). A gain circuit that multiplies the complex signal by a gain coefficient modulates the Radar Cross Section (RCS). Multiplication is implemented by left-shifting I and Q binary numbers using a parallel array of multiplexers. The last stage in the Range Bin Processor (RBP) is the summation of the gain block results with the adjacent (delayed) adder output and sending the results forward to the next RBP.

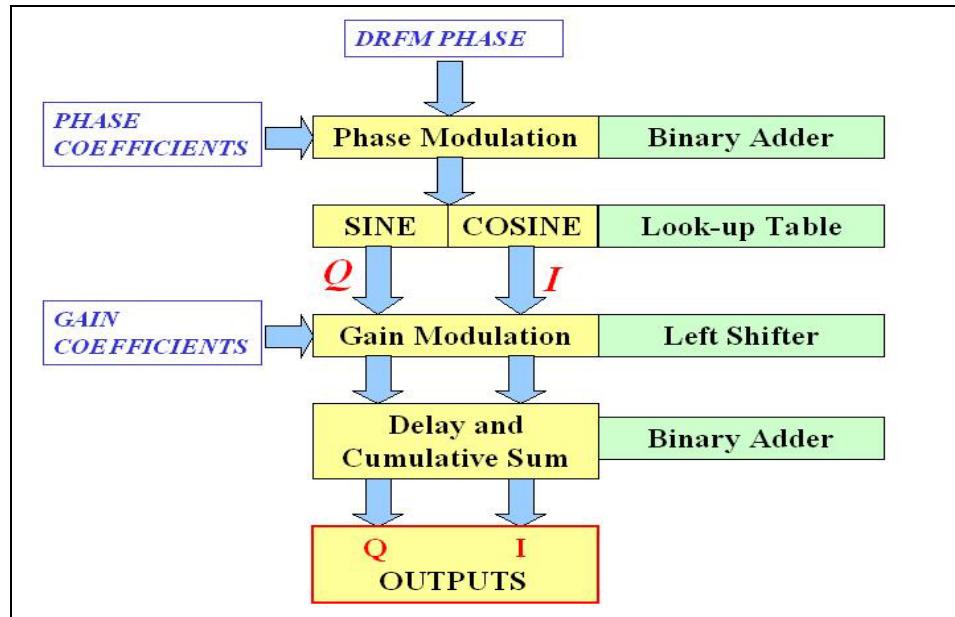


Figure 5. Single RBP Data Flow and Implementation Method

The output of the range bin processors is

$$I(m, n) = \sum_{r=0}^{N_r-1} 2^{g(r,n)} e^{i(\phi(n-r,n)+\phi_{inc}(r,n))}, \quad (2.1)$$

where $2^{g(r,n)}$ is the gain multiplication coefficient factor and $e^{i(\phi(n-r,n)+\phi_{inc}(r,n))}$ is the phase of the signal, which includes $\phi_{inc}(r,n)$, the phase increment, added by each range bin processor. [1]

Each range bin processor computes a part of the final sum. The range bins are cascaded so that each adds its individual partial sum to the partial sum of previous processors. Double buffering of the programming data allows the processors to be programmed independent of the current sum they are computing. [9]

For additional information regarding the background of the DIS and the theory of operation, refer to [1] and [2].

B. HARDWARE IMPLEMENTATION

Overall, the DIS chip consists of 512 RBP s cascaded serially, self-test, phase extraction, and programming and control logic circuitry. Figure 6 shows the overall hardware block diagram. Four different set of phase samples can be steered into the RBP block using the control and programming inputs. The clock signal flows backwards with respect to the phase sample data flow direction. Cascaded RBPs produce the final I/Q output values using the phase and gain coefficients. Each RBP should be given these values separately prior to the introduction of the phase samples.

Figure 7 shows the actual schematic capture from S-Edit. In order to find detailed information on design parameters and S-Edit design process, refer to [9].

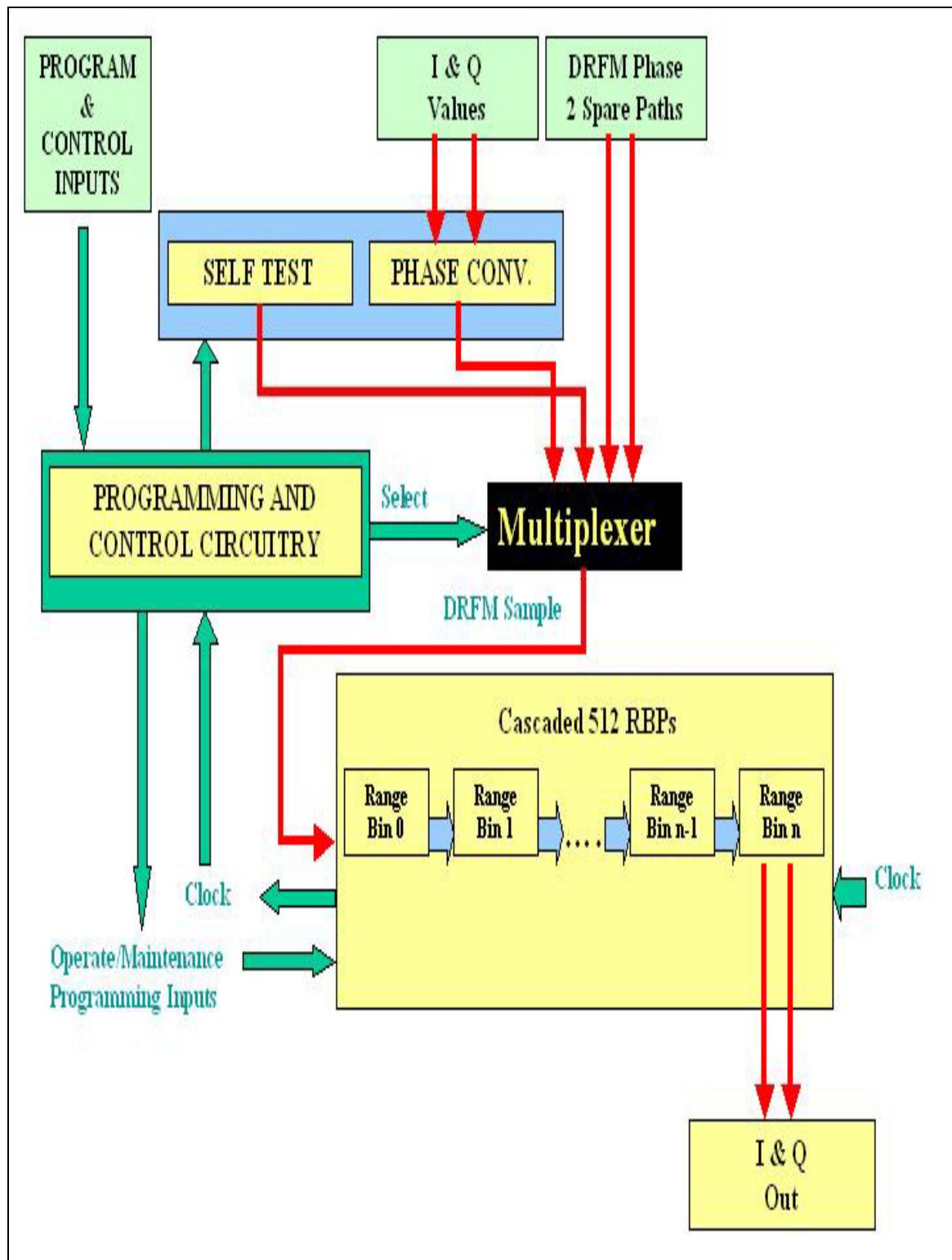


Figure 6. Whole DIS Virtual Hardware Implementation

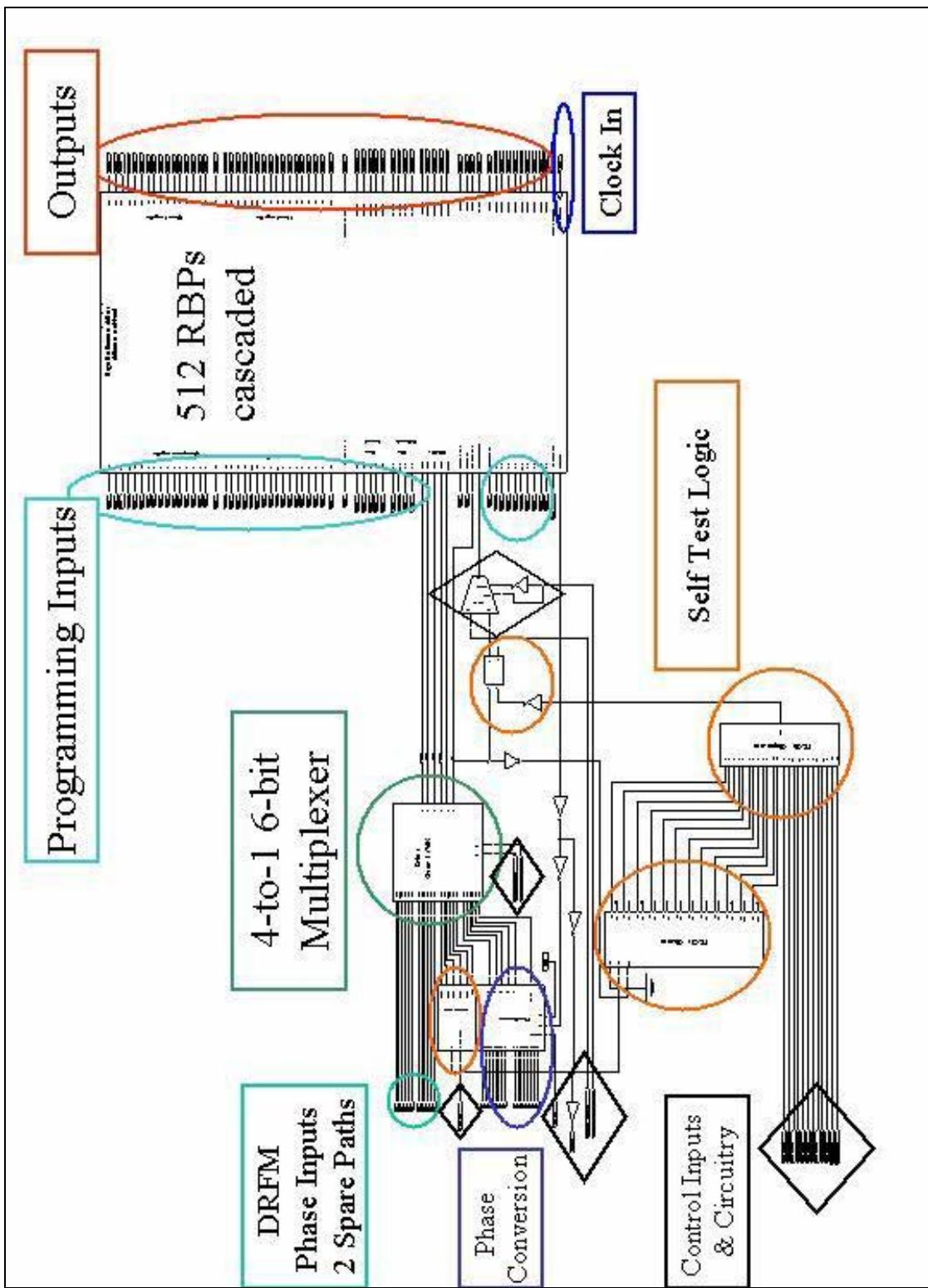


Figure 7. Complete DIS Hardware Implementation

1. 512-Range-Bin-Processor Block

This block is comprised of 512-range bin processors cascaded serially. The pipelining structure allows daisy chained clock distribution. The clock signal is propagated from the 512th RBP to the first RBP, which in turn conveys it to the phase extraction circuit and self-test circuit. As shown in Figure 8, each RBP calculates I/Q outputs and passes them to the next RBP to be added with the I/Q results from that RBP to generate the target profile.

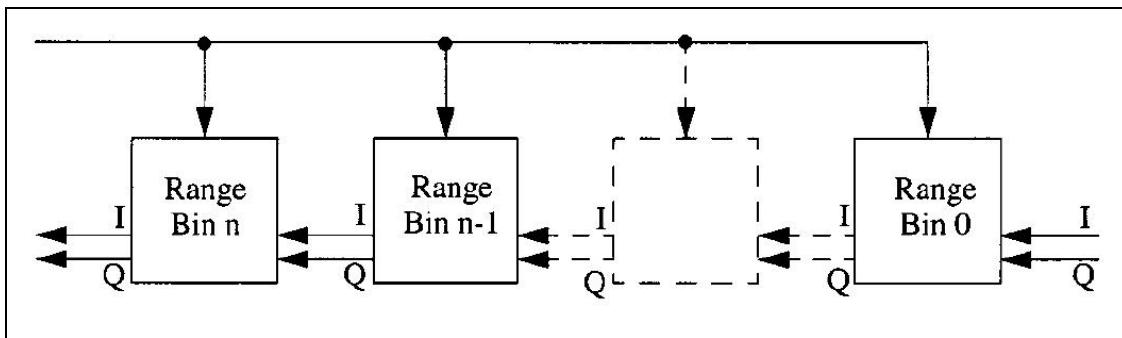


Figure 8. 512- Range-Bin-Processor Implementation (From [2])

Each Range Bin Processor is comprised of a phase adder, a look-up table (LUT), gain shifters, and final adders along with registers used for pipelining and pre-loading. The architecture of a single range bin processor can be seen in Figure 5, whereas the actual hardware implementation is presented in Figure 9.

Each RBP needs to be programmed with the phase increment and gain coefficients. This requires selectively programming them before the DRFM phase samples are fed to the RBP block. The address of each RBP, a 9-bit binary number, is hardwired into each RBP. For instance, address lines in RBP 0 are grounded whereas they are tied to VDD in RBP 511.

As select inputs and associated coefficients propagate in the pipe, they are compared with the address of each RBP. The matching RBP latches the proper coefficient values. A comparator and a preload register accomplish this function.

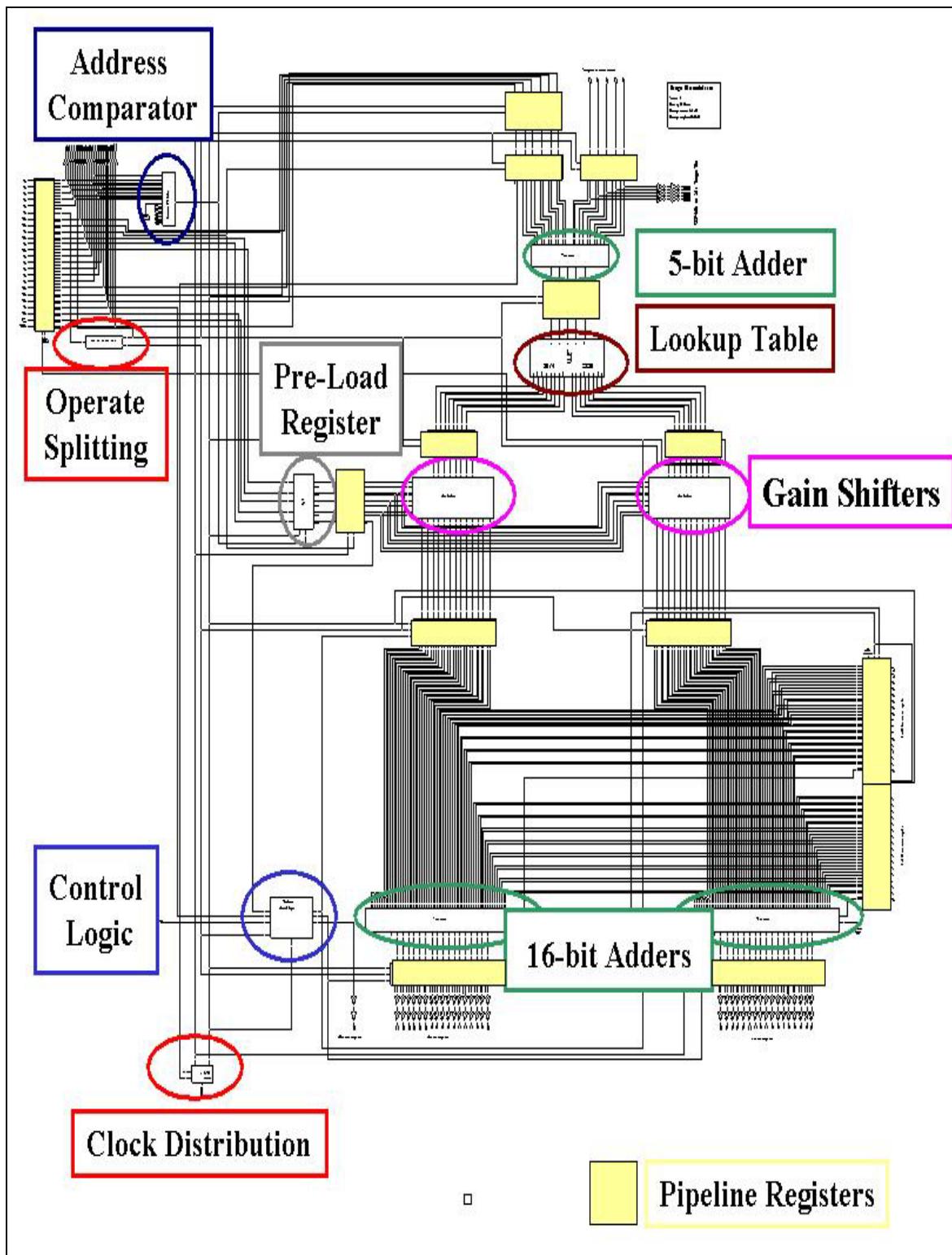


Figure 9. Single RBP Actual Hardware Implementation

The phase rotation adder generates the motion profile of the range bin by adding DRFM phase samples and phase increment values (PInc). The incremented phase values are converted to I /Q values by the Lookup Table (LUT).

I/Q values from the LUT are modulated with gain shifters by applying gain coefficients. The proper values are programmed by the control microprocessor. The gain shifters realize multiplication by powers of 2.

The I/Q values from previous range bins are then added to the computed I/Q values by using 16-bit adders. The sum is the final result if the range bin is the 511th RBP. Otherwise, the results are sent to the next consecutive RBP with the next clock.

2. Self Test Logic

The self-test logic is basically a linear feedback shift register (LFSR) counter, which can have $2^n - 1$ (in this case 4095) states. It is used to generate a maximum-length sequence of inputs. The pseudo random counting sequence of the LFSR is more likely to detect errors than a binary counting sequence. More information on the LFSR can be found in [11].

The self-test logic circuit implementation is shown in Figure 10. With the initialization of the sequence, one register is set and the others are cleared, which eliminates the all zero-valued-registers case. Therefore, as the self-test sequence is started, it generates Phase Sample Valid (PSV) and DRFM0 – DRFM4 outputs in a pseudo-random pattern. The outputs of the circuit can be monitored and compared with predicted results to detect any malfunction in the overall circuit. The outputs of the self-test logic and their use with the control circuitry will be discussed in Chapter V.

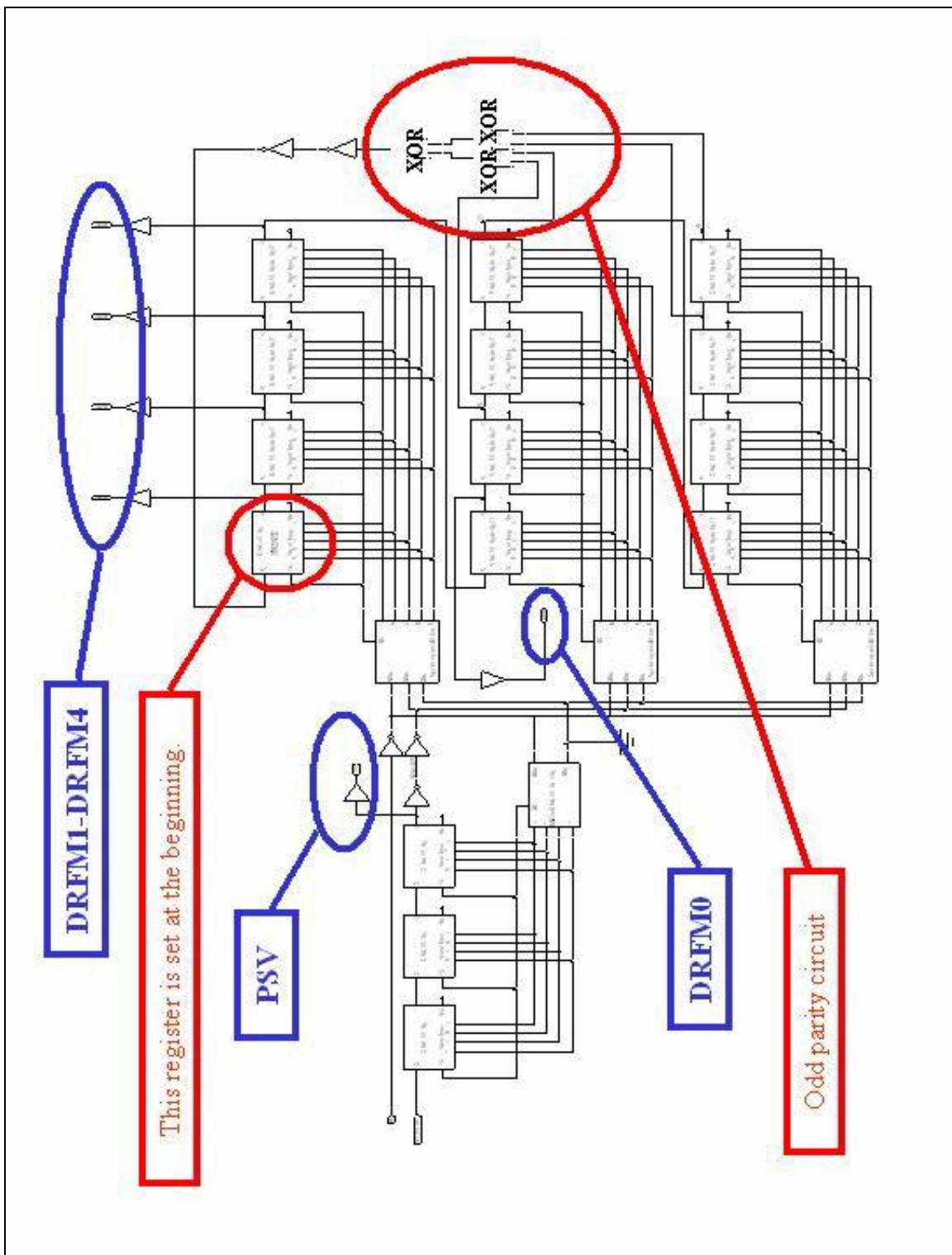


Figure 10. LFSR as a Self Test Sequence Generator

3. Phase Extractor

This circuit converts the I/Q values supplied by the DRFM as eight-bit two's complement numbers into corresponding phase angle values expressed as five-bit unsigned numbers for generating the false target signature. The detailed information on the conversion methodology and implementation can be found in [10].

4. Programming and Control Circuitry

This portion consists of the programming coefficient inputs for the range bin processors and select inputs to address a specific range bin to be programmed, a 4-to-1 6-bit multiplexer that steers the data from four sources (self test, phase extractor, two separate paths) into the 512-RBP block, a counter to determine the length of the self test sequence, and an S/R latch with a 2-to-1 multiplexer to switch the operating mode from/to operate to/from maintenance modes. Extra inputs are used to select the operating mode, the data path to be used, and start self-test sequence or phase extraction.

Figure 11 shows the control circuitry implementation in detail. The programming inputs can be seen in Figure 7.

5. Fabrication Technology

As presented by Mattox in [12], the proof-of-concept chip was manufactured with an $0.5\text{ }\mu\text{m}$ process and 81632 transistors, including I/O pads. It had 126 input/output pins and two ground and two VDD pins. It operated with a 3.3 V voltage supply at 70 MHz, consuming 0.132 Watts. It occupied 5.5 mm by 6.1 mm of area.

The design and technology used in the DIS has been greatly modified relative to the proof-of-concept chip in order to comply with the full specifications for the DIS and to benefit from technology improvements. Prof. Fouts and Mattox have completed the final design. Table 1 shows the information about the final design.

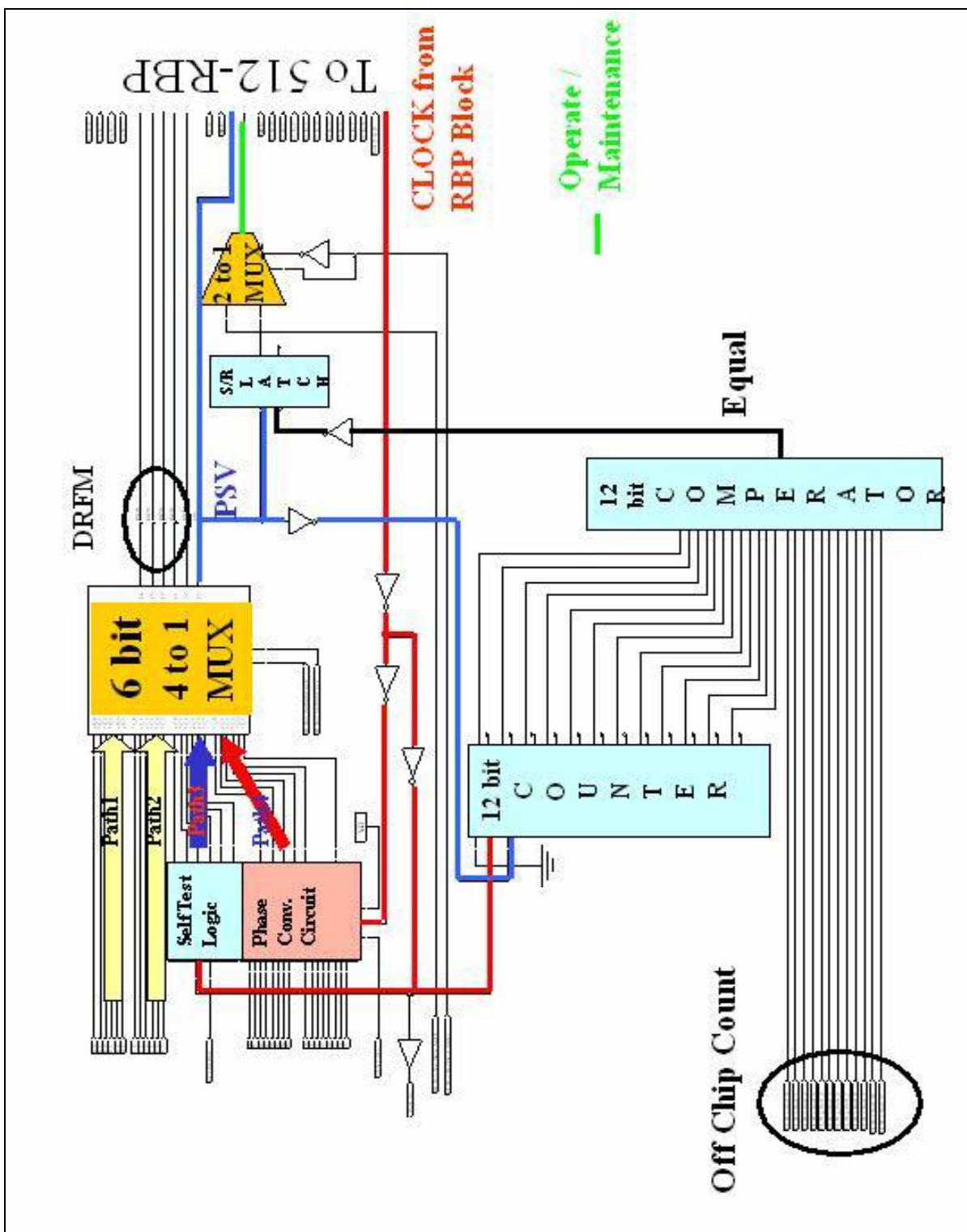


Figure 11. Control Circuitry Implementation

Process	0.18 mm CMOS 6 metal process (TSMC)
Physical dimension	“9.0 mm x 7.9 mm” (minimum, RBP block only)
Number of Transistors	Over 5.5 Million Transistors
Number of Pins	130 I/O pins, Dozens of VDD/GND pins
Power Consumption	16.1 W at 700 MHz using 1.8-V supply

Table 1. Specifications of the Final Chip (After [12])

The theory lying behind countering ISARs and the hardware implementation of the DIS discussed in this chapter forms the main subject of the design process. The testing and verification phases of the design process consist of using a hardware description language, VHDL, for simple and precise functional simulations of the DIS. Chapter III gives information on VHDL and the simulation software used to test the components.

III. INTRODUCTION TO VHDL HARDWARE DESCRIPTIVE LANGUAGE AND ACTIVE HDL™

This chapter contains basic information on Hardware Description Languages and the VHDL. It also introduces the software tool, Aldec Active HDLTM, used in VHDL modeling, functional simulation and verification of the DIS.

A. VHDL HARDWARE DESCRIPTIVE LANGUAGE

1. Background

The need for a standardized representation of digital systems to share designs of subsystems across contractors became apparent. To address this issue, the first version of VHDL was released in 1985 by a committee of the U.S. Department of Defense (DoD). The Institute of Electrical and Electronic Engineers (IEEE) standardized the language and released IEEE standard 1076-1987 in 1987. The latest version of the VHDL standard is IEEE 1076-1993. Drafts for a revised standard are currently in progress. [8]

2. Digital Design Using Hardware Descriptive Languages and VHDL

The digital systems design process starts from the specification of requirements and proceeds to produce a functional design. This design is then physically implemented through a sequence of steps. Like the full-custom Digital Image Synthesizer addressed in this thesis, a custom ASIC is generally the highest performing solution for any computation but often the most expensive and time consuming one. An example of the sequence of activities that typically take place during classical ASIC design is shown in Figure 12.

System requirements often consist of the function(s) to be realized, speed, power consumption, size and cost constraints. These functional requirements are then refined to a more detailed design description at the level of registers, memories, arithmetic units and state machines, which becomes the Register Transfer Level (RTL) of the design. Implementation of each RTL component produces the Logic Design of the system. Both RTL and logic level designs can be used to ensure that the design meets the original specifica-

tions. Fault simulations can be conducted to measure the effects of possible manufacturing defects on the chip and the environmental factors in which the chip is to be operated.

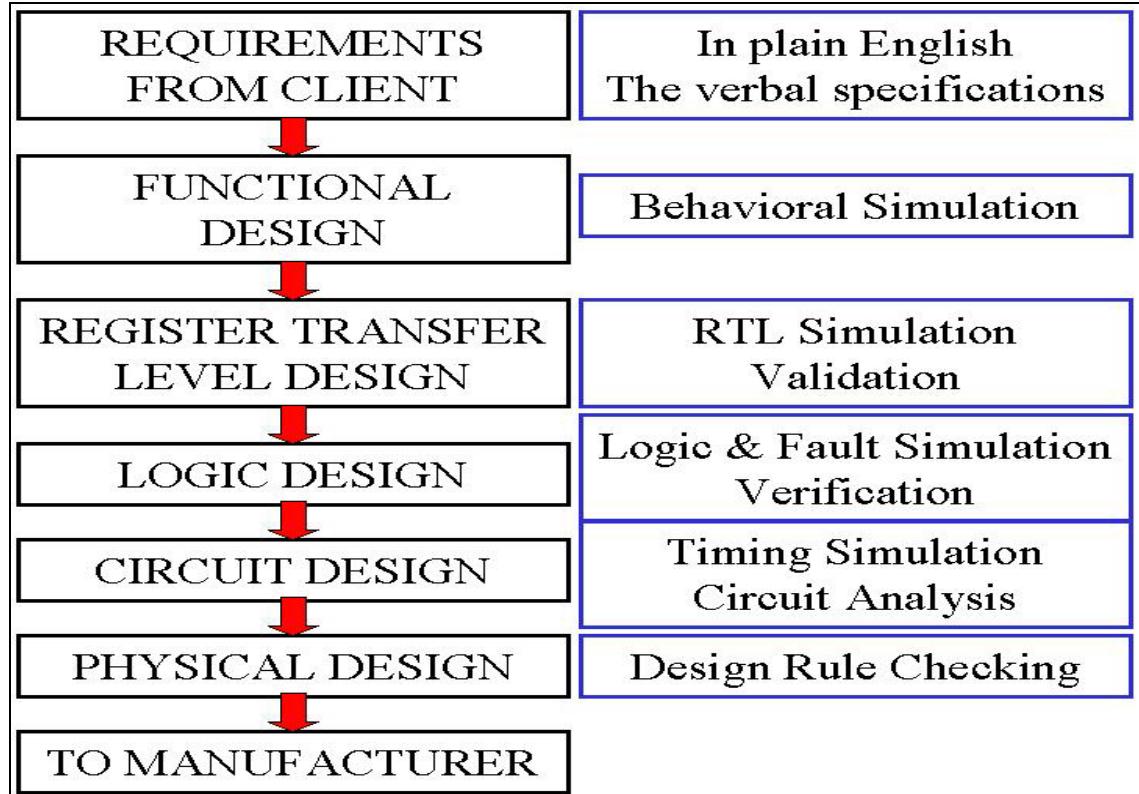


Figure 12. Activity Flow in Classic Digital System Design (After [13])

Finally, the logic level implementation is transformed into a circuit level implementation and physical chip layout. Design rule checks and circuit parameter extraction can be done at the physical design level.

At each level of this design hierarchy there are components that are used to describe the design. At the higher, or more abstract, levels there is a smaller number of more powerful components such as arithmetic units and memories. At the lower, and less abstract, levels there is a larger number of simpler, less-powerful components such as logic gates and transistors. Each level of the design hierarchy corresponds to a level of abstraction. The accuracy of simulation results increases at lower levels of hierarchy with the cost of longer simulation times.

In this classical approach, the design errors at low levels of detail are expensive to correct. They can also lead to a longer development time, which naturally increases the cost. The major drawback of traditional design methods is the manual translation of the design description into a set of logical equations. This step can be entirely eliminated with Hardware Description Languages (HDLs). With the ability of simulating circuits at different levels of abstraction, errors can be discovered and corrected early. [13]

In VHDL, designs can be decomposed hierarchically. Each design has not only a well-defined interface to connect it to other components but also a precise behavioral specification to simulate it. VHDL can be used to define behavioral specifications either in an algorithm or in actual hardware structure. For example, an algorithm can be used to stimulate a component to test higher levels of operation and it can be replaced with real hardware implementation later if the simulations are successful at higher levels. VHDL also allows concurrency, timing and clock modeling. It can also handle asynchronous circuits as well as synchronous sequential-circuit structures. Logical operation and timing behavior of a design can also be simulated.

In this thesis, the VHDL code of a full-custom Digital Image Synthesizer ASIC was generated automatically by a schematic capture editor, Tanner Pro S-Edit. Although it has the pictorial schematics of the components to provide the hardware design engineers a “sense and feel” of the design process, it lacks a logic level simulator. For simulation purposes, the code generated by Tanner Pro S-Edit was used in the Aldec Active HDL™ tool. In this code, the components are defined in the structural domain, describing them in actual circuitry with minimum levels of abstraction to predict the system behavior as accurately as possible. Although the code generated is not optimum in size, it allowed a thorough testing and verification of each component and the overall circuit in Active HDL™.

B. VHDL CAPABILITIES OF ACTIVE HDL™

1. VHDL as a Programming Language in Active HDL™

The primary hardware abstraction in VHDL is the *entity*. It represents a part of the design with well-defined inputs and outputs and performs a well-defined function. *Entity*

is the description of the interface between a design and its external environment. It may also specify the declarations and statements that are part of the design *entity*. A given *entity* declaration may be shared by many design *entities*, each of which has a different *architecture*. Thus, an *entity* declaration can potentially represent a class of design *entities*, each having the same interface. *Entity* declarations resemble software class descriptions.

Architecture body describes input output transformations and the internal composition or the behavior of the *entity* more like a software object. It is associated with an *entity* declaration to describe the internal organization or operation of a design entity. It is also used to describe the behavior, data flow, or structure of a design *entity*.

Signals provide the interactions between concurrent statements. *Signal* is an object with a past history of values. A *signal* may have multiple drivers, each with a current value and projected future values. The term *signal* refers to objects declared by *signal* declarations and *port* declarations.

A *component* describes a substructure of a design entity that is interconnected through signals. It represents an *entity/architecture* pair and specifies a subsystem, which can be *instantiated* in another *architecture* leading to a hierarchical specification.

A *process* statement defines an independent sequential *process* representing the behavior of some portion of the design. It consists of the sequential statements whose execution is made in the order defined by the user. During execution all concurrent statements are executed during the same simulation cycle and values of all modeled signals are computed. No VHDL model should depend on the order of execution of its concurrent statements. *Process* statements such as *case* and *loop* allow user defined sequential statements, which are beneficial especially in sequential circuits that have feedback loops for initialization purposes. When a *signal* takes on a new value, the sensitivity list of the concurrent statement decides if the statement is sensitive to that particular signal and acts accordingly.

As an example, the logic symbol and schematic representation of an inverter is shown in Figure 13. The code given in Figure 14 is generated by S-Edit and modified to supply the behavioral descriptions of n-type and p-type transistors.

As seen in the VHDL code, the descriptions of transistors and *entities* Vdd and Gnd (power supplies) are defined as *behavioral* descriptions in *architecture* body and they are *instanced* in the *entity* inverter.

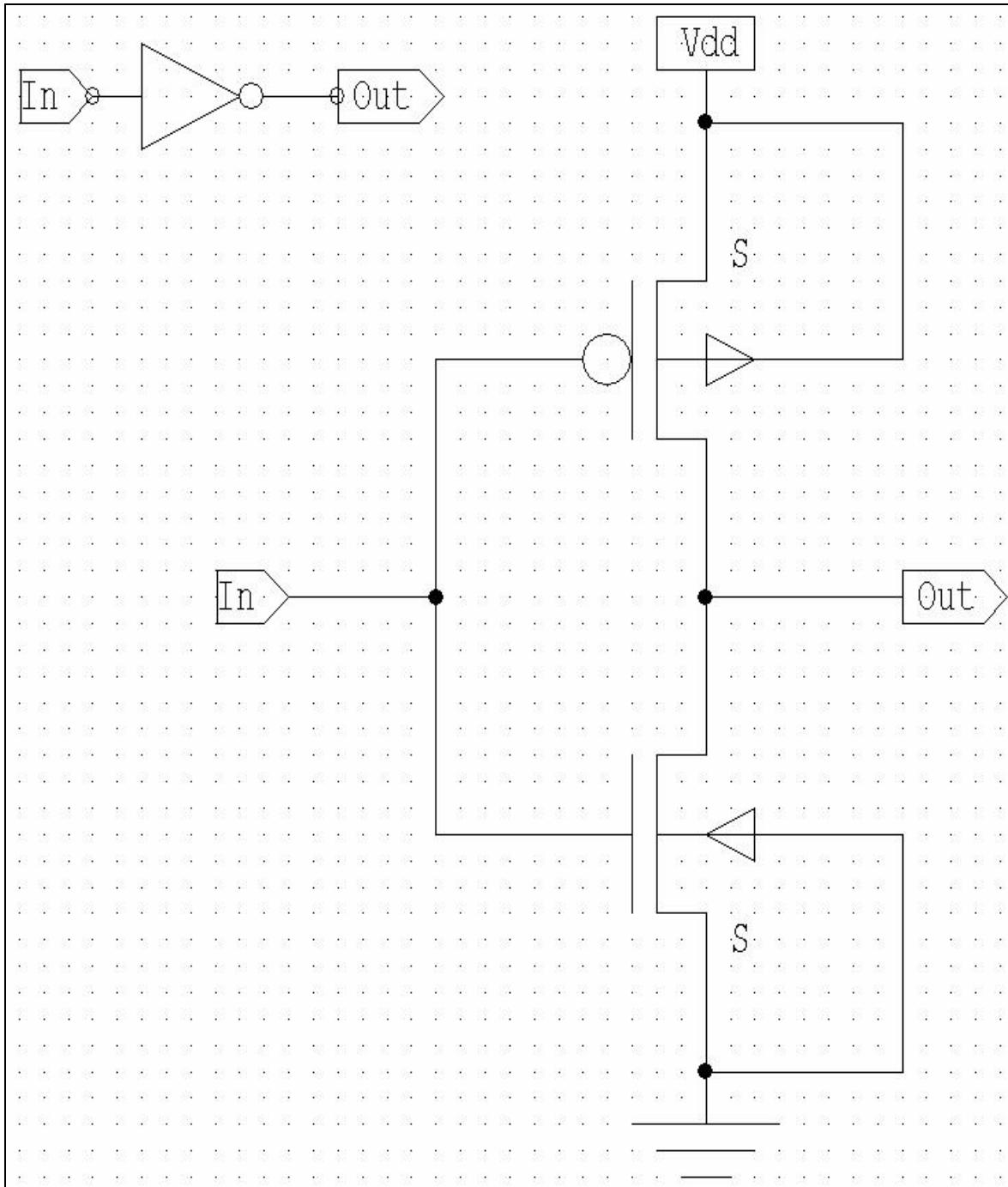


Figure 13. Logic Symbol and Schematic Representation of an Inverter in S-Edit

```

LIBRARY IEEE;
USE IEEE.std_logic_1164.all; } Library Definitions
                                  } Each entity should have a library defined.

-- ***** Gnd model *****
-- external ports
ENTITY Gnd IS PORT (
    Gnd : OUT std_logic
);
END Gnd;

-- internal behavior
ARCHITECTURE behavioral OF Gnd IS } Entity name and port definitions for entity
                                     } Gnd. It has only one port, which is an output signal of standard logic.

    -- TODO: user must define behavior of VHDL primitives
END behavioral;

-- ***** DJF_NFET model *****
-- external ports
ENTITY DJF_NFET IS PORT ( } Entity name
    B : IN std_logic;      and port definitions for entity
    D : OUT std_logic;     DJF_NFET.
    G : IN std_logic;
    S : IN std_logic
);
END DJF_NFET;

-- internal behavior
ARCHITECTURE behavioral OF DJF_NFET IS } Behavioral architecture description of entity Gnd
    -- TODO: user must define behavior of VHDL primitives
END behavioral;

-- ***** DJF_PFET model ***
-- external ports
ENTITY DJF_PFET IS PORT ( } Behavioral architecture
    B : IN std_logic;      description of entity Gnd
    D : OUT std_logic;
    G : IN std_logic;
    S : IN std_logic
);
END DJF_PFET;

```

BEGIN
Gnd <= '0';

```

BEGIN
    NFET:PROCESS(B,G,S)
BEGIN
    if G='0' then D<='Z';
    elsif (G='1' and S='0') then D <= '0';
    elsif (G='1' and S='1') then D <= '1';

    elsif (G='1' and S='Z') then D <= 'Z';
end if;
end process NFET;

```

Figure 14. Modified VHDL Code for an Inverter

```

-- internal behavior
ARCHITECTURE behavioral OF DJF_PFET IS
  -- TODO: user must define behavior
END behavioral;

-- ***** Vdd model *****
-- external ports
ENTITY Vdd IS PORT (
  Vdd : OUT std_logic
);
END Vdd;

-- internal behavior
ARCHITECTURE behavioral OF Vdd IS
  -- TODO: user must define behavior of VHDL primitives
END behavioral;

-- ***** DJF_Invix model *****
-- external ports
ENTITY DJF_Invix IS PORT (
  \In\ : IN std_logic;
  \Out\ : OUT std_logic
);
END DJF_Invix;

-- internal structure
ARCHITECTURE structural OF DJF_Invix IS

-- COMPONENTS

COMPONENT Gnd
PORT (
  Gnd : OUT std_logic
);
END COMPONENT;

COMPONENT DJF_NFET
PORT (
  B : IN std_logic;
  D : OUT std_logic;
  G : IN std_logic;
  S : IN std_logic
);
END COMPONENT;

```

Entity name and port definitions for entity DJF_Inv1x. It has one input port and one output port.

Components defined in structural architecture before they are instanced.

```

BEGIN
  PFET:PROCESS(B,G,S)
    BEGIN
      if G='1' then D<='Z';
      elsif (G='0' and S='0') then D <= '0';
      elsif (G='0' and S='1') then D <= '1';
      elsif (G='0' and S='Z') then D <= 'Z';
      end if;
    end process PFET;
    end process NFET;
  BEGIN
    Vdd <= '1';

```

Modified VHDL Code for an Inverter, Continued

```

COMPONENT DJF_PFET
PORT (
    B : IN std_logic;
    D : OUT std_logic;
    G : IN std_logic;
    S : IN std_logic
);
END COMPONENT;

COMPONENT Vdd
PORT (
    Vdd : OUT std_logic
);
END COMPONENT;

-- SIGNALS
SIGNAL Vdd : std_logic;
SIGNAL N1 : std_logic;

-- INSTANCES
BEGIN
Gnd_1 : Gnd PORT MAP(
    Gnd => N1
);
NFET_1 : DJF_NFET PORT MAP(
    B => N1,
    D => \Out\,
    G => \In\,
    S => N1
);
PFET_1 : DJF_PFET PORT MAP(
    B => Vdd,
    D => \Out\,
    G => \In\,
    S => Vdd
);
Vdd_1 : Vdd PORT MAP(
    Vdd => Vdd
);
END structural;

```

Components defined in structural architecture before they are instanced.

Signals in the entity DJF_Inv1x

Instances in the entity DJF_Inv1x

Modified VHDL Code for an Inverter, Continued

2. About Active HDL™

Aldec, Inc, of Henderson, NV, developed the tool chosen to perform the VHDL simulations, Active HDL™ 5.1. It provides a number of useful features for development as well as testing hardware components. Its simulation technology supports IEEE VHDL 1076-1987/1993 and IEEE Verilog 1364-1995. Furthermore, it also supports EDIF 2.0.0 and single (VHDL or Verilog) or mixed (VHDL and Verilog together) language configurations.

This tool allows the user to create a design with three different methods. The first one, Text Editor, can be used to manually write the VHDL code or to copy a code into the design. The editor provides colorful representations of different syntax structures and makes programming easier. The second method, Block Diagram Editor, can be used to generate graphical symbols for gates and logic elements as well as to connect them for building larger structures. It provides visual assistance for the design engineer. The last method is the Finite State Machine Editor, which can be used to graphically creating designs using state diagrams.

The Active HDL™ Text Editor resembles any text editor used for high level programming languages, such as C++. This environment is tightly integrated with the compiler and the simulator, which provides debugging capabilities. It also supplies the user with a built-in language assistance, automatic design structure generation capability, and setting or clearing of code breakpoints and cross probing of error messages. From the VHDL code, Active HDL™ can generate block diagrams or finite state machines. Figure 15 shows the Text Editor.

The Block Diagram Editor is a graphical representation of each entity in the VHDL code including signals and nodes. Active HDL™ has a built-in library from different vendors to create schematics. The user can define and save new components and create a library. The Block Diagram Editor can export EDIF schematics as well as have a Design Rule Checking (DRC) capability. When compiled, it can generate the source code, which is executable. Figure 16 shows the Block Diagram Editor.

```

Active HDL 5.1 (ozk_PADTOPAD_24march) - C:\My_Designs\ozk_PADTOPAD_24march\src\DTM_Dis4_ForVHDL_WithPads.vhd / DTM_Dis4_ForOzkan_1/DTM_RBF_Pipelined_Inv_4/DTM_24bitReg_2
File Edit Search View Design Simulation Tools Window Help
100 ns | No simulation
Design Browser
dmt_dis4_forvhdl_withpads.vhd
Unsorted
ozk_PADTOPAD_24mc
dmt_dis4_forvhdl_withpads.vhd
DLM_Dis4_ForVHDL.vhd
working_path_selfTest
D_DF_NFET.bde
D_DF_FFET.bde
D_DF.bde
Vdd.bde
D_DF_Inv1x.bde
D_DF_Inverter.bde
D_DF_FFET1x.bde
CC_FFET1x.bde
CC_Nand1x.bde
CC_Nand2x.bde
CC_Nand3x.bde
CC_Nand4x.bde
CC_Nand5x.bde
CC_Nor2x.bde
CC_SbitAdder1x.bde
CG_PassGate1x.bde
CG_MSFFPGreq_1x.bde
CG_Delay.bde
CG_FFET_Logic.bde
CG_FFET_Logic_0GIC
CG_MSFFPGreq_0GIC
CG_Nor1x.bde
CG_LogReq_CLB_1x.bde
CG_Zeroing_1x.bde
CG_Reg1Reg1Ix.bde
CG_Reg1Reg5Ix.b
CG_Reg1Reg5_1x.b
CG_MSFFPG_CLReq
CG_10MUX2to1.bde
CG_12MUX3to1.bde
CG_12MUX3to1_ibc
CG_Sign_Shifter_1x.b
D_DF_Inv1x.bde
D_DF_PassGate1x.bde
D_DF_18kAdder.bde
D_DF_Nand2_1x.bde
D_DF_Nand3_1x.bde
D_DF_Nand4_1x.bde
D_DF_Cryk4AndGen.b
D_DF_Nor2_1x.bde
D_DF_GPGen.bde
D_DF_18kAdder.bde
D_DF_Nand5_1x.bde
D_DF_Grpk4AndGen.b
D_DF_16k4Adder.bde
D_DF_PG_1x.bde
D_DF_2to1_MUX1_ibc
D_DF_2to1_2x.bde
DTM_FFET1x.bde
DTM_Inv_2x.bde
DTM_NFET_4x.bde
DTM_FFET_4x.bde
DTM_Inv_4x.bde
DTM_NFET_3x.bde
DTM_FFET_3x.bde
DTM_Inv_3x_Short.b
D_DF_Clock_Com.bde
CG_MSFFPGnotCLKn
DTM_24bitReg.bde
DTM_6bitReg.bde
D_DF_Inv1x.bde
Design flow \working_pa... \dmt_dis4_f...
File Stru... Res...
design flow \working_pa... \dmt_dis4_f...

```

Figure 15. Text Editor in Active HDL™

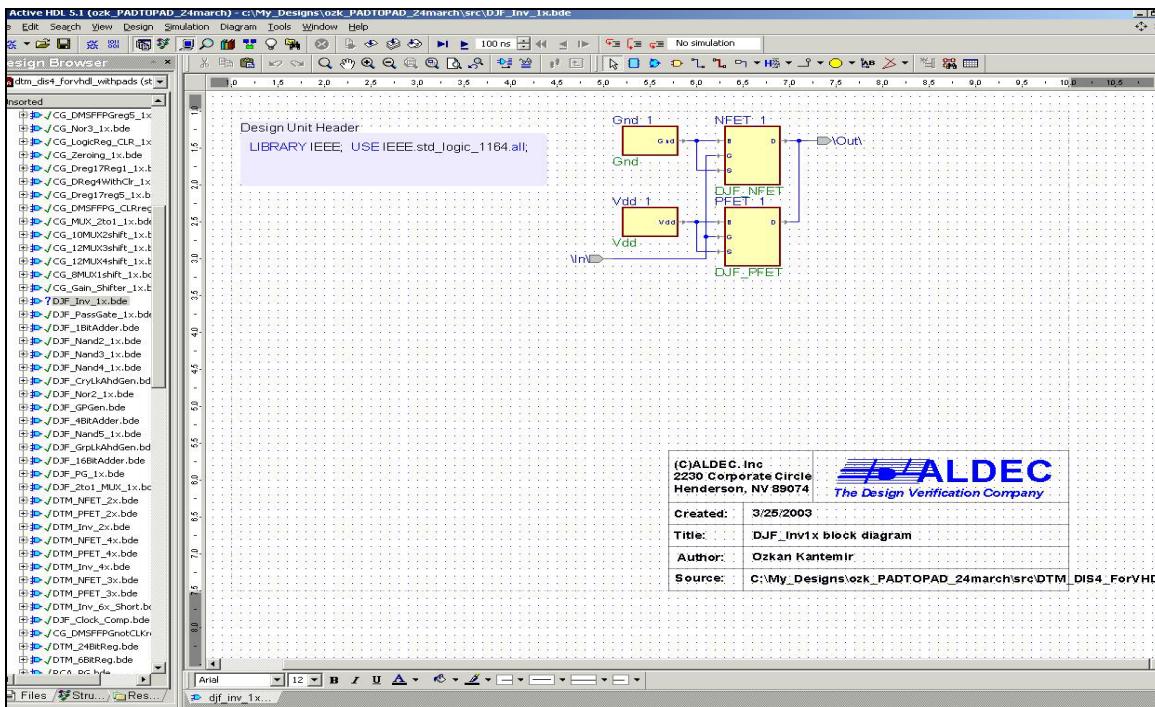


Figure 16. Block Diagram Editor in Active HDL™

The Finite State Machine Editor allows the user to enter a state diagram-based design. This diagram can be converted into VHDL or Verilog code for simulation and debugging purposes. HDL can be used with state diagrams. Figure 17 shows an example of a state diagram in Active HDL™. More information on creating a design, generating test benches, the waveform editor and utilizing the editors mentioned above can be found at [14].

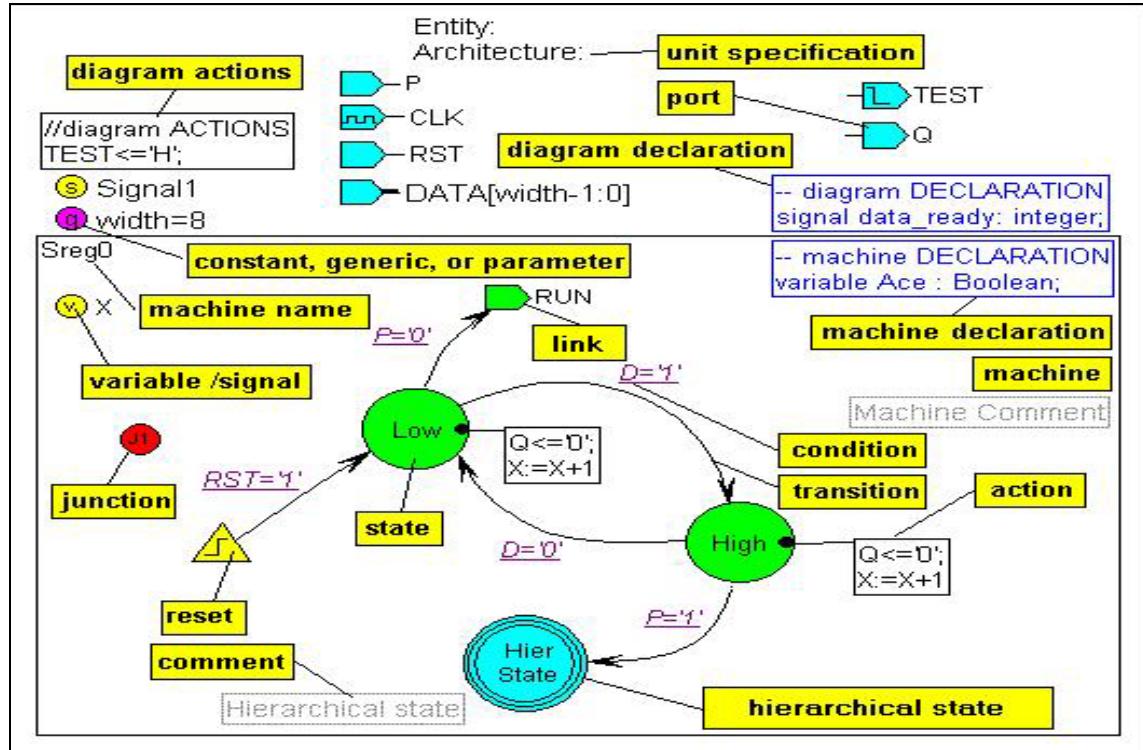


Figure 17. Finite State Machine Editor in Active HDL™

3. Test and Verification Methodology

The VHDL code generated by the Tanner Pro S-EDIT tool contained some parts that need to be modified. First, the basic cells defined as VHDL primitives in S-EDIT should be re-defined in Active HDL™. For instance, the schematic representation of the *entity* DJF_NFET is shown in Figure 18 while the generated code for it and inserted behavioral description are in Figure 19. The *entity* is connected to other components via the ports shown in the schematic. The user should insert its *behavioral* description. Table 2 gives the *behavioral descriptions* used for the lower level *entities*.

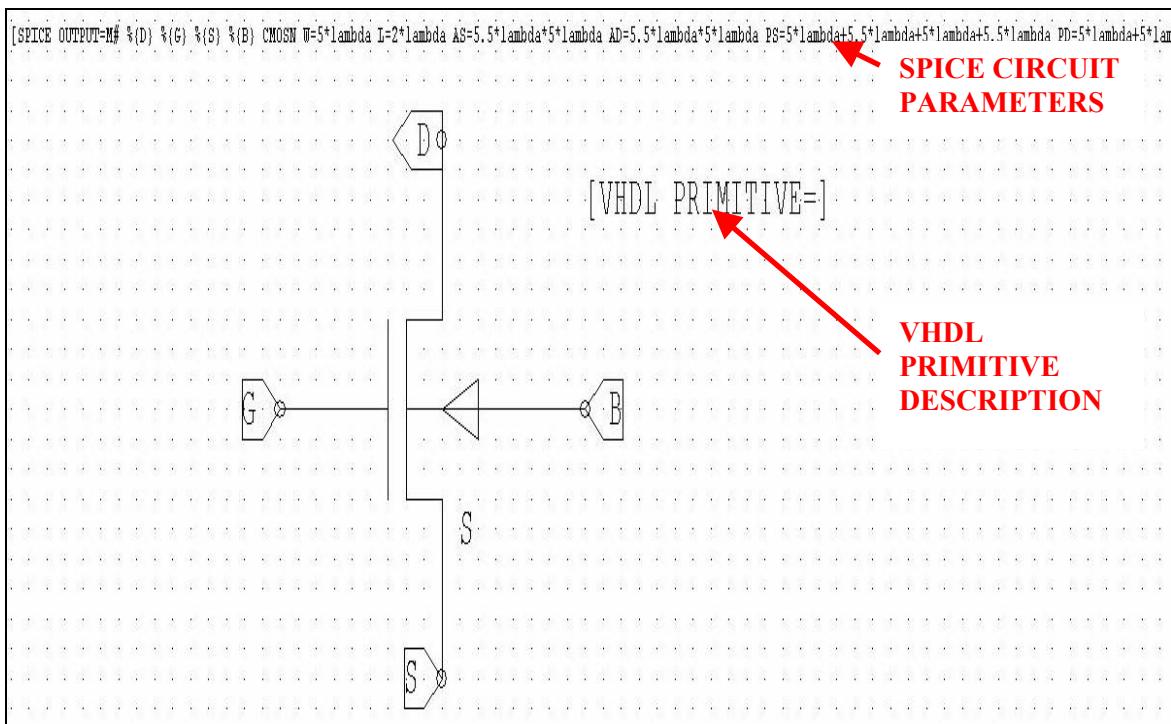


Figure 18. Schematic Representation of *Entity DJF_NFET* in S-EDIT

```
-- ***** DJF_NFET model *****
-- external ports
LIBRARY IEEE;  USE IEEE.std_logic_1164.all; ENTITY DJF_NFET IS PORT (
    B : IN std_logic;
    D : OUT std_logic;
    G : IN std_logic;
    S : IN std_logic
);
END DJF_NFET;

--  internal behavior
ARCHITECTURE behavioral OF DJF_NFET IS
BEGIN
    NFET:PROCESS(B,G,S)
BEGIN
    if G ='0' then D<='Z';
    elsif (G='1' and S='0') then D <= '0';
    elsif (G='1' and S='1') then D <= '1';
    elsif (G='1' and S='Z') then D <= 'Z';
    end if;
    end process NFET;
END behavioral;
```

} **INSERTED BEHAVIORAL DESCRIPTION**

Figure 19. Generated Code and Inserted Behavior for Entity DJF_NFET

<i>Entity</i>		<i>Behavioral Description</i>
Ground	Gnd	<pre> begin Gnd <= '0'; end behavioral;</pre>
Power Supply	Vdd	<pre> begin Vdd <= '1'; end behavioral;</pre>
n-type transistors	NFET s	<pre> begin NFET:PROCESS(B,G,S) begin if G ='0' then D<='Z'; elsif (G='1' and S='0') then D <= '0'; elsif (G='1' and S='1') then D <= '1'; elsif (G='1' and S='Z') then D <= 'Z'; end if; end process NFET; end behavioral;</pre>
p-type transistors	PFET s	<pre> begin PFET:PROCESS(B,G,S) begin if G ='1' then D<='Z'; elsif (G='0' and S='0') then D <= '0'; elsif (G='0' and S='1') then D <= '1'; elsif (G='0' and S='Z') then D <= 'Z'; end if; end process PFET; end behavioral;</pre>
Delay Element	DJF_Delay_Element	<pre> begin Out_Delay <= In_Delay after 1 ps; end behavioral;</pre>
SR Latch	DTM_FfnotSnotR	Please Refer to Chapter IV Section B.

Table 2. Inserted VHDL *Behavioral Descriptions* for *Entities*

The use of Find/Replace and other utilities in the Text Editor eases the insertion of behavioral descriptions. In addition, every *entity* should have a library statement before its definition, which is “LIBRARY IEEE; USE IEEE.STD_LOGIC_1164.ALL; ”.

One other thing to be modified in the machine-generated code is the syntax of some entity names. In Active HDL™, the *entity* or *signal* names cannot contain special characters or special operators. Since the naming convention for *entities* in S_EDIT is not the same as the one in Active HDL™, there are several names to be changed so they will fit the simulation tool naming rules.

For example, neither “CG_DMSFFPG~CLKreg4_1x” as an *entity* name nor “SELECT” as a *signal* name is accepted in Active HDL™. The entity name must be changed to “CG_DMSFFPGnotCLKreg4_1x”, while the reserved word SELECT must be modified to “SLCT”. Since the naming corrections are done through the entire code, the modifications do not affect the simulation results and the behavior of the circuit.

4. Example, Inverter

This section contains an example simulation phase of an inverter.

- Open Active HDLTM, by clicking the program icon on the desktop.
- In the dialog box, select “Create New Design” and click “OK” as shown in Figure 20.

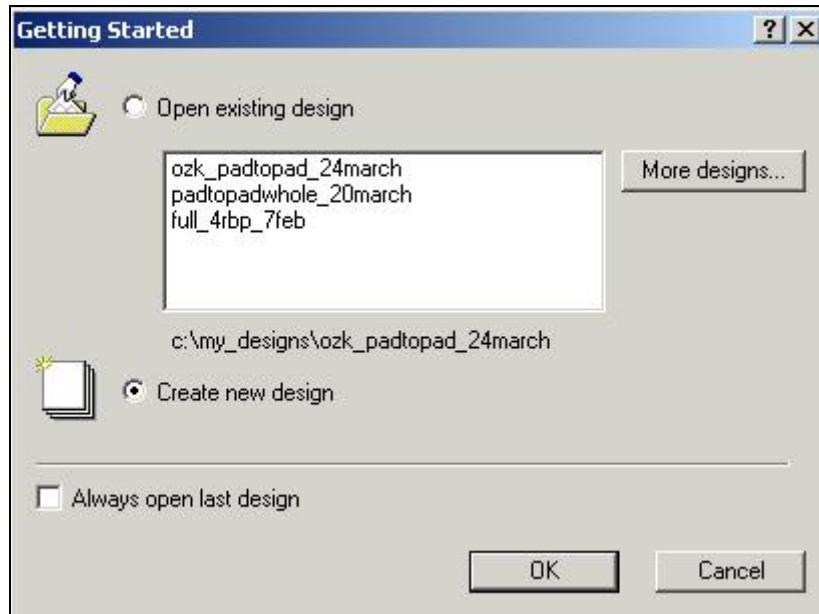


Figure 20. Example, Inverter – Creating New Design

- In the dialog box, select “Add Existing Resource Files” and click “Next”. Then, in the second dialog box, select the file generated by S-EDIT with extension “. VHD”. This phase is shown in Figure 21.

- Skip the dialog box for the synthesis tools by clicking “Next” since the design is used only in verification and testing of the circuit. Give a name in the next box for the design and click “Next”. Figure 22 shows this procedure.

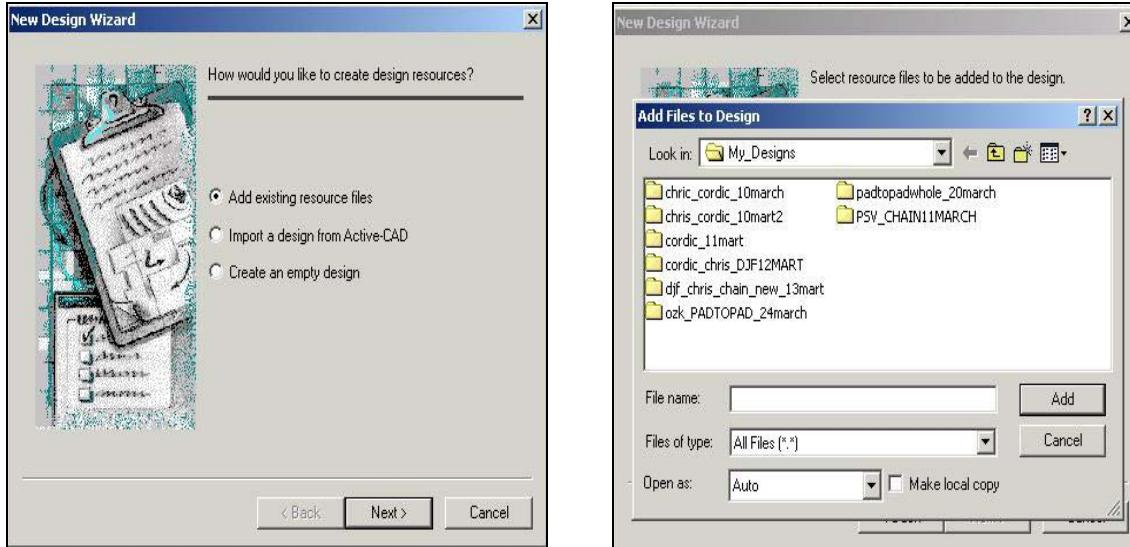


Figure 21. Example, Inverter – Adding VHD Code

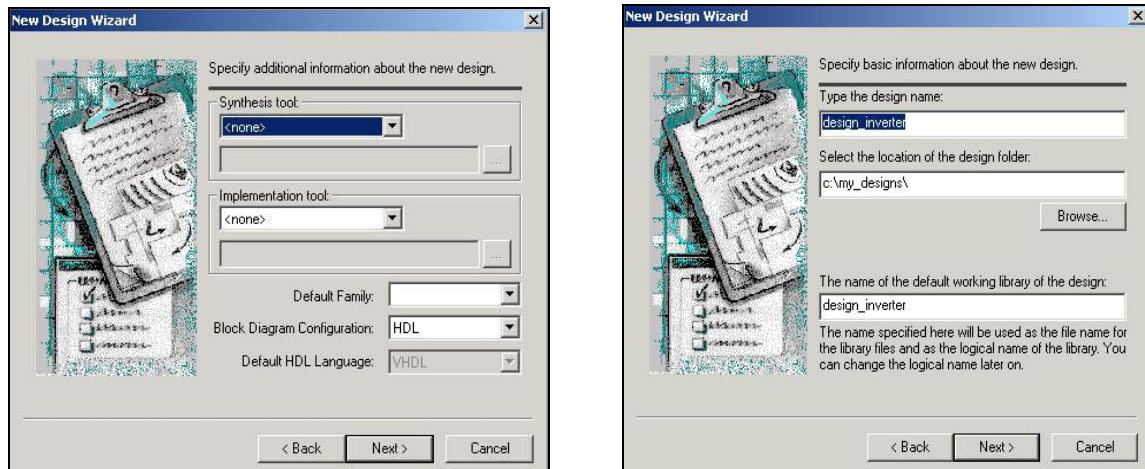


Figure 22. Example, Inverter – Naming the Design

- Click “Finish” to Finalize Creating a New Design as shown in Figure 23. Selecting “Compile source files after creation” is not recommended for large VHD codes, since the compilation process may take too much time.
- In the text editor that has appeared, make the modifications necessary and either press “F11” or use Design > Compile menu option/ Shortcut to compile

the source file. Repeat this procedure until the code is error and warning free. The corrected code in the text editor is shown in Figure 24.



Figure 23. Example, Inverter – Finishing the New Design Entry

```

-- **** Gnd model ****
-- external ports
LIBRARY IEEE; USE IEEE.std_logic_1164.all; ENTITY Gnd IS PORT (
    Gnd : OUT std_logic
);
END Gnd;

-- internal behavior
ARCHITECTURE behavioral OF Gnd IS
BEGIN
    Gnd <= '0';
END behavioral;

-- **** DJF_NFET model ****
-- external ports
LIBRARY IEEE; USE IEEE.std_logic_1164.all; ENTITY DJF_NFET IS PORT (
    B : IN std_logic;
    D : OUT std_logic;
    G : IN std_logic;
    S : IN std_logic
);
END DJF_NFET;

-- internal behavior
ARCHITECTURE behavioral OF DJF_NFET IS
BEGIN
    NFET:PROCESS(B,G,S)
    BEGIN
        if G ='0' then D<='Z';
        elsif (G='1' and S='0') then D <= '0';
        elsif (G='1' and S='1') then D <= '1';
        elsif (G='1' and S='Z') then D <= 'Z';
        end if;
        end process NFET;
    END behavioral;

```

Figure 24. Example, Inverter – Corrected Code

- Select the top-level structure, the inverter, from the roll-down menu in the Design Browser and click on the top level in Structure Section of the Design Browser to see input, output and routing *signals* of interest at that particular *structural* level. Figure 25 shows the Design Browser and Structure Section.

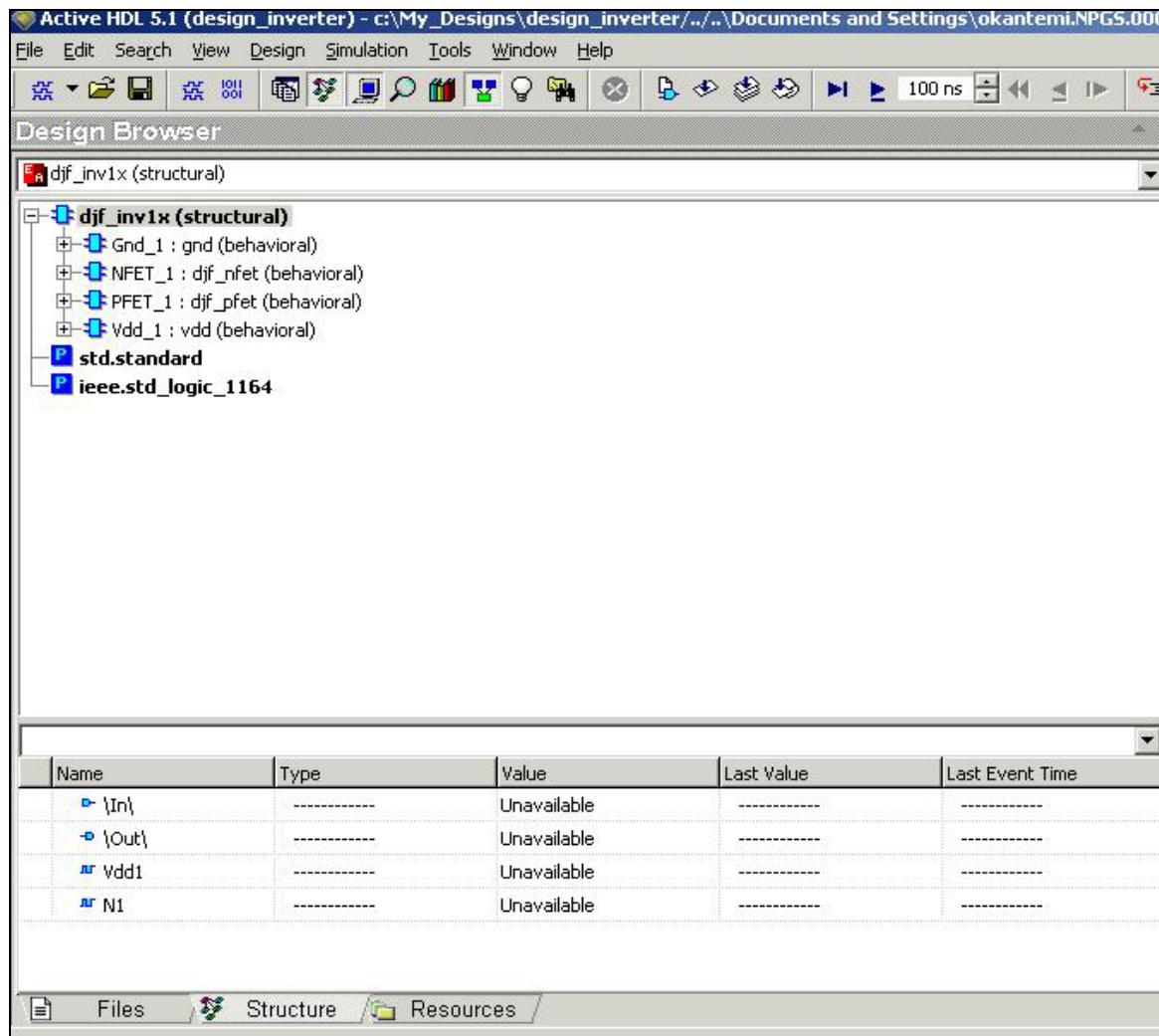


Figure 25. Example, Inverter – Top Level Selection

- To generate a waveform, simply select the signals from the signal list by holding the shift key and left clicking on each of the signal names. Right click and select “Add to Waveform” option. The waveform editor generated provides the inputs to be entered in various ways and outputs to be observed in time. Figure 26 shows the Waveform Editor.

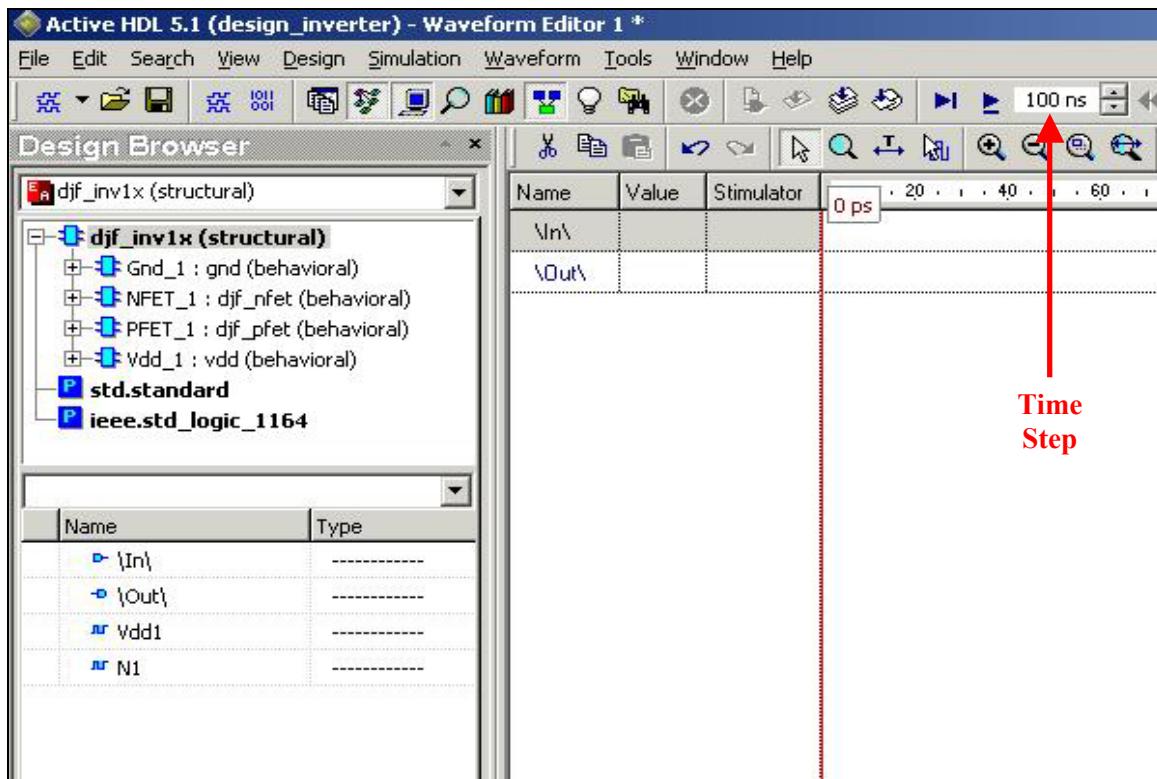


Figure 26. Example, Inverter – Waveform Editor

- In the waveform editor, select the input \In\ and right click. Select the “Stimulators” option. The stimulators allow *signals* to be assigned values in various ways. A *signal* can be assigned as a clock, counter, formula or other pre-defined sequences. It is also possible to assign a keyboard button to a signal to toggle the value of that signal in the simulation. For simplicity in this example, select “Clock” option, adjust the frequency and click “Apply”. The Stimulators menu is shown in Figure 27.

- From the Simulation menu select the “Initialize Simulation” option and specify the time step in the box shown in Figure 26. For this example use 10 ns.

- Click once on the right arrow next to the time step box for each simulation step. Repeat as many as necessary to observe the proper input/output relationships. The simulation and the correct operation for the inverter at the end of 10 ns is shown in Figure 28.

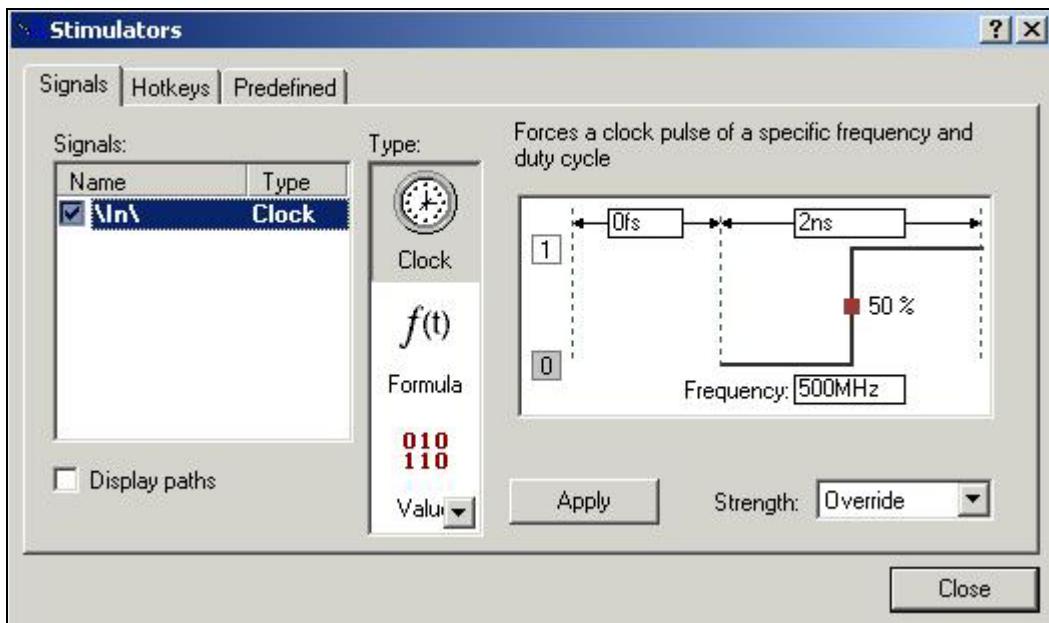


Figure 27. Example, Inverter – Stimulators Menu

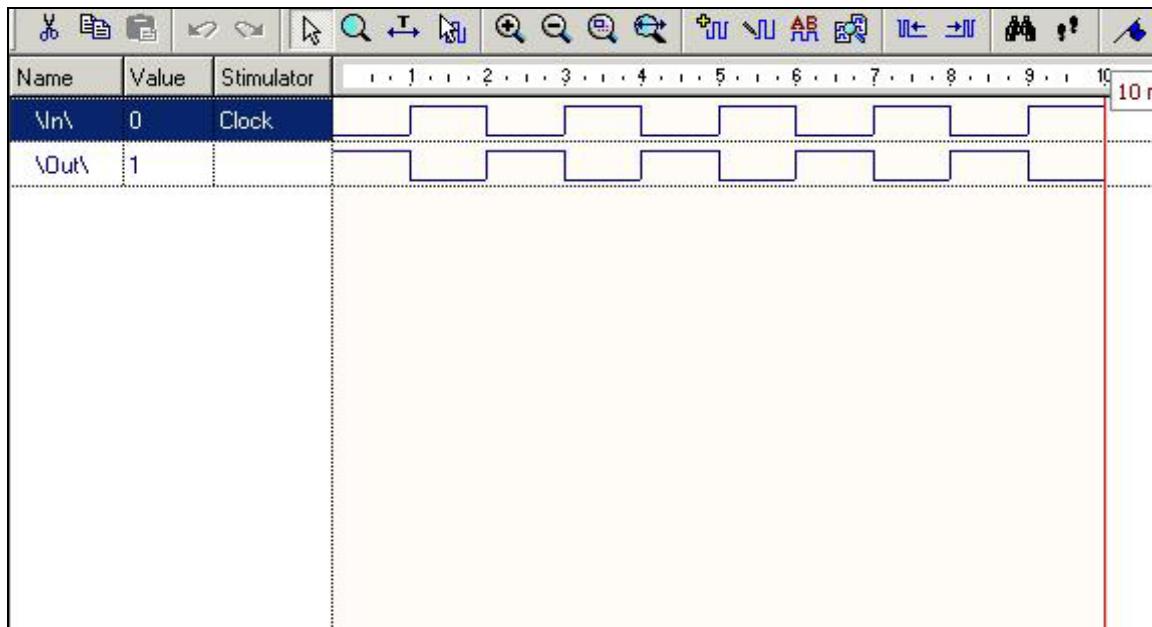


Figure 28. Example, Inverter – Simulation and Correct Operation

For each code, a block diagram can be generated and used during simulation to trace the signal values in time.

- In order to obtain a block diagram from VHDL code, select the Tools > Code2Graphics Conversion Wizard and follow the instructions in the dialog boxes.

The wizard generates a block diagram for each entity declaration and connects them properly. The graphical representation enhances debugging capabilities and tracing opportunities. Figure 29 presents the generated block diagram and its use in the simulation for the example circuit.

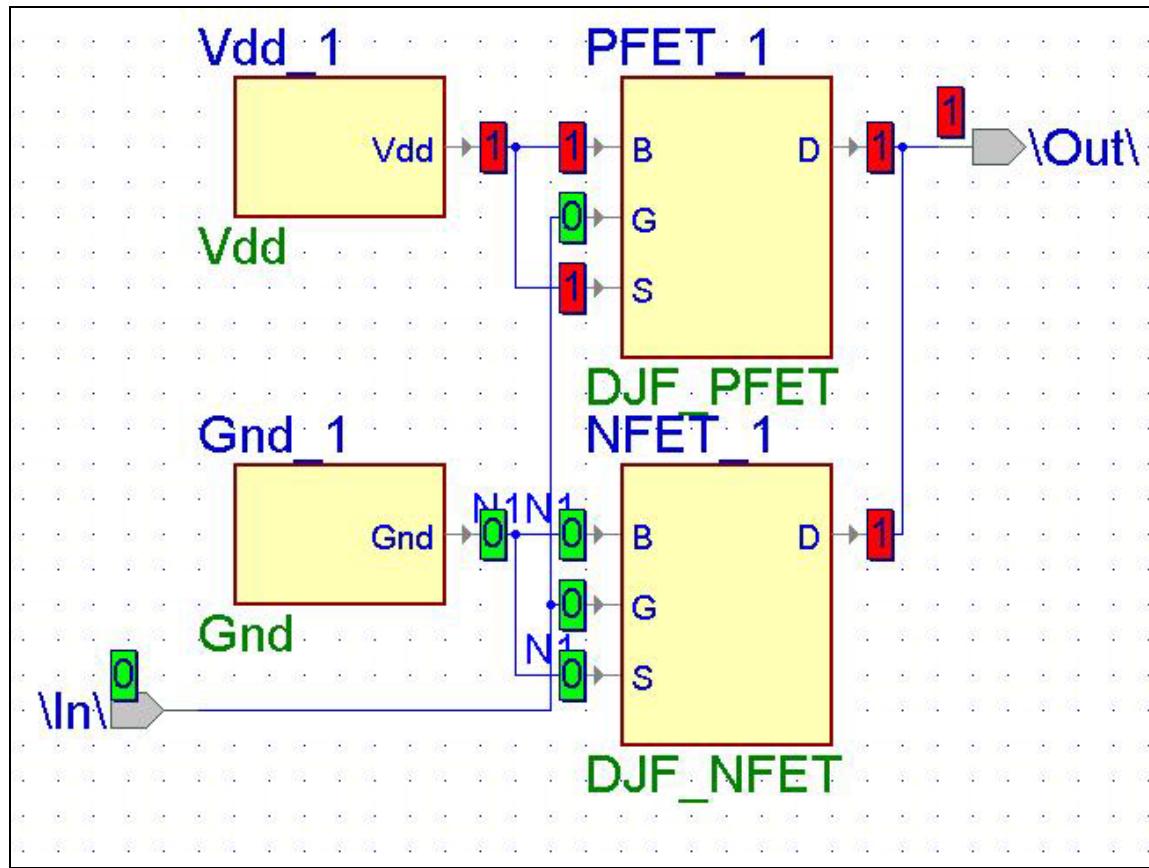


Figure 29. Example, Inverter – Generated Block Diagram for the Top Level

From the top-level graphic, it is possible to navigate down to the lower level *instanced entities* simply by left clicking the box representing the *entity* of interest. An example for the graphical representations of the entities described with behavioral descrip-

tions can be obtained by selecting the *instanced entity* DJF_NFET. The graphical representation of DJF_NFET during simulation is shown in Figure 30.

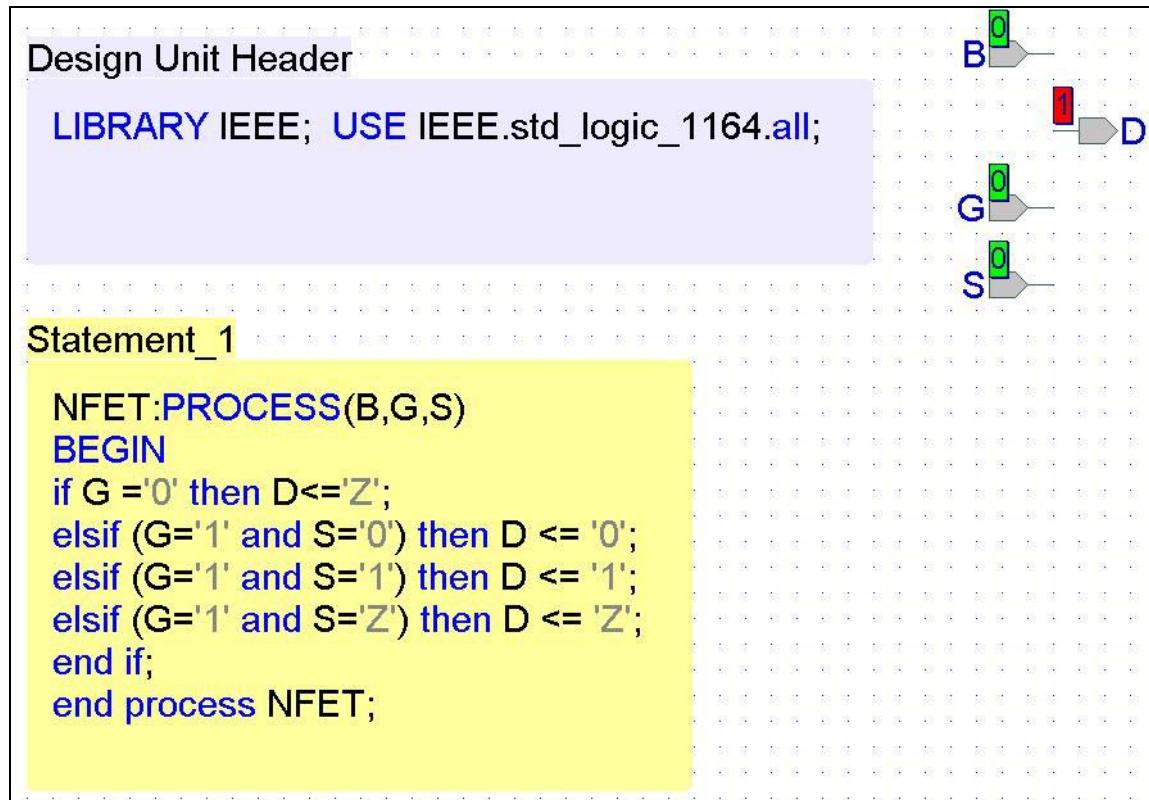


Figure 30. Example, Inverter –Block Diagram for DJF_NFET

The signal values can be saved as a list by adding them in a List Editor in the same way they can be added in a waveform editor. A list of *signal* values is very helpful in comparing the results with expected values for functional verification. Figure 31 displays a list of the signals for the example inverter in time. This file can be saved as a text file to be processed in any text editor or spreadsheet tool.

5. Reference

The words in *italics* are protected VHDL constructs. For further reference on Active HDLTM, refer to [14], the vendor firm web site.

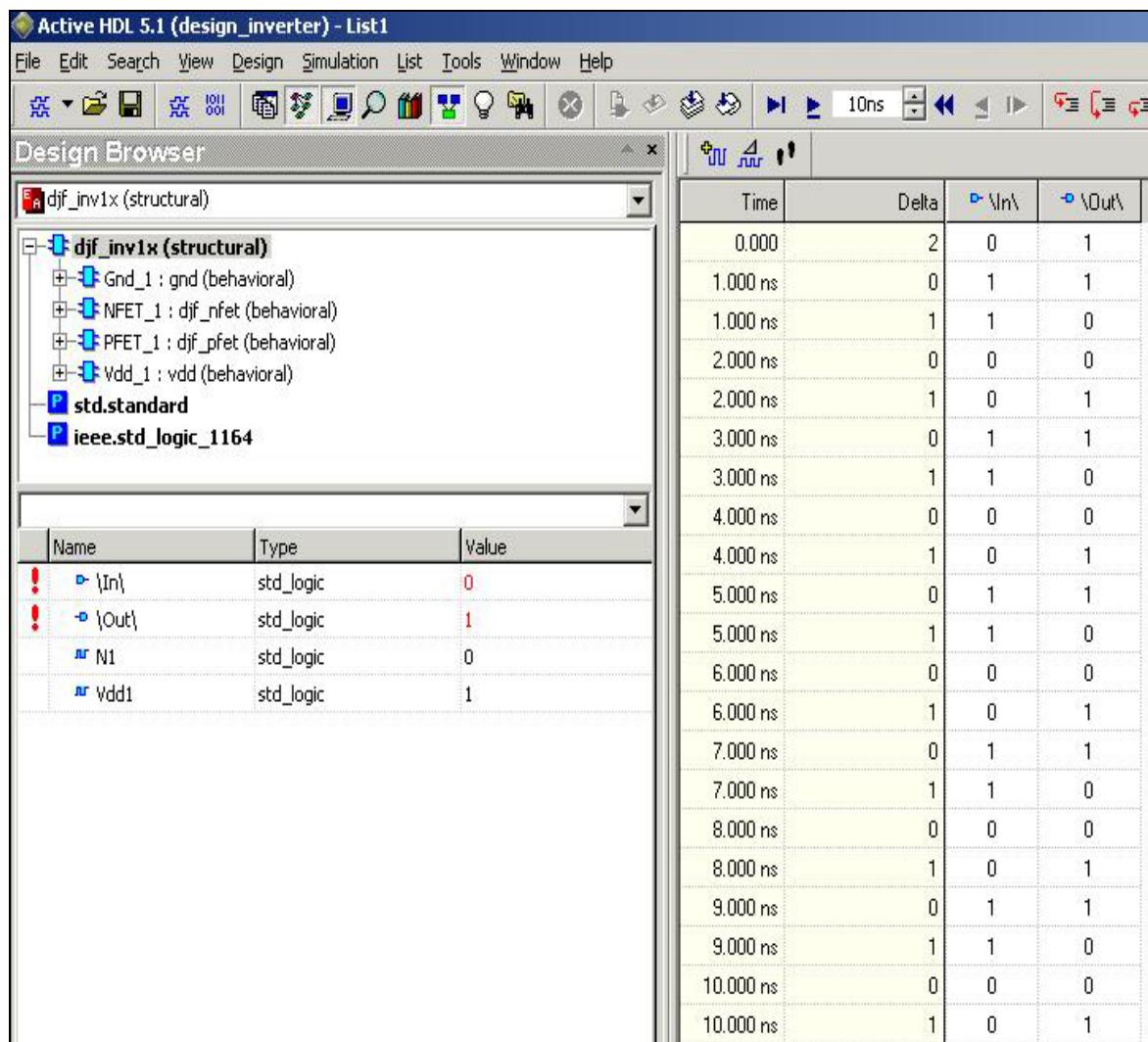


Figure 31. Example, Inverter –List File

This chapter provides an introduction to the VHDL programming language and a guide to the simulation software used to test and verify the DIS. The editors of the Active HDL™ are used extensively in testing the low level cells in the DIS as discussed in Chapter IV.

IV. VHDL SIMULATIONS OF LOW LEVEL CELLS

This chapter shows the simulation methodology of the low level cells used in hardware implementation of the DIS. The components of interest are shown as schematic captures. Input and output signals were introduced. The waveforms or list files used in simulations for verification of each cell are also provided.

A. VERIFICATION OF 5-BIT REGISTER

1. Logic Symbol and Schematic

The logic symbol and circuit schematic for a 5-bit register in S-EDIT are shown in Figure 32 and Figure 33, respectively. For additional information on the design of the circuit, refer to [3] and [12].

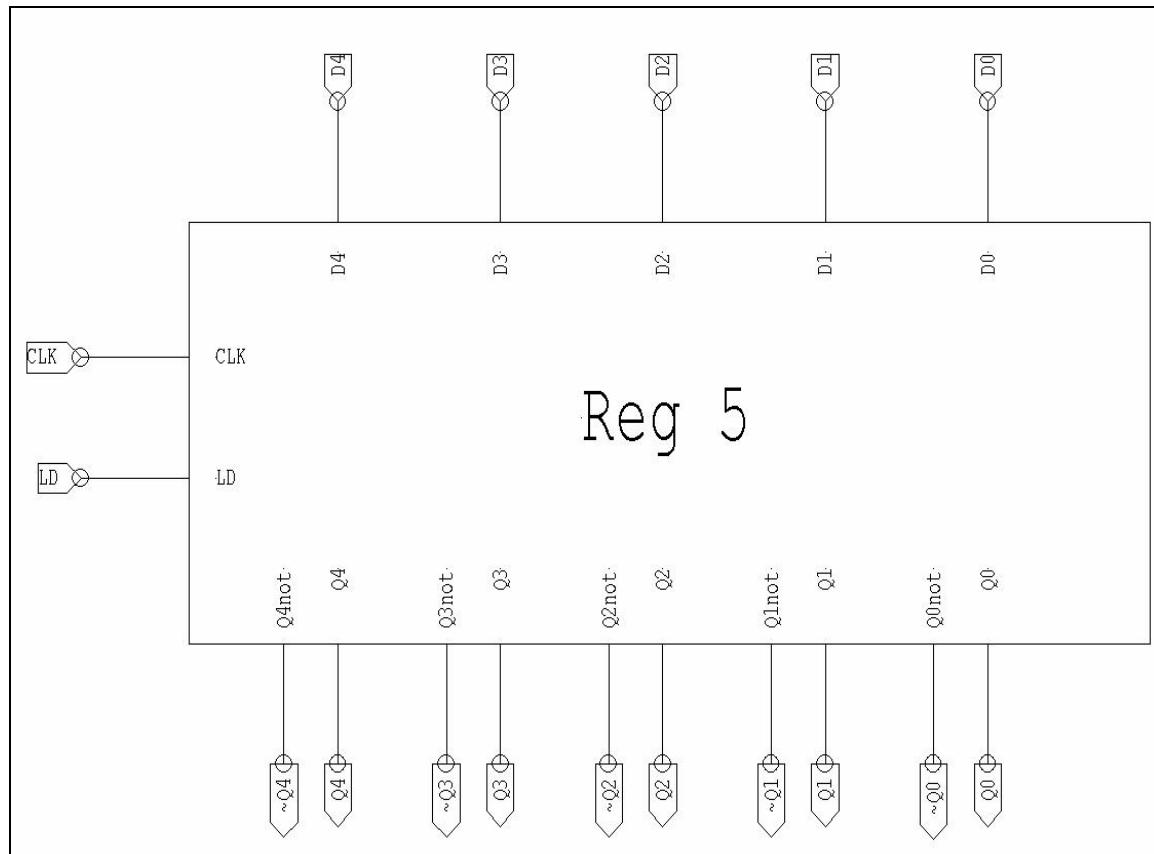


Figure 32. 5-Bit Register Logic Symbol in S-EDIT

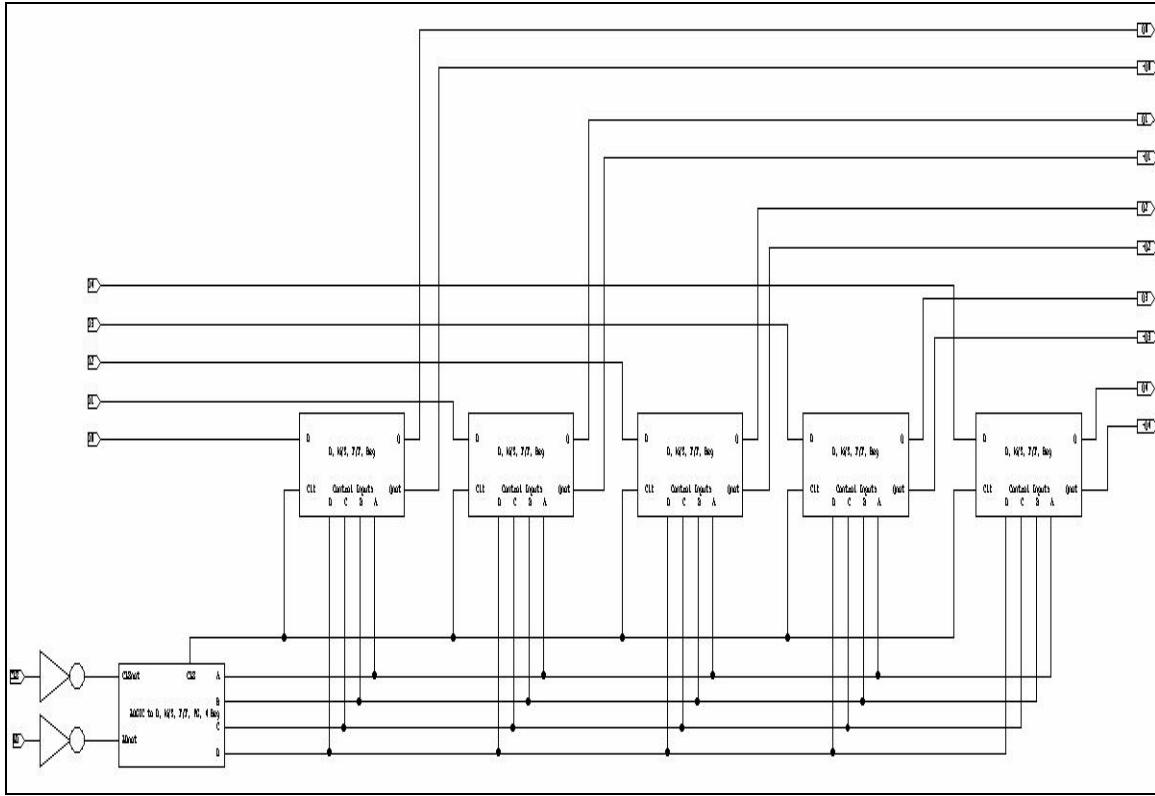


Figure 33. 5-Bit Register Circuit Schematic in S-EDIT

2. Signals

The input and output signals of Figures 32 and 33 are:

- CLK: Clocking signal
- LD: Load signal that latches the inputs into the registers on the rising edge of the clock
- D0 through D4: Input signals
- Q0 through Q4: Output signals that are stored in registers
- $\sim Q0$ through $\sim Q4$: Complements of signals Q0 through Q4.

3. Testing

The state table for the operation of a 1-bit register is given in Table 3. The time at which the inputs are applied is denoted by “t” while the previous value of a signal is represented with “ t_0 ”.

CLK	LD	D	Q (t)	$\sim Q(t)$
0 to 1	0	0	$Q(t_0)$	$Q(t_0)$
0 to 1	0	1	$Q(t_0)$	$Q(t_0)$
0 to 1	1	0	0	1
0 to 1	1	1	1	0
1 to 0	0	0	$Q(t_0)$	$Q(t_0)$
1 to 0	0	1	$Q(t_0)$	$Q(t_0)$
1 to 0	1	0	$Q(t_0)$	$Q(t_0)$
1 to 0	1	1	$Q(t_0)$	$Q(t_0)$

Table 3. State Table for 1-Bit Register

The methodology explained in Chapter III was used in testing. The VHDL code was used to generate a graphical representation of the circuit in Active HDL™, which is shown in Figure 34. The waveform used to test the circuit is presented in Figure 35.

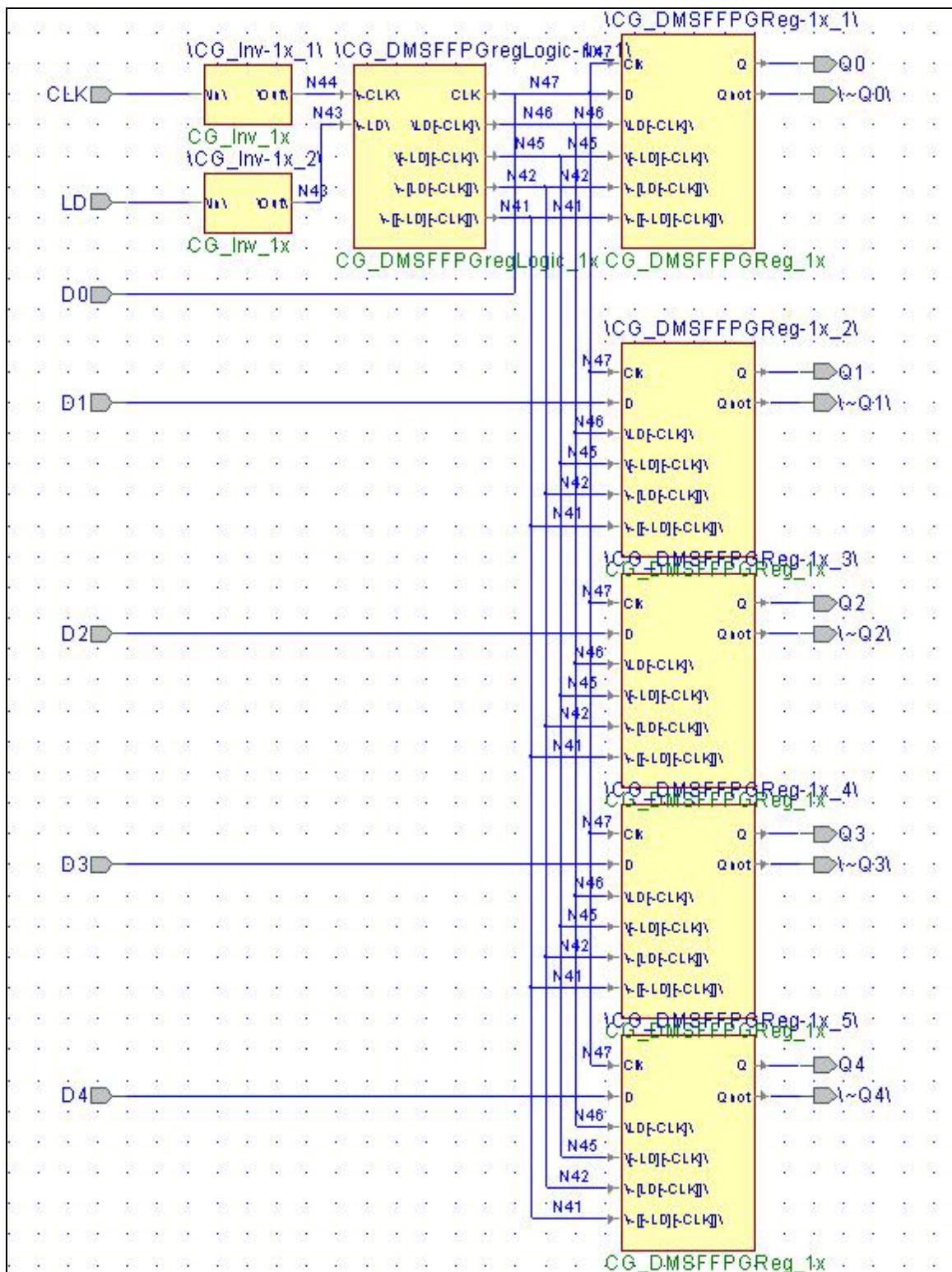


Figure 34. 5-Bit Register Graphical Representation

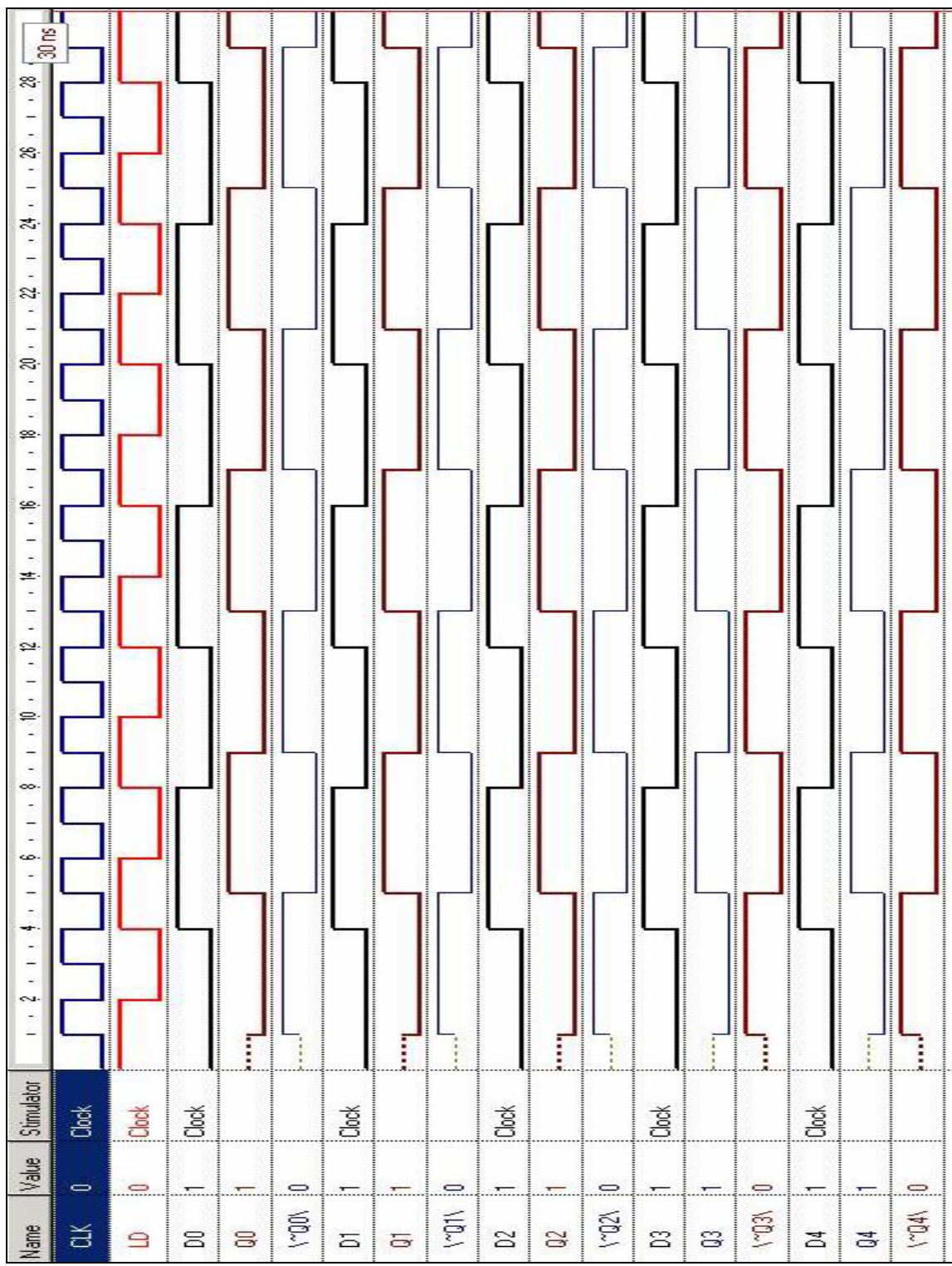


Figure 35. Waveform Showing Proper Operation for 5-Bit Register

4. Verification

The List File, shown in Figure 36, obtained from the simulation shows the values of the signals with respect to time.

Time	Delta	CLK	LD	D0	D1	D2	D3	D4	Q0	Q1	Q2	Q3	Q4	\^Q0\	\^Q1\	\^Q2\	\^Q3\	\^Q4\
0.000	0	0	1	0	0	0	0	0	U	U	U	U	U	U	U	U	U	U
1.000 ns	0	1	1	0	0	0	0	0	U	U	U	U	U	U	U	U	U	U
1.000 ns	10	1	1	0	0	0	0	0	U	U	U	U	U	1	1	1	1	1
1.000 ns	11	1	1	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
2.000 ns	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
3.000 ns	0	1	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
4.000 ns	0	0	1	1	1	1	1	1	0	0	0	0	0	1	1	1	1	1
5.000 ns	0	1	1	1	1	1	1	1	0	0	0	0	0	1	1	1	1	1
5.000 ns	10	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0
5.000 ns	11	1	1	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0
6.000 ns	0	0	0	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0
7.000 ns	0	1	0	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0
8.000 ns	0	0	1	0	0	0	0	0	1	1	1	1	1	0	0	0	0	0
9.000 ns	0	1	1	0	0	0	0	0	1	1	1	1	1	0	0	0	0	0
9.000 ns	10	1	1	0	0	0	0	0	1	1	1	1	1	1	1	1	1	1
9.000 ns	11	1	1	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
10.000 ns	0	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
11.000 ns	0	1	0	0	0	0	0	0	0	0	0	0	0	1	1	1	1	1
12.000 ns	0	0	1	1	1	1	1	1	0	0	0	0	0	1	1	1	1	1
13.000 ns	0	1	1	1	1	1	1	1	0	0	0	0	0	1	1	1	1	1
13.000 ns	10	1	1	1	1	1	1	1	0	0	0	0	0	0	0	0	0	0
13.000 ns	11	1	1	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0
14.000 ns	0	0	0	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0
15.000 ns	0	1	0	1	1	1	1	1	1	1	1	1	1	0	0	0	0	0

Figure 36. List Editor Showing Proper Operation for 5-Bit Register

It can be seen that the output transitions occurred at the low-to-high change of the clock signal as long as the input LD is high. Counters were used as input signals. It is important to keep the LD and D inputs stable during low-to-high clock transition to observe proper circuit behavior.

Table 4 compares the simulation results and state table for the circuit. By reviewing the data in Table 4 and comparing the columns labeled “Simulation Results” against the columns labeled “State Table”, it can be seen that the simulation ran correctly.

Control Inputs		State Table			Simulation Results		
CLK	LD	D	Q	$\sim Q$	D	Q	$\sim Q$
0 to 1	0	0	$D(t_0)$	$\sim D(t_0)$	0	$D(t_0)$	$\sim D(t_0)$
0 to 1	0	1	$D(t_0)$	$\sim D(t_0)$	1	$D(t_0)$	$\sim D(t_0)$
0 to 1	1	0	0	1	0	0	1
0 to 1	1	1	1	0	1	1	0
1 to 0	0	0	$D(t_0)$	$\sim D(t_0)$	0	$D(t_0)$	$\sim D(t_0)$
1 to 0	0	1	$D(t_0)$	$\sim D(t_0)$	1	$D(t_0)$	$\sim D(t_0)$
1 to 0	1	0	$D(t_0)$	$\sim D(t_0)$	0	$D(t_0)$	$\sim D(t_0)$
1 to 0	1	1	$D(t_0)$	$\sim D(t_0)$	1	$D(t_0)$	$\sim D(t_0)$

Table 4. Comparing Simulation Results and State Table for 5-Bit Register

B. VERIFICATION OF $\sim S/\sim R$ LATCH

1. Logic Symbol and Schematic

The logic symbol and circuit schematic for an $\sim S/\sim R$ Latch in S-EDIT are shown in Figures 37 and 38, respectively.

Buffers in Figure 38 are added to the schematic before extracting the VHDL code to accommodate a rule in Active HDL™ requiring users to avoid networks that go to a logic gate input and an output port. Furthermore, in order to avoid assigning an output signal as an input signal for the circuit itself, a behavioral description for the latch was inserted in the VHDL code, which is given in Figure 39.

2. Signals

- $\sim S/\sim R$: Complement of Set/Reset signals in a regular S/R latch.
- Q/QN: Stored latch value at time “t”.

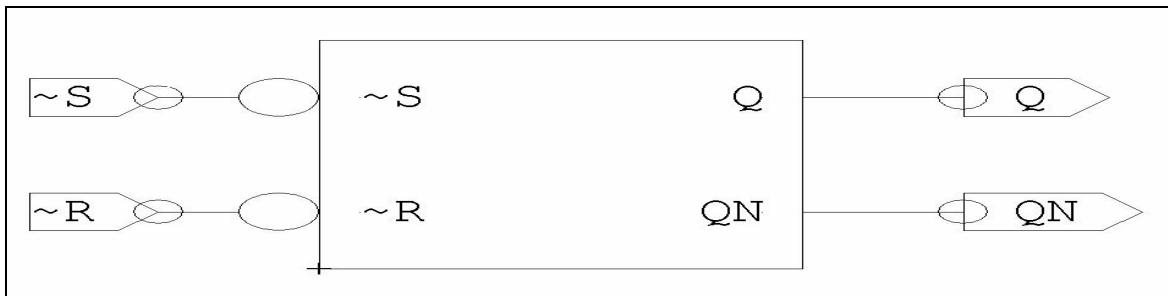


Figure 37. ~S/~R Latch Logic Symbol in S-EDIT

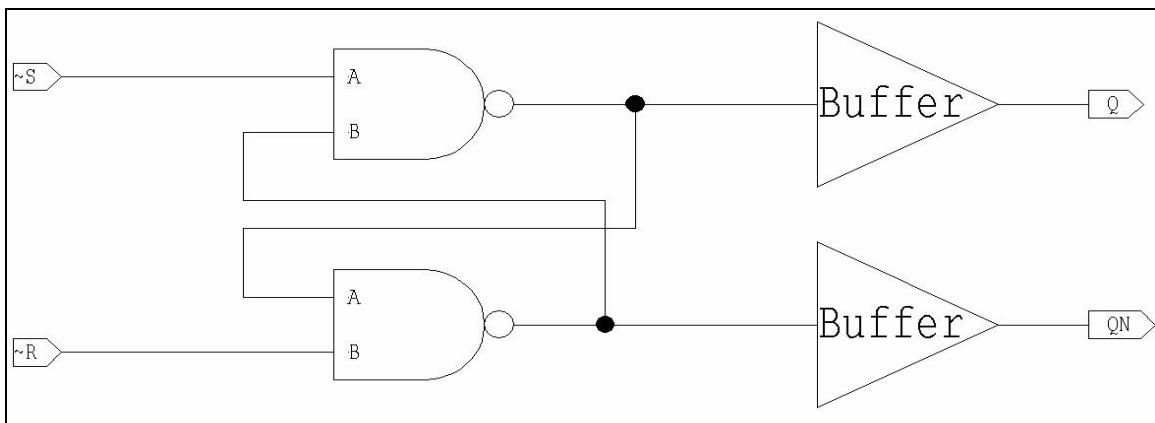


Figure 38. ~S/~R Latch Circuit Schematic in S-EDIT

3. Testing

The state table for the operation of the $\sim S/\sim R$ is given in Table 5. The present input values are denoted by “t” while the previous value of a signal is represented with “ t_0 ”.

$\sim S$	$\sim R$	$Q(t)$	$QN(t)$
1	1	$Q(t_0)$	$QN(t_0)$
1	0	0	1
0	1	1	0
0	0	Not Allowed	

Table 5. State Table for $\sim S/\sim R$ Latch

The behavioral description implements the state table by using two different variables for Q_now and QN_now to define the latch state for initialization purposes. Since the signal values are computed in a single simulation cycle, assigning unknown values to any input would result in unknown states at the outputs, which in turn would cause an infinite loop resulting in incorrect simulation results.

Although the ($\sim S, \sim R$)=(0,0) case is not allowed in the state table, for initialization purposes, this set of inputs are included in the behavioral description.

```

ARCHITECTURE behavioral OF DTM_FFnotSnotR IS
BEGIN
    latch: process(\~R\, \~S\) is
variable Q_now, QN_now :std_logic;
begin

    if (\~R\='0' and \~S\='0') then
        Q <='1';
        QN <='1';
        Q_now :='1';
        QN_now :='1';
    end if;
    if (\~R\='1' and \~S\='0') then
        Q <='1';
        QN <='0';
        Q_now :='1';
        QN_now :='0';
    end if;
    if (\~R\='0' and \~S\='1') then
        Q <='0';
        QN <='1';
        Q_now :='0';
        QN_now :='1';
    end if;
    if (\~R\='1' and \~S\='1') then
        Q <=Q_now;
        QN <=QN_now;
    end if;
end process latch;
end behavioral;
```

Figure 39. Behavioral Description of $\sim S/\sim R$ Latch

The waveform used in testing the circuit is shown in Figure 40. The state of the latch is initialized to the $Q, QN = (1,1)$ case in the behavioral description since these values make the NAND gates sensitive to the $\sim S$ and $\sim R$ inputs.

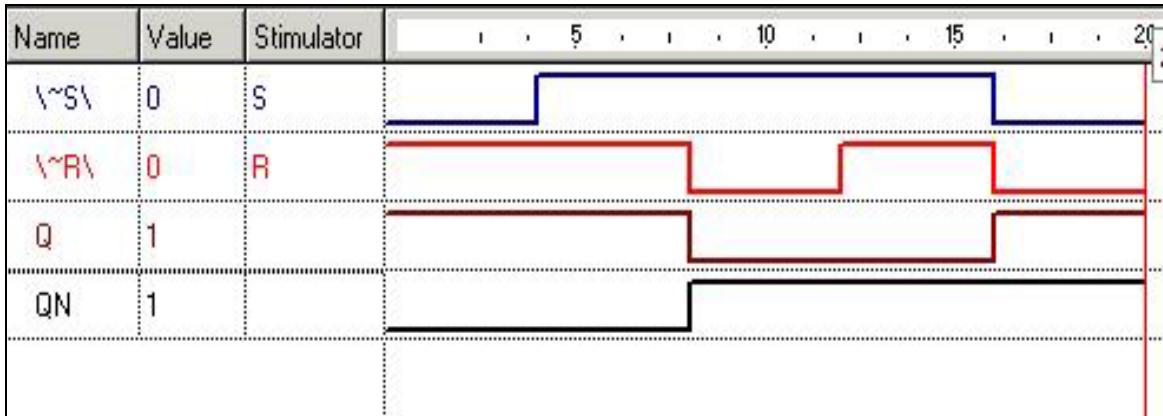


Figure 40. Waveform Showing Proper Operation for $\sim S/\sim R$ Latch

4. Verification

The List File is given in Figure 41, while Table 6 compares the simulation results, and the state table.

Time	Delta	$\sim S$	$\sim R$	Q	QN
0.000	0	0	1	U	U
0.000	1	0	1	1	0
4.000 ns	1	1	1	1	0
8.000 ns	1	1	0	1	0
8.000 ns	2	1	0	0	1
12.000 ns	1	1	1	0	1
16.000 ns	1	0	0	0	1
16.000 ns	2	0	0	1	1

Figure 41. List Editor Showing Proper Operation for $\sim S/\sim R$ Latch

Inputs		State Table		Simulation Results	
$\sim S$	$\sim R$	Q	QN	Q	QN
0	1	1	0	1	0
1	1	1	0	1	0
1	0	0	1	0	1
1	1	0	1	0	1
0	0	Not Allowed		1	1

Table 6. Comparing Simulation Results and State Table for $\sim S/\sim R$ Latch

C. VERIFICATION OF 12-BIT COMPARATOR

1. Logic Symbol and Schematic

A 12-bit comparator is used in the overhead circuitry as a part of the self-test mechanism. It compares the number of test vectors generated, which was supplied by a binary counter, and the desired test vector number provided externally. If the two numbers are the same, the output signal causes the cascade of Range Bin Processors (RBP s) to switch into the Maintenance Mode. The correct operation of the comparator in combination with the counter is of great importance to the self-test logic. The comparator's logic symbol and schematic are given in Figures 42 and 43, respectively.

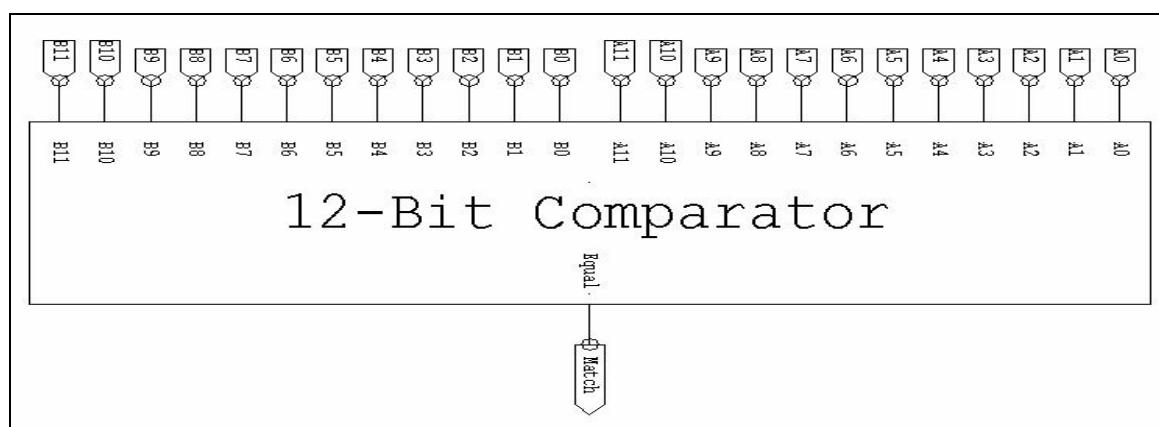


Figure 42. 12-Bit Comparator Logic Symbol in S-EDIT

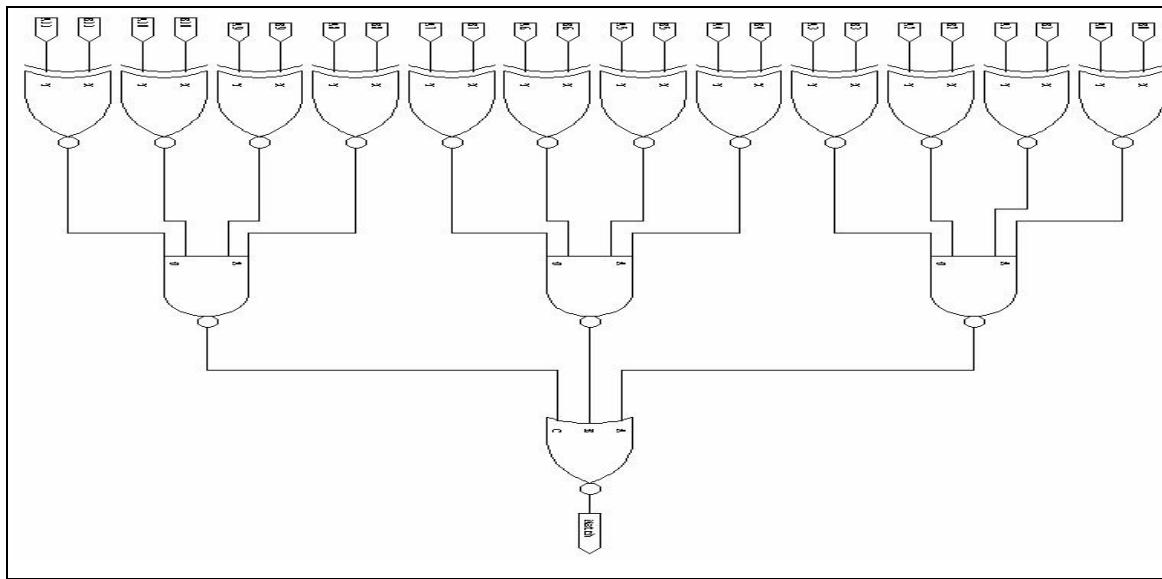


Figure 43. 12-Bit Comparator Circuit Schematic in S-EDIT

2. Signals

The input and output signals of Figures 42 and 43 are:

- A0 through A11: Inputs from the counter
- B0 through B11: Off-Chip Count inputs
- Equal: Output signal effecting Operate/Maintenance input to the RBP s via an $\sim S/\sim R$ latch.

3. Testing

The truth table for the comparator is given in Table 7.

A	B	Match
$A \neq B$		0
$A = B$		1

Table 7. Truth Table for 12-Bit Comparator

By using every possible value for the A and B signals, and by observing the output Match signal, an exhaustive test was conducted. A part of the waveform generated is shown in Figure 44. The graphical representation generated in Active HDL™ is given in Figure 45.

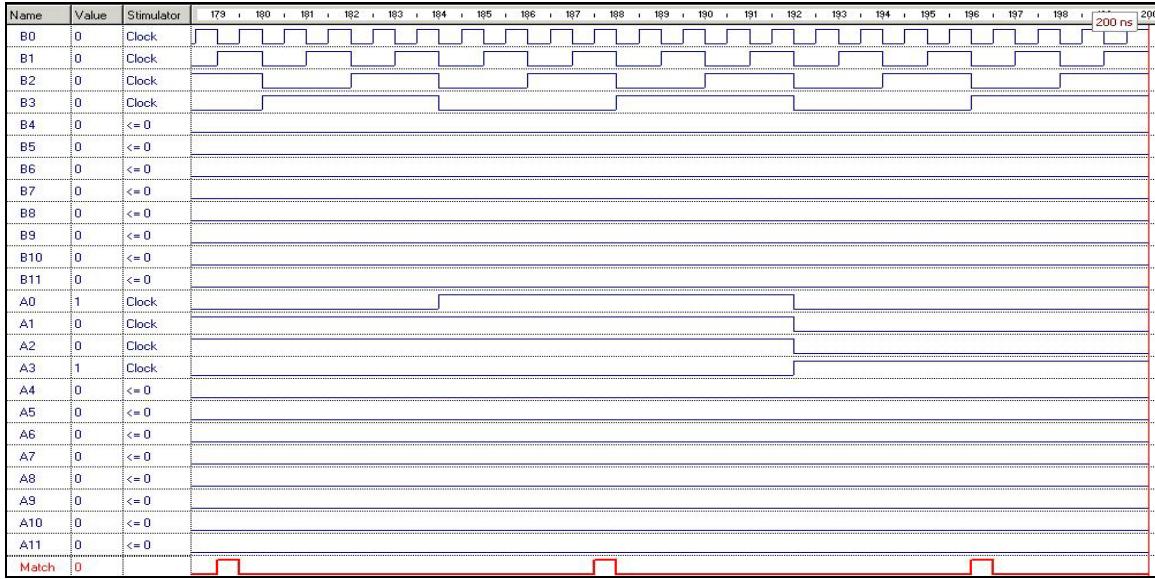


Figure 44. Waveform Showing Proper Operation for 12-Bit Comparator

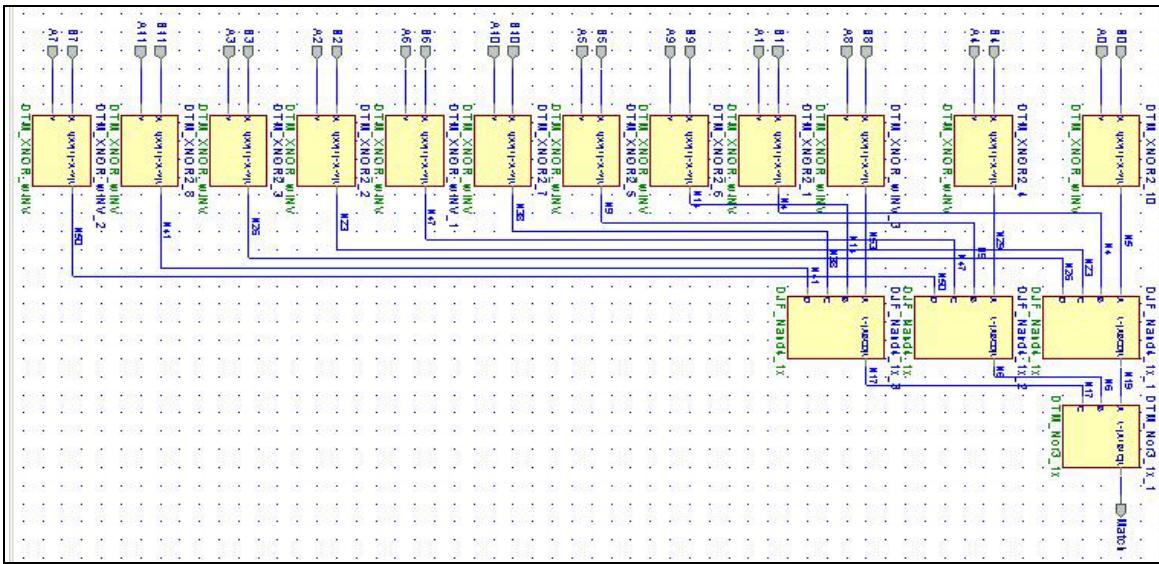


Figure 45. 12-Bit Comparator Graphical Representation

4. Verification

Results are verified by comparing the List File for the simulation for the A and B vectors and the resultant Match signal with a separate Matlab generated text file. The results perfectly match with the state table. The algorithm used to generate the Matlab code and set up the input values in Active HDL is presented in Table 8.

MATLAB	ACTIVE HDL™ Waveform Editor							
	Signal Stimulator Clock Periods							
for every_value of vector_A begin for every_value of Vector B begin if Value_A=Value_B then Match=1; Else Match=0; end; end;	A0	2^0	A6	2^6	B0	2^{12}	B6	2^{18}
	A1	2^1	A7	2^7	B1	2^{13}	B7	2^{19}
	A2	2^2	A8	2^8	B2	2^{14}	B8	2^{20}
	A3	2^3	A9	2^9	B3	2^{15}	B9	2^{21}
	A4	2^4	A10	2^{10}	B4	2^{16}	B10	2^{22}
	A5	2^5	A11	2^{11}	B5	2^{17}	B11	2^{23}

Table 8. Exhaustive Test and Verification Algorithm for 12-Bit Comparator

D. VERIFICATION OF 5-BIT ADDER

1. Logic Symbol and Schematic

Different types of adders are used in the Digital Image Synthesizer (DIS). Their proper operation is of great importance for correct target signature generation. Here, a 5-Bit Adder, whose logic symbol/schematic are provided in Figures 46 and 47, is tested for proper operation. For further information on the carry look-ahead adder design, refer to [3].

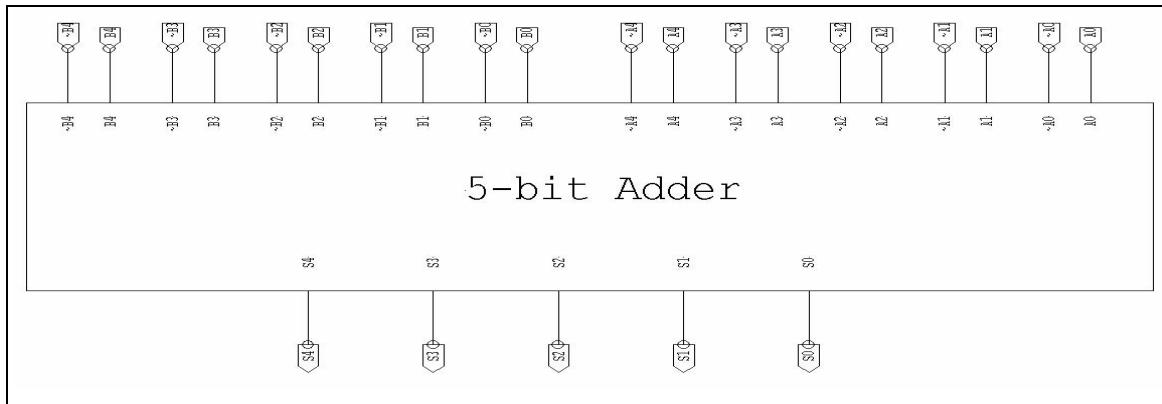


Figure 46. 5-Bit Adder Logic Symbol in S-EDIT

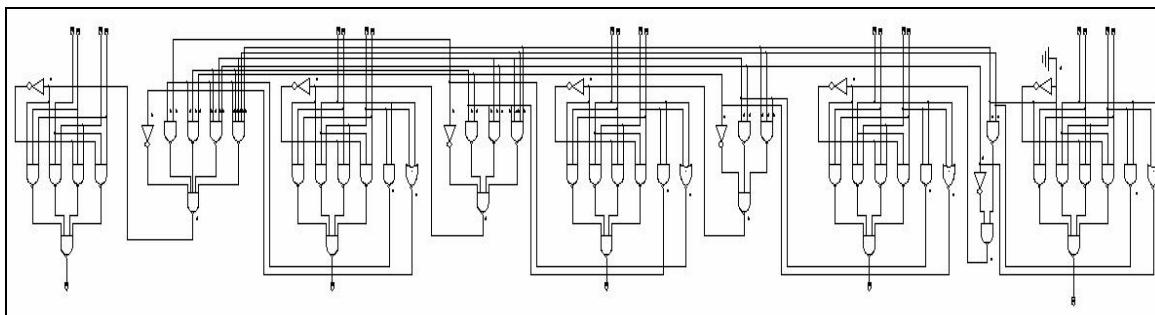


Figure 47. 5-Bit Adder Circuit Schematic in S-EDIT

2. Signals

The input and output signals of Figures 46 and 47 are:

- A0 through A4 and B0 through B4 represent binary numbers to be added together.
- $\sim A_0$ through $\sim A_4$ and $\sim B_0$ through $\sim B_4$ represent the complement of the input signals supplied by the pipeline register preceding the adder.
- S0 through S4: Resulting binary number

3. Testing

Addition results in a 5-bit number, which ignores carry out for the final result.

Table 9 shows the state table for the 5-Bit Adder in the decimal number system.

A	B	S
0	0 through 31	0 through 31
1	0 through 31	1 through 31, 0
2	0 through 31	2 through 31, 0,1
...
29	0 through 31	29, 30, 31,0,.., 28
30	0 through 31	30, 31,0,.., 29
31	0 through 31	31, 0,.., 30

Table 9. State Table for 5-Bit Adder

By using every possible value for A(4:0) and B(4:0) and by observing the output S (4:0), an exhaustive test was conducted. The graphical representation generated in Active HDL™ is given in Figure 48. A part of the waveform generated is shown in Figure 49.

4. Verification

For a complete verification of the adder, an algorithm similar to the one used for the 12-Bit Comparator was applied. It is given in Table 10.

The Matlab results are compared to the simulation values and the operation of the 5-bit adder confirmed for every possible value by comparing the List File with a separate Matlab generated file.

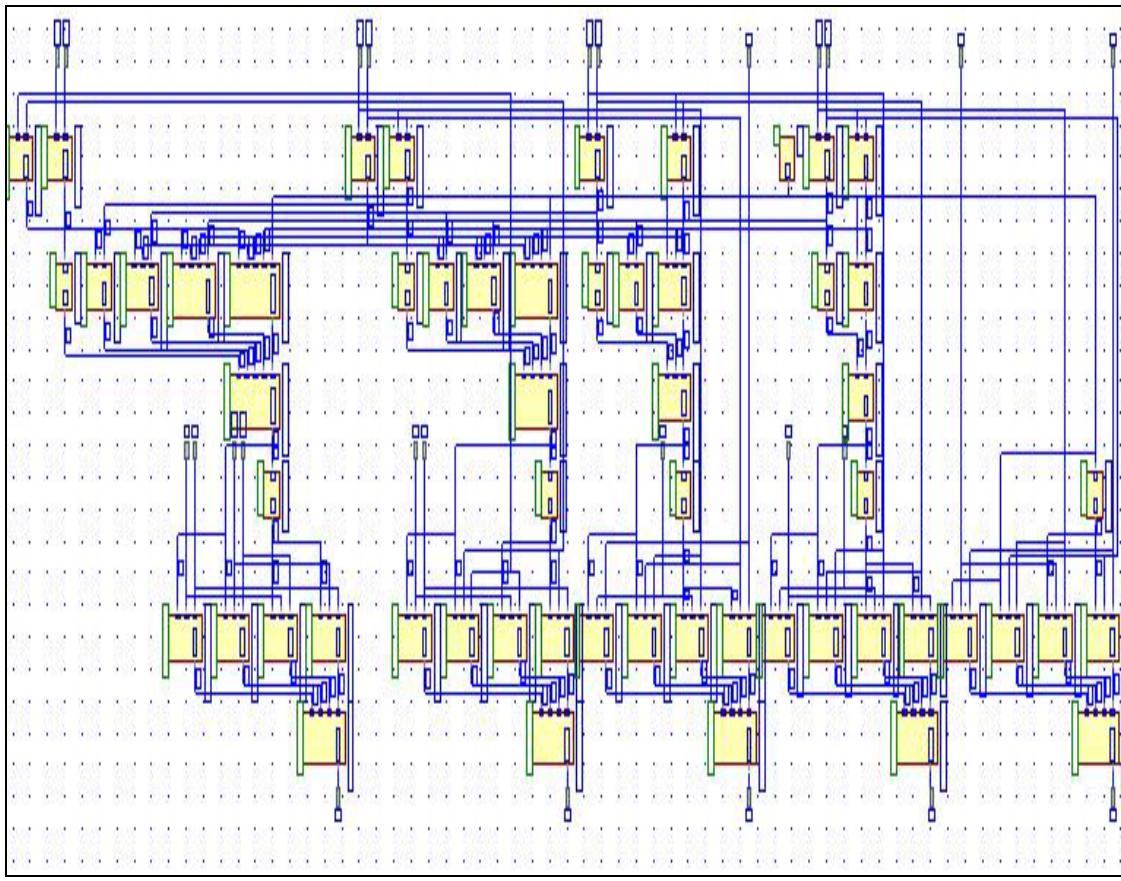


Figure 48. 5-Bit Adder Graphical Representation

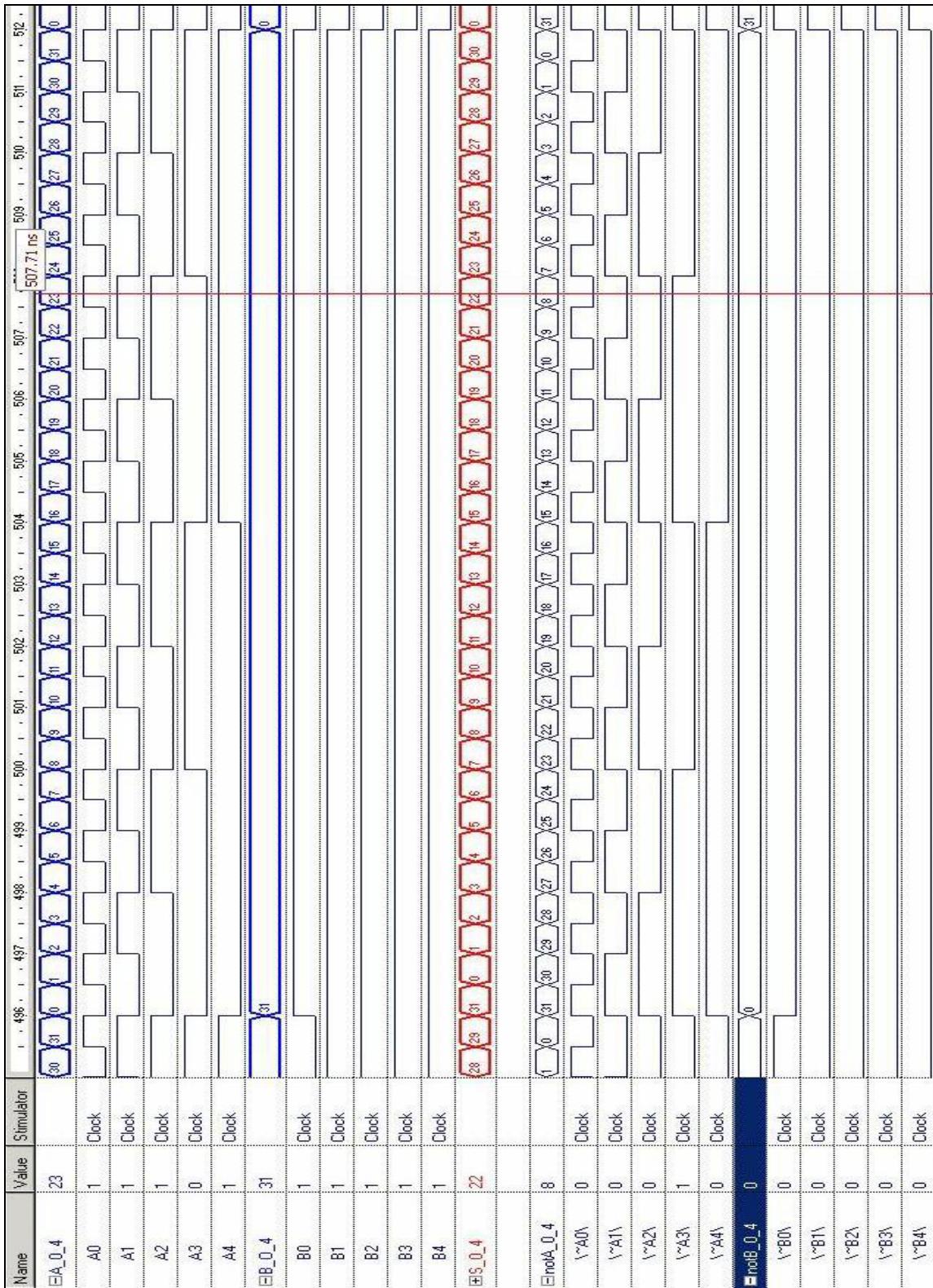


Figure 49. Waveform Showing Proper Operation for 5-Bit Adder

MATLAB		ACTIVE HDL™ Waveform Editor Signal Stimulator Clock Periods			
for every_value of vector_A	begin	A0	2^0	B0	2^5
for every_value of Vector B	begin	A1	2^1	B1	2^6
begin		A2	2^2	B2	2^7
Sum = vector_A + vector_B		A3	2^3	B3	2^8
if Sum>=2^5 then		A4	2^4	B4	2^9
Sum=Sum-2^5;		$\sim A / \sim B$ signals are generated with the complements of the clock signals above.			
end;					
end;					

Table 10. Exhaustive Test and Verification Algorithm for 5-Bit Adder

E. VERIFICATION OF 1 BIT 4-TO-1 MULTIPLEXER

1. Logic Symbol and Schematic

The phase samples for the cascade of RBP s can be sourced from four different sources. A 6-bit 4-to-1 multiplexer steers one of the inputs set into the RBP cascade. It consists of six identical 1-bit 4-to-1 multiplexers. The logic symbol and circuit schematic for one bit is shown in Figures 50 and 51, respectively.



Figure 50. 1-Bit 4-to-1 Multiplexer Logic Symbol in S-EDIT

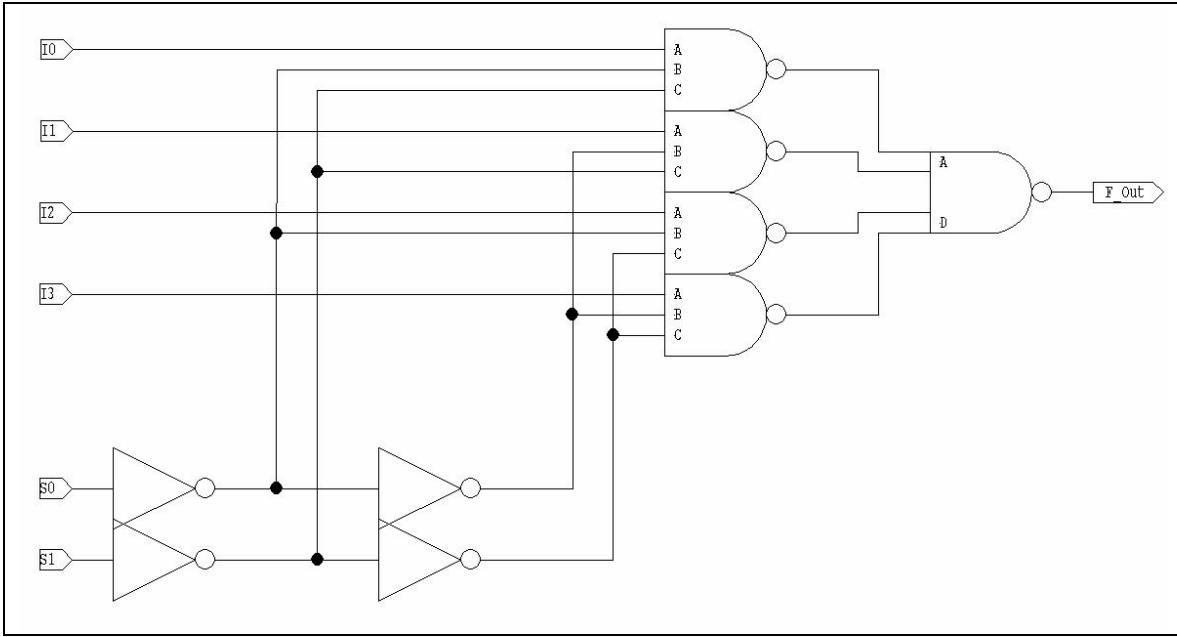


Figure 51. 1-Bit 4-to-1 Multiplexer Circuit Schematic in S-EDIT

2. Signals

The input and output signals of Figures 50 and 51 are:

- I0 through I3 are the signals into the multiplexer
- S1 and S0 are the signals that select the data to be steered
- F_Out is the selected signal among the inputs

3. Testing

The state table for the multiplexer is given in Table 11. A complete testing was conducted using all possible input combinations.

I3	I2	I1	I0	S1	S0	F_OUT
D	C	B	A	0	0	A
D	C	B	A	0	1	B
D	C	B	A	1	0	C
D	C	B	A	1	1	D

Table 11. State Table for 1-Bit 4-to-1 Multiplexer

The waveform used is shown in Figure 52, while the graphical representation generated in Active HDL™ is given in Figure 53.

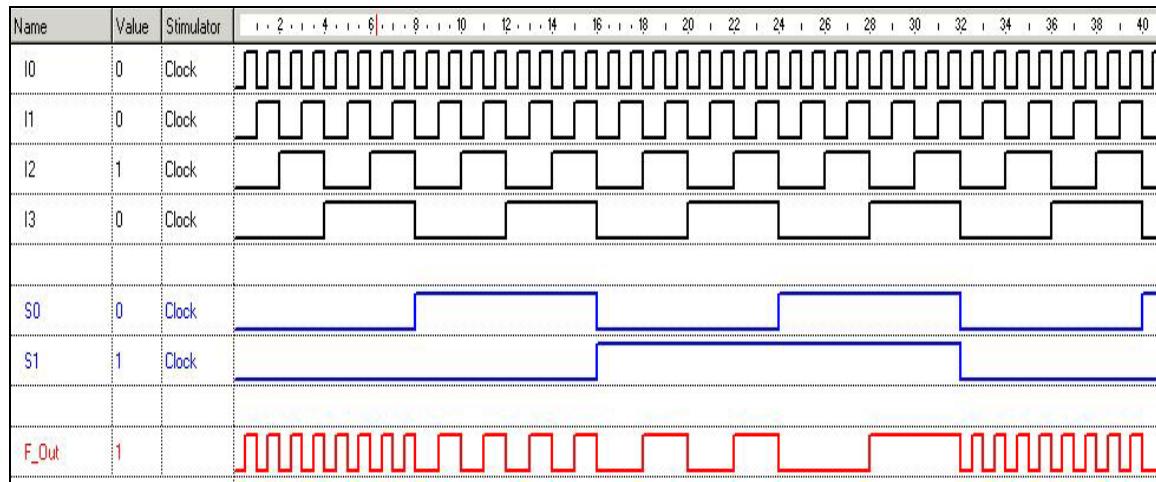


Figure 52. Waveform Showing Proper Operation for the Multiplexer

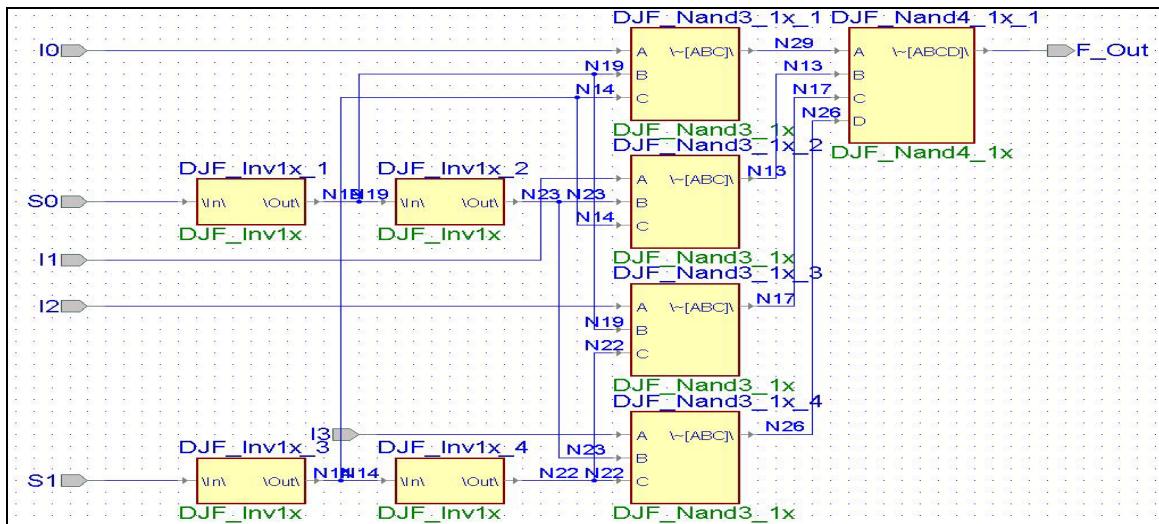


Figure 53. 1-Bit 4-to-1 Multiplexer Graphical Representation

4. Verification

In the waveform editor, one of the useful tools is the ability to compare waveforms. The procedure to compare two waveforms is as follows:

- Assign the desired input path number to S1 and S0 as a binary number. For instance, if it is desired to steer I0, force the control inputs to be $(S1, S0) = (0,0)$ using a proper stimulator.
- Assign values for $(I3:I0)$ in a counter fashion in the same way as in Figure 52 and run the simulation.
- Select F_Out and the proper I input at the same time by using the shift key and left mouse click.
- From the menu select Waveform > Compare Waveform
- There should not be any difference between the two waveforms.
- Repeat the procedure for all input paths using proper control signal values.

Using the procedure above, the circuit was tested and proved to be working properly. Figure 54 shows a part of the waveform used to test the I2 path by applying $(1,0)$ for $(S1, S0)$.

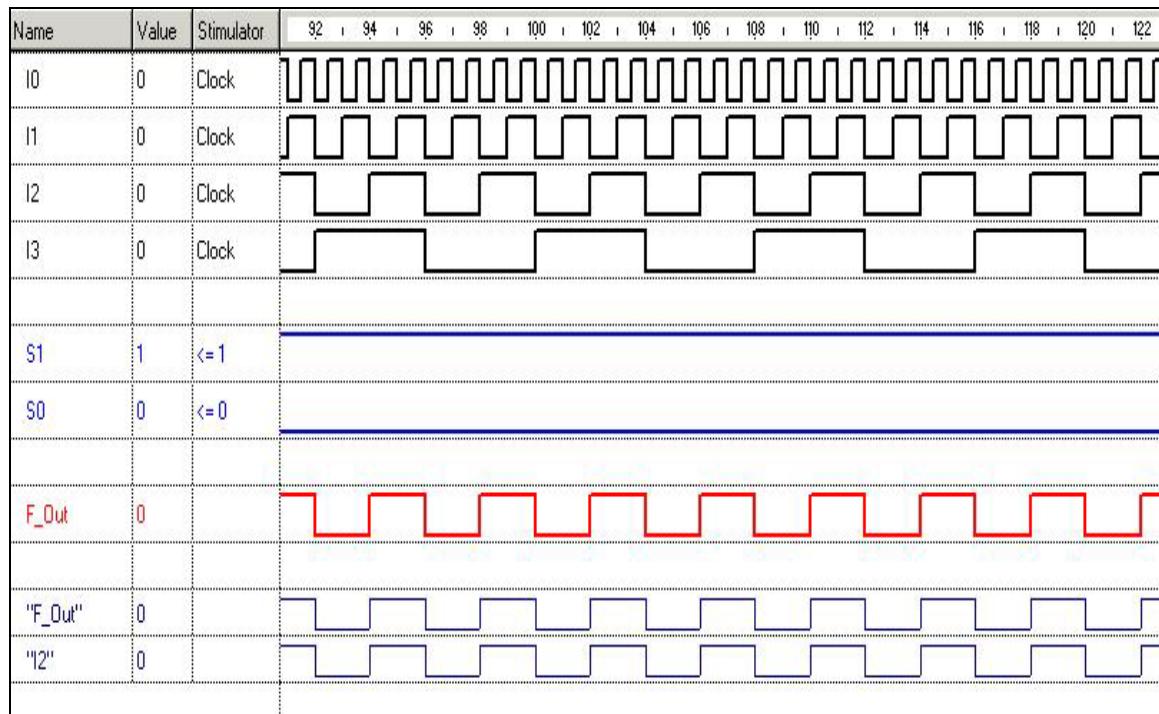


Figure 54. Exhaustive Test and Verification of 1-Bit 4-to-1 Multiplexer

This chapter has discussed the verification of the low level cells. VHDL Simulation results were compared against the C++ simulation results. The low level cells were tested and verified to operate properly. The next step in modeling and simulation of the DIS was the testing of the higher-level components and the data paths. Chapter V presents the methodology of testing the complete design.

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V. VHDL SIMULATIONS OF THE DIS CHIP

This chapter summarizes the tests conducted to verify the data paths and several functional blocks, self-test logic and phase extraction circuit. Overall DIS system was also tested with a 16 RBP block and verified to be functionally operating.

A. DATA FLOW PATHS

1. General View

Figure 55 contains the general block diagram of the Digital Image Synthesizer (DIS), with the overhead control circuitry.

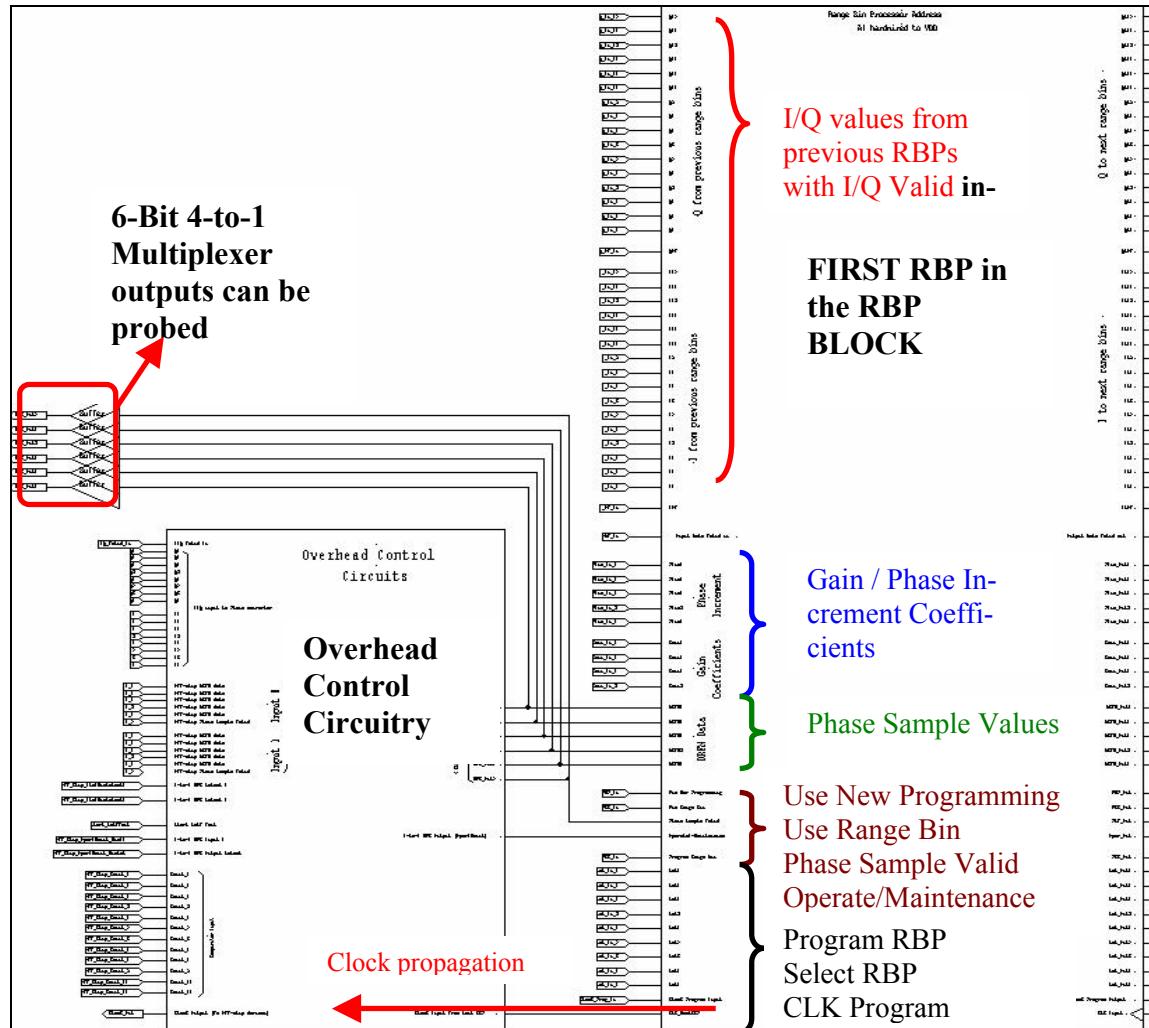


Figure 55. General Block Diagram of the DIS with the Overhead Control Circuitry

There are four data paths for the phase sample values. Two of them are for external input of the phase sample values into the Range Bin Processors (RBP s). Path 4 accomplishes the phase sample value extraction from in-phase (I) and quadrature (Q) inputs while Path 3 feeds the RBP s with test vectors to accomplish the self-test function. The inputs to those paths can be observed easily in the logic diagram of the overhead control circuitry in Figure 56, while the circuit schematic is given in Figure 57.

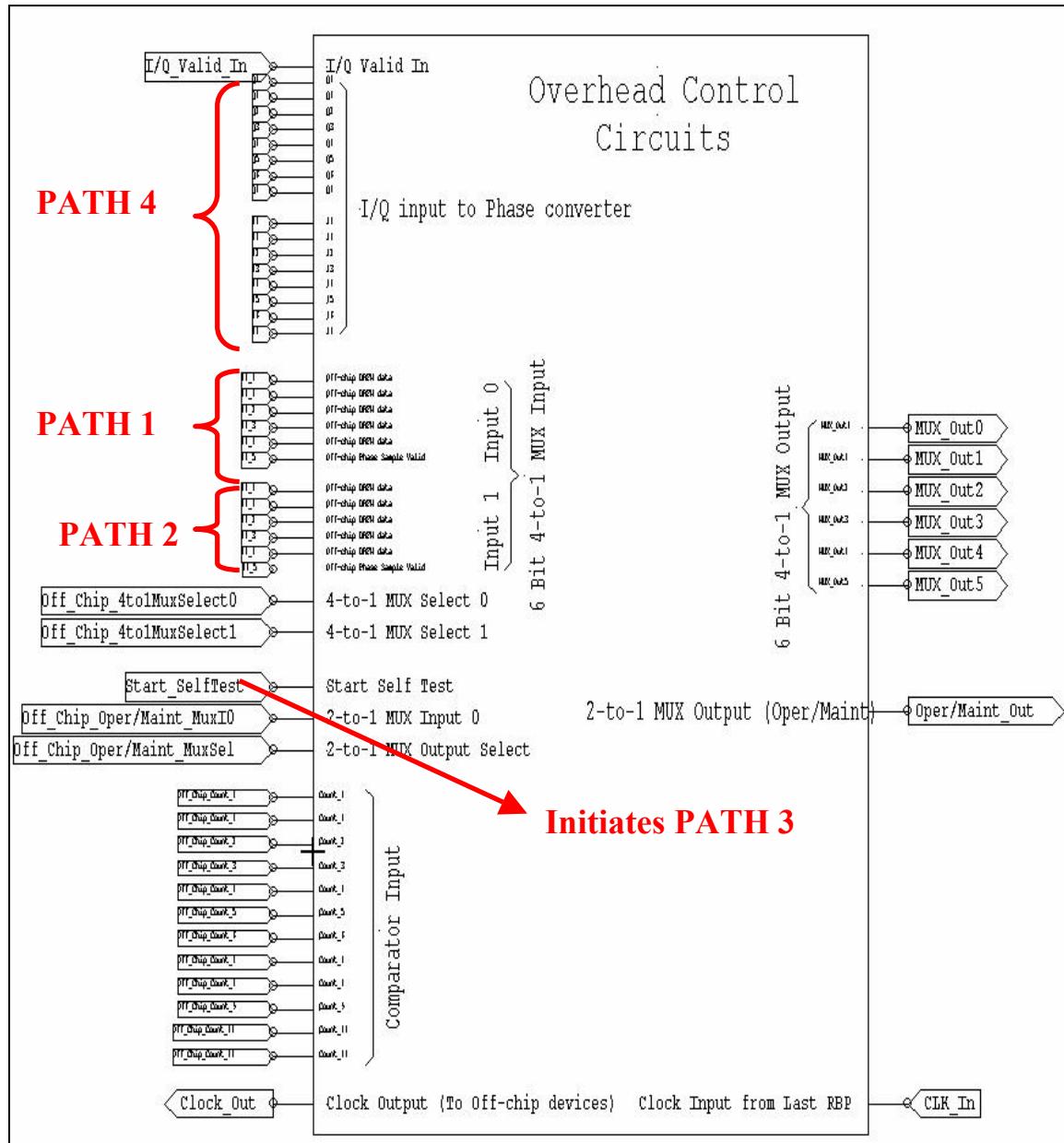


Figure 56. Logic Diagram of Overhead Control Circuitry

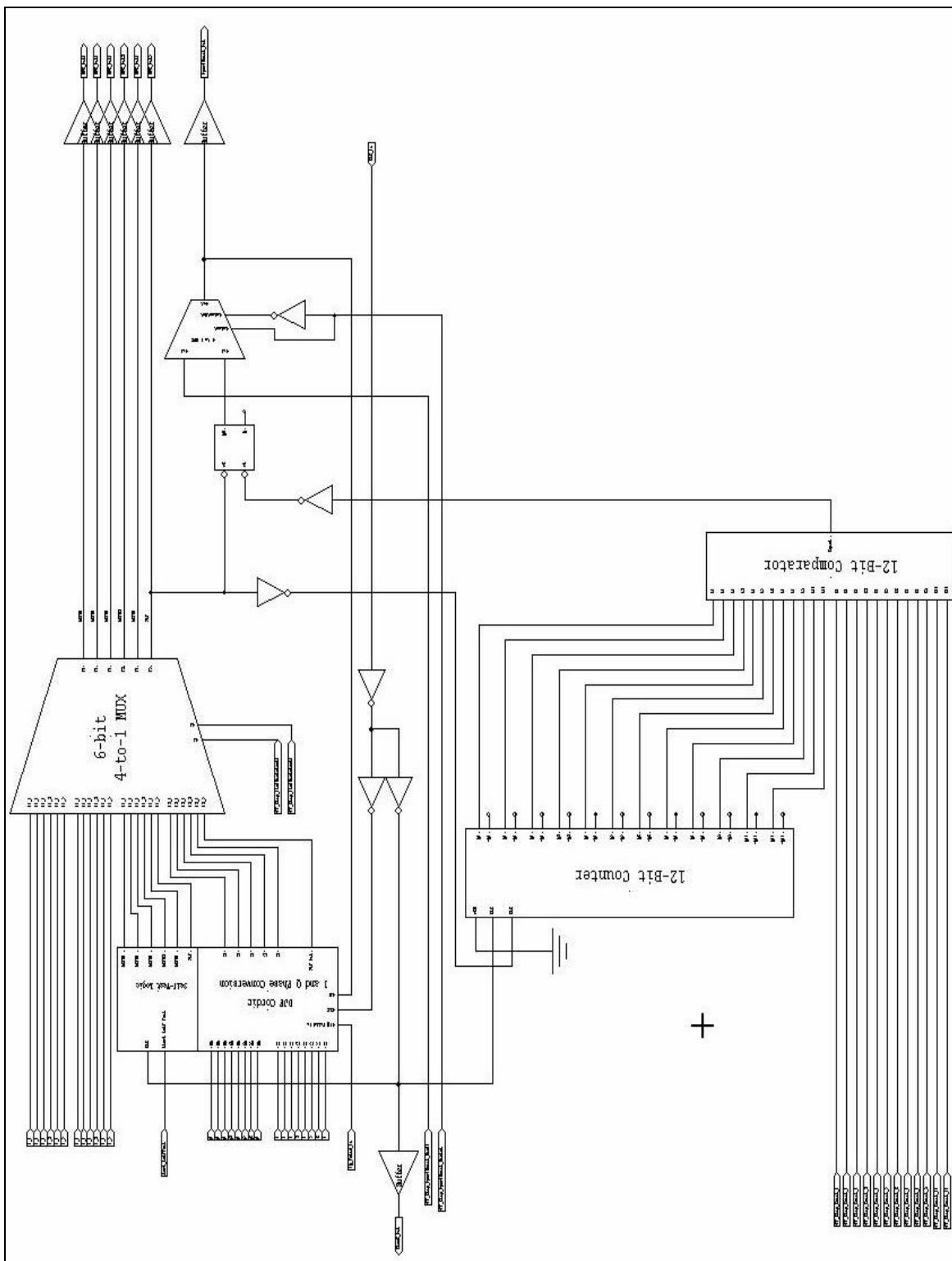


Figure 57. Circuit Schematic of Overhead Control Circuitry

2. Path 1 – External Phase Sample Values to RBPs

The first data path is shown in Figure 58. The off-chip inputs may be used directly to feed the Range Bin Processors (RBPs) with phase sample values. The 6-bit 4-to-1 multiplexer steers five-bit phase information along with the 1-bit Phase Sample Valid (PSV) signal that indicates a valid phase sample is ready to be processed. The 4-to-1 multiplexer select inputs should be programmed to choose the first path. The Operate/ Maintenance signal input to the RBP s is forced to “high” using a 1-bit 2-to-1 multiplexer select input and off-chip Operate/ Maintenance input. The former should be “low” while the latter is “high”. Table 12 shows the control inputs and their required values to test the first path.

3. Path 2 – External Phase Sample Values to RBPs

The second data path is nothing but a duplicate of the Path 1. It may be used as a substitute for the first path and allows for future upgrades of the external circuitry. Path 2 can be seen in Figure 59 while Table 12 shows the control signals and their required values to test the path.

Control Inputs	PATH1	PATH2
	Required Value	Required Value
Off_Chip_4to1MuxSelect0	Low (0)	High (1)
Off_Chip_4to1MuxSelect1	Low (0)	Low (0)
Off_Chip_Oper/Maint_MuxIO	High (1)	High (1)
Off_Chip_Oper/Maint_MuxSel	Low (0)	Low (0)

Table 12. Control Signals to Test Path 1 and Path 2

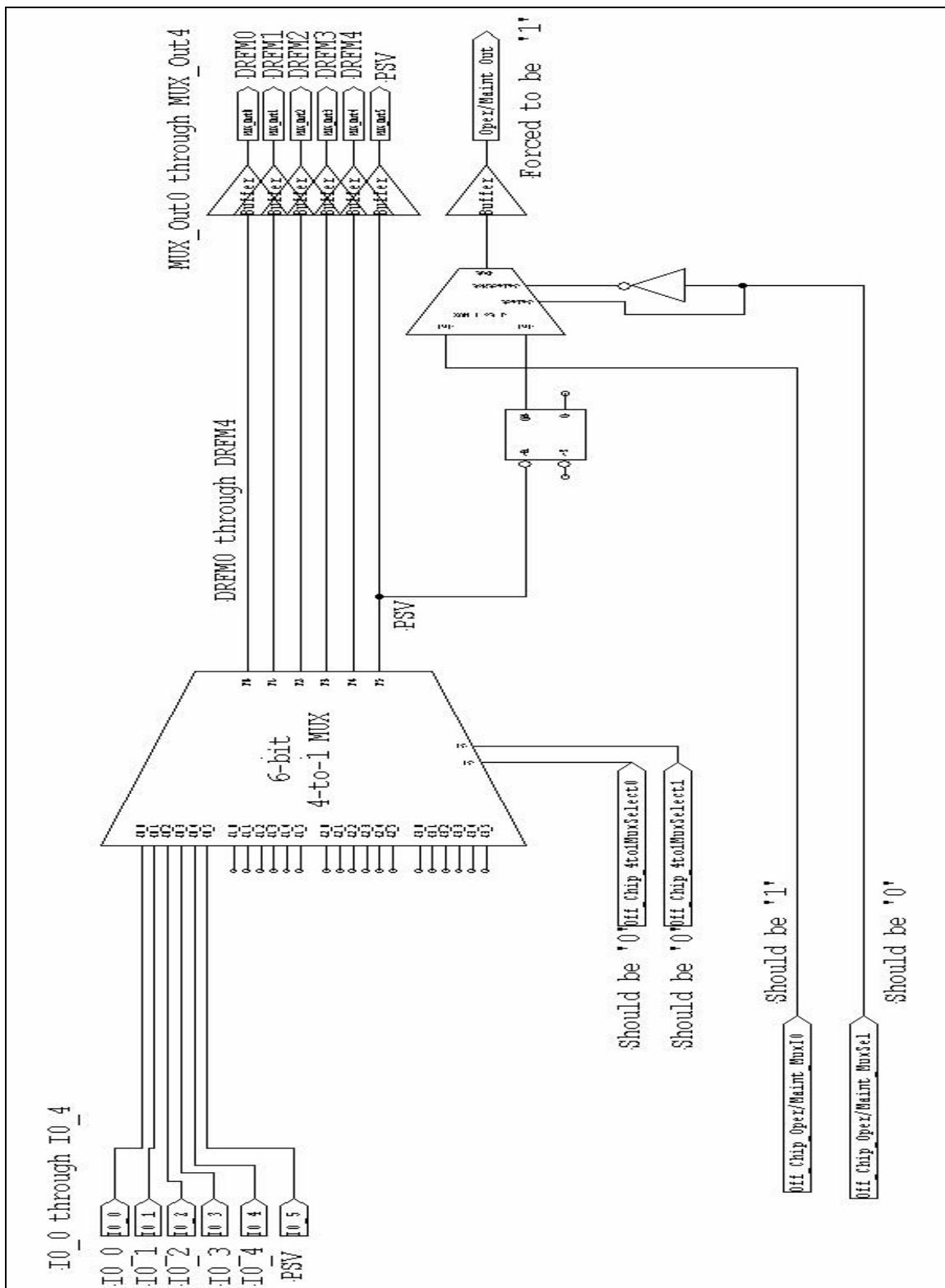


Figure 58. Data Path 1 – External Phase Sample Values

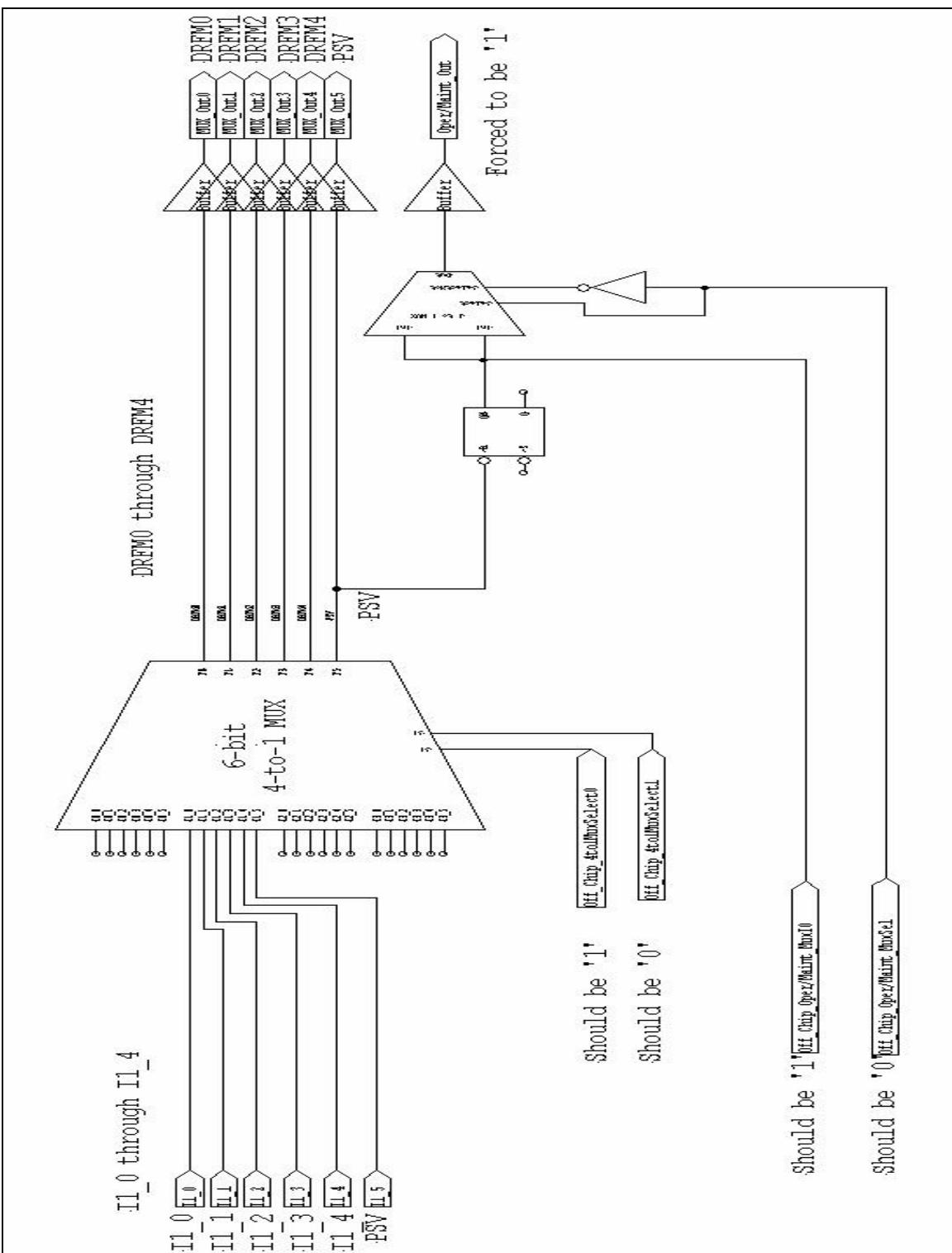


Figure 59. Data Path 2 – External Phase Sample Values

4. Path 3 – Phase Sample Values from Self Test Circuit to RBPs

The third path, shown in Figure 60, feeds the RBP s with automatically generated phase sample values as test vectors. Once the self-test sequence is started, it generates PSV and DRFM0 – DRFM4 outputs in a pseudo-random pattern. The proper target signature for the sequence is known by theory. By comparing the results of the self-test sequence and the ideal signature one can functionally test the DIS.

The Self-test mechanism is initiated by asserting the input Start_SelfTest. PSV output is “low” before the self-test starts, which causes the binary counter to be cleared. The number of the test vectors to be applied can be configured by the user; once self-test starts and PSV becomes “high” the binary counter starts to count upwards. Twelve off-chip inputs and the binary counter value are compared and when the values are equal, the Operate/Maintenance output becomes “low”. I/Q values from the RBP s should “freeze” at the end of the self-test. However, since the test vectors from the Self-Test Logic are generated three clock cycles after the Start_SelfTest input goes “high”, the off-chip number should be three greater than the desired test length. For instance, if the number of the self-test vectors to be generated is 61, the off-chip input should be 64.

The 2-to-1 multiplexer steers the Operate/Maintenance output to the RBP s via the $\sim S/\sim R$ latch. When the last test vector is generated, the comparator asserts the signal Equal, which sets the latch. The QN output of the latch becomes “low” and in turn, the Operate/Maintenance signal becomes “low”. That freezes the target signature created in the RBP s.

As with the previous two paths, the control inputs to the 6-bit 4-to-1 multiplexer should be configured to select the self-test logic circuit outputs. The input Off_Chip_Oper/MaintMuxIO can either be “low” or “high”. The input Off_ChipOper/MaintMuxSel input selects the output of the latch for proper self-test operation. Table 13 shows the control signals and their values to test the path.

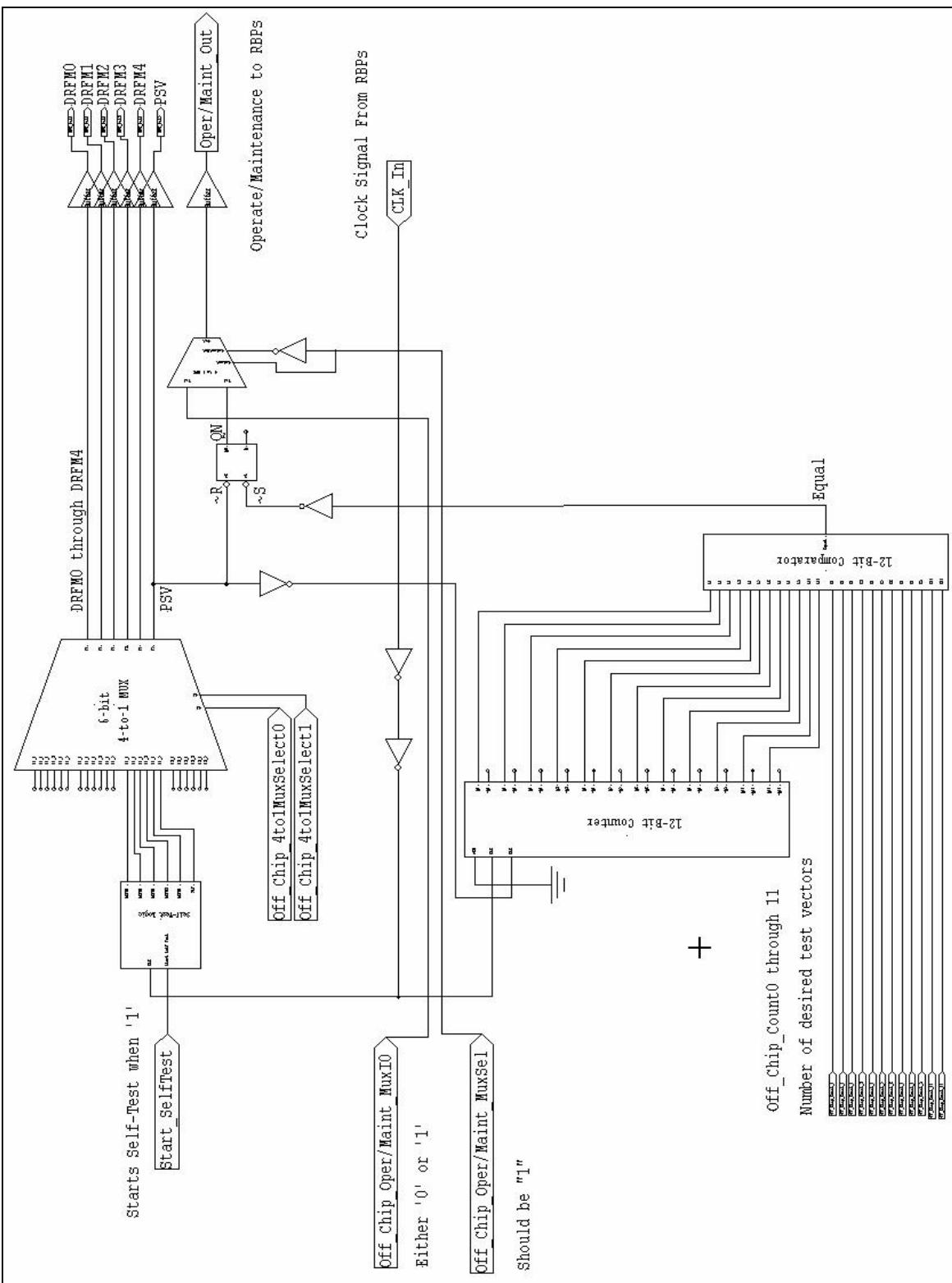


Figure 60. Data Path 3– Self-Test

Control Input	Required Value
Off_Chip_4to1MuxSelect0	Low (0)
Off_Chip_4to1MuxSelect1	High (1)
Off_Chip_Oper/Maint_MuxIO	Don't Care
Off_Chip_Oper/Maint_MuxSel	Low (0)
Off_Chip_Count0 through Off_Chip_Count11	Desired number of the test vectors
Start_SelfTest	Should be asserted to start the self-test sequence

Table 13. Control Signals to Test Path 3

5. Path 4 – Phase Sample Values from Phase Extraction Circuit to RBPs

The phase extraction circuit converts the I/Q values supplied by the Digital Radio Frequency Memory (DRFM) as eight-bit two's complement numbers into a corresponding phase angle value expressed as five-bit unsigned numbers for generating the false target signature.

The path from the phase extraction circuit to the RBP s is shown in Figure 61. The control inputs are given in Table 14. The extraction is enabled with the assertion of the signal I/Q_Valid_In. The DRFM values are loaded continuously since the Load input of the phase extraction circuit is hard-wired to “high”.

The 6-bit 4-to-1 multiplexer should be controlled so that proper data is transferred to the RBP s. The 2-to-1 multiplexer passes a “high” for the Operate/Maintenance signal into the RBP s. The I/Q values are off-chip signals coming from the DRFM.

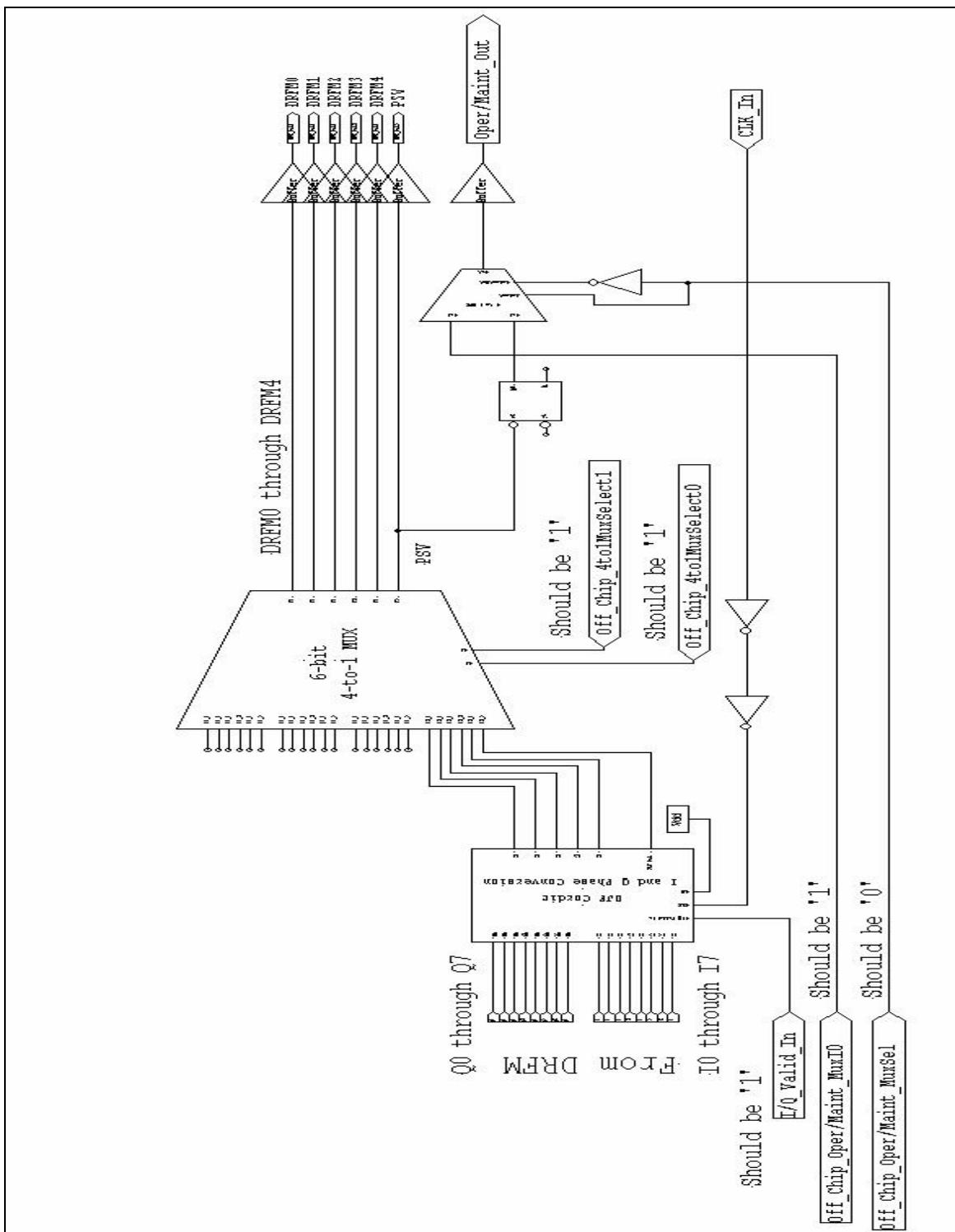


Figure 61. Data Path 4—Phase Extraction

Control Input	Required Value
Off_Chip_4to1MuxSelect0	High (1)
Off_Chip_4to1MuxSelect1	High (1)
Off_Chip_Oper/Maint_MuxIO	High (1)
Off_Chip_Oper/Maint_MuxSel	Low (0)
I/Q_Valid_In	Asserted to start phase extraction

Table 14. Control Signals to Test Path 4

B. INPUT / OUTPUT SIGNALS

A number of input and output signals must be instantiated with specific values at certain times in order to drive the simulation. Table 15 lists the input signals and their functions while Table 16 shows the output signals and their descriptions.

C. SIMULATIONS

The simulations performed on the Range Bin Processors include simulations on a single RBP and 4 and 16 cascaded RBPs. Due to the memory allocation problem on initialization in the simulator software used, Aldec Active HDL™, simulations with 256 RBPs and 512 RBPs could not been conducted. However, because all RBPs are identical in hardware design and programming style and input/output signal propagation, even four RBPs cascaded together can represent the circuit behavior of all serial 512 RBPs. Simulations involving the control circuitry and the different data paths are conducted with four RBPs cascaded together, representing the overall DIS. The important features of the DIS, Self-test Logic and Phase Extraction Circuit, are tested separately before they are integrated with the rest of the circuit.

SIGNAL	DESCRIPTION
Q0 through Q15	Initial Q value for the RBP from previous RBP, usually set to ‘low’
Q_OF_In	Overflow input for Q from previous RBP, usually set to ‘low’
I0 through I15	Initial I value for the RBP from previous RBP, usually set to ‘low’
I_OF_In	Overflow input for I from previous RBP, usually set to ‘low’
ODV_In	Output Data Valid input from previous RBP, usually set to “low”
PInc_In 0 through Pinc_In 4	Phase increment programming value for each RBP, used to program the RBP
Gain_In 0 through Gain_In 3	Gain coefficient for each RBP, used to program the RBP
URB_In	Use Range Bin from previous RBP, usually set to “high”
PRB_In	Program Range Bin from previous RBP. Used to program the RBP’s with phase increment and gain coefficient values. Asserted “high” during programming, should be “low” before UNP_In is “high” for proper operation.
UNP_In	Used to latch the phase increment and gain coefficients into the selected RBP to conclude programming. It completes programming after the coefficients are fed with PRB_In input. When asserted, all RBP’s are latched with the previously provided phase increment value and gain coefficients at once.
Sel_In 0 through Sel_In 8	Select RBP, used to select the single RBP to be programmed with Pinc_In and Gain_In values.
Clock_Prog_In	Clock Program Input, Used to adjust the clock skew between RBP’s (Refer to [8] and [12]).
Clock_In	Clocking signal coming from the next RBP. Clock signal propagates in the opposite direction with the data and control signals.
I0_0 through I0_4	Off Chip DRFM Data – Path 1
I0_5	Off Chip Phase Sample Valid Signal – Path 1
I1_0 through I0_4	Off Chip DRFM Data – Path 2
I1_5	Off Chip Phase Sample Valid Signal – Path 2
I/Q_Valid_In	I/Q Valid input signal to enable the Phase Extractor outputs
I0 through I7	8-bit I value stored in DRFM to the Phase Extraction Circuit
Q0 through Q7	8-bit Q value stored in DRFM to the Phase Extraction Circuit
Off_Chip_4to1MuxSelect0 and Off_Chip_4to1MuxSelect1	Off chip multiplexer select inputs, used to steer the desired phase samples and PSV signals to the RBP block. Selects the data path to be created between the inputs and the RBPs.
Start_SelfTest	Start self-test input to initiate the self-test sequence whose length is determined by Off_Chip_Count inputs
Off_Chip_Count0 through Off_Chip_Count1	Off chip count inputs to allow user to determine the number of the self-test vectors to be created.
Off_Chip_Oper/Maint_MuxSel	Off chip multiplexer select for Operate/Maintenance input to the RBP’s
Off_Chip_Oper/Maint_MuxIO	Off chip alternative Operate/Maintenance input. Asserted “low” only testing path 3, kept “high” while testing paths 1 and 2. The value of the signal while testing path 4 can be either (don’t care)

Table 15. Input Signals to the Digital Image Synthesizer

SIGNAL	DESCRIPTION
Q_Out_0 through Q_Out_15	Q value from the RBP
Q_OF_Out	Q Overflow indicator from the RBP
I_Out_0 through I_Out_15	I value from the RBP
I_OF_Out	I Overflow indicator from the RBP
ODV_Out	Output Data Valid, when “high” the results from the RBP for I/Q are valid outputs.
PInc_Out_0 through PInc_Out_4	Phase increment programming value from the RBP
Gain_Out_0 through Gain_Out_3	Gain coefficient from the RBP
URB_Out	Use Range Bin from the RBP
PRB_Out	Program Range Bin from the RBP
UNP_Out	Use New Programming output from the RBP
Sel_In_0 through Sel_In_8	Select RBP from the RBP
Clock_Prog_Out	Clock Program Output from the RBP, for further information, refer to [8] and [12].
Clock_Out	Clocking signal coming from the RBP to the next RBP. It also drives Phase Extraction Circuit and Self-test Circuitry.
DRFM_Out_0 through DRFM_Out_4	Phase Sample Values from the RBP
PSV_Out	Phase Sample Valid output from the RBP

Table 16. Output Signals from the Digital Image Synthesizer

1. Simulation of a Single RBP

A single RBP, shown in Figure 62, is functionally tested and verified. The simulation results are compared with the ideal outputs that are computed using C++ by Prof. Fouts. For details on the design of the RBP s, refer to [12].

The pipeline registers inside the RBP s should be cleared prior to introducing valid phase sample values to the RBP. In order to accomplish this task, the circuit should be clocked N times where N is the sum of the number of pipeline stages and the number of the RBP s.

Moreover, the delay signal should be initialized. The signal “Delay” is the input Clk_Prog_In stored in a bit in the 6-bit register. Because there is a feedback to the Clock Splitting circuit from the 6-bit register, the VHDL programmer should initialize the value for the Delay signal to either ‘0’ or ‘1’ to create a valid clock signal to the RBP. The “Delay” signal is also shown in Figure 62.

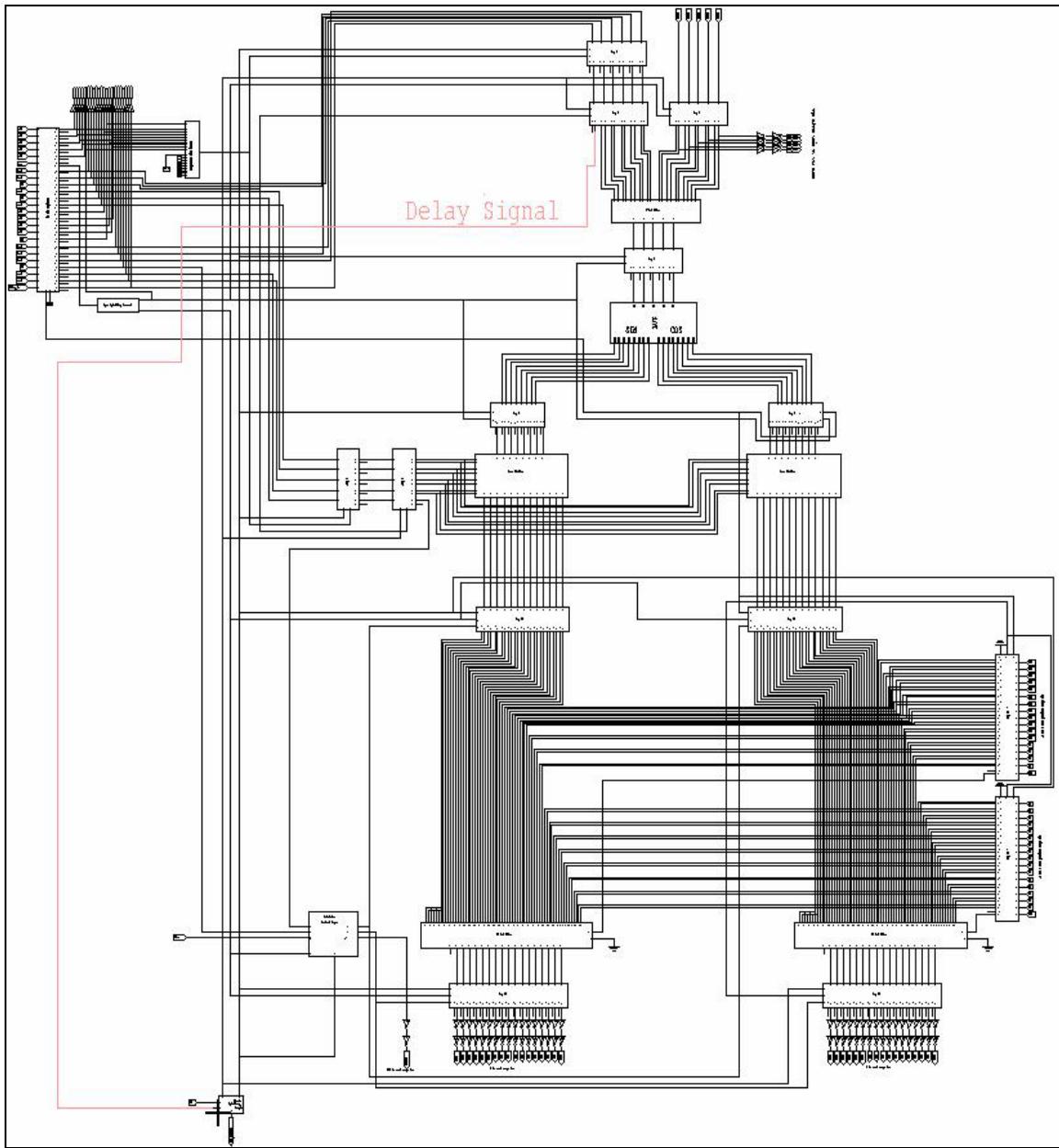


Figure 62. A Single Range Bin Processor Schematic and Delay Signal in S-Edit

The simulation algorithm is as follows:

- Set Addr0 through Addr8 = '0', the address of the RBP. In the actual hardware implementation, this is accomplished by hardwiring address lines to Vdd or Gnd. The VHDL programmer need not assign any values.
- Set Clock Rate, CLK = Stimulator → Clock → 2ns.

- Set Clk_Prg_In, I0 through I15, Q0 through Q15, IOV, QOV, ODVIn and Sel0 through Sel8 ='0' by Stimulator → Value → 0
 - Set Delay='1'. (Delay signal is in the *entity* DTM_ClockSplitter_1)
 - Set Oper, URB = '1' by Stimulator → Value → 1
 - Set PSV=0, UNP=0, PRB=0
 - Clock RPB for 5 times to clear the pipeline
 - Set PRB = '1' and Gain0 through Gain3='0', PIInc0 through PIInc4='0'
 - Clock RBP once
 - Set PRB = '0', UNP='1'
 - Clock RBP once
 - Set UNP = '0'
 - Clock RBP until ISOV, QSOV and ODVOut are '0'
 - Set PSV ='1' and DRFM0 through DRFM4 to the desired phase sample values, clock RBP, repeat for every DRFM sample value
 - Set PSV= '0'
 - Clock RBP until ODVOut = '0'
 - Watch and record the values for IS0 through IS15, QS0 through QS15, ISOV (Overflow), QSOV (Overflow) and ODV_Out
 - Compare the results with the C++ outputs
 - If they don't match, use the Active HDLTM Block Diagram Editor to trace the signals and find the problem. If they match, document the results.

The waveform used in the simulation is shown in Figure 63.

Table 17 presents the programming coefficients for the RBP, the simulation results and the comparison with the C++ outputs.

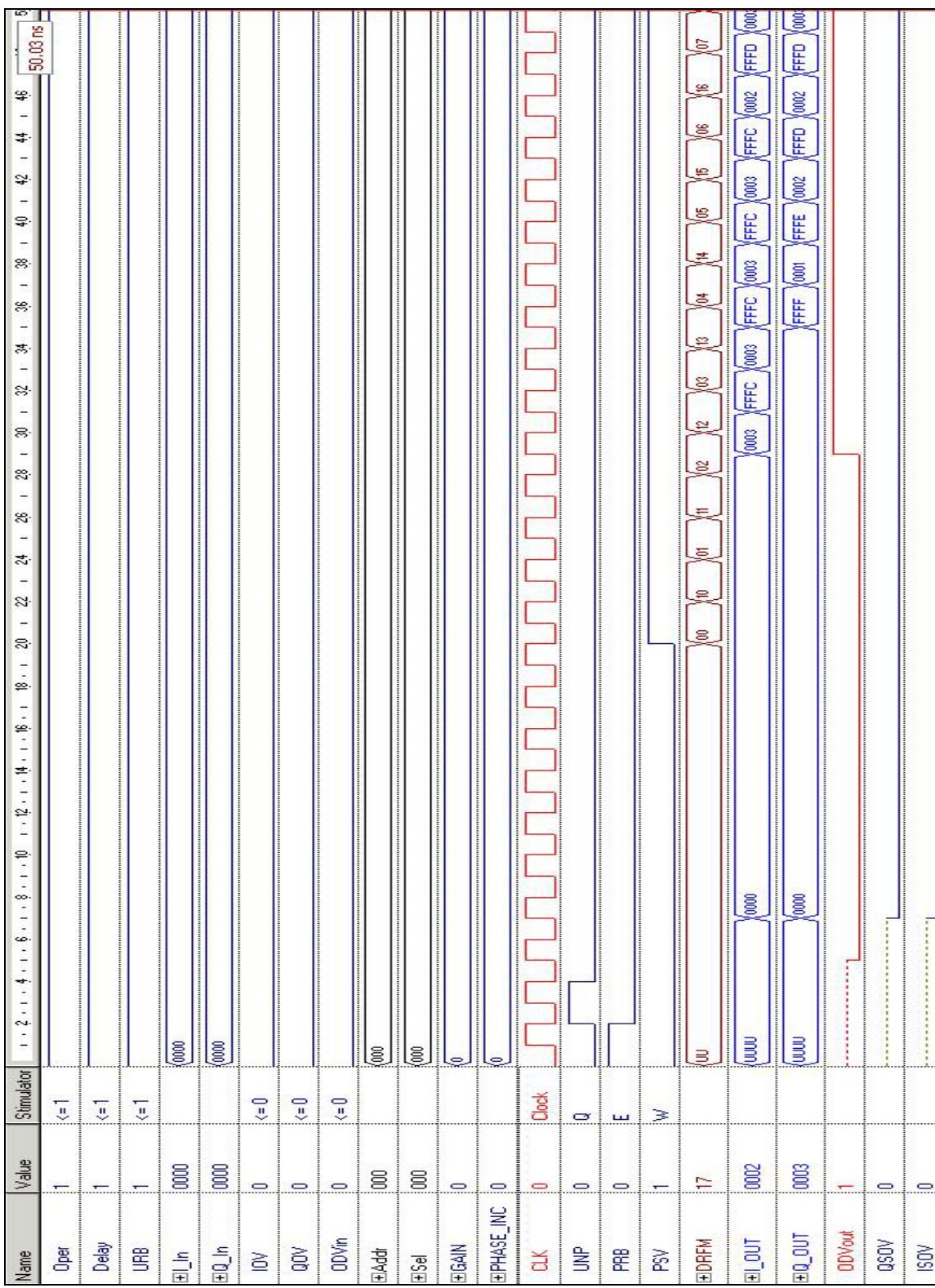
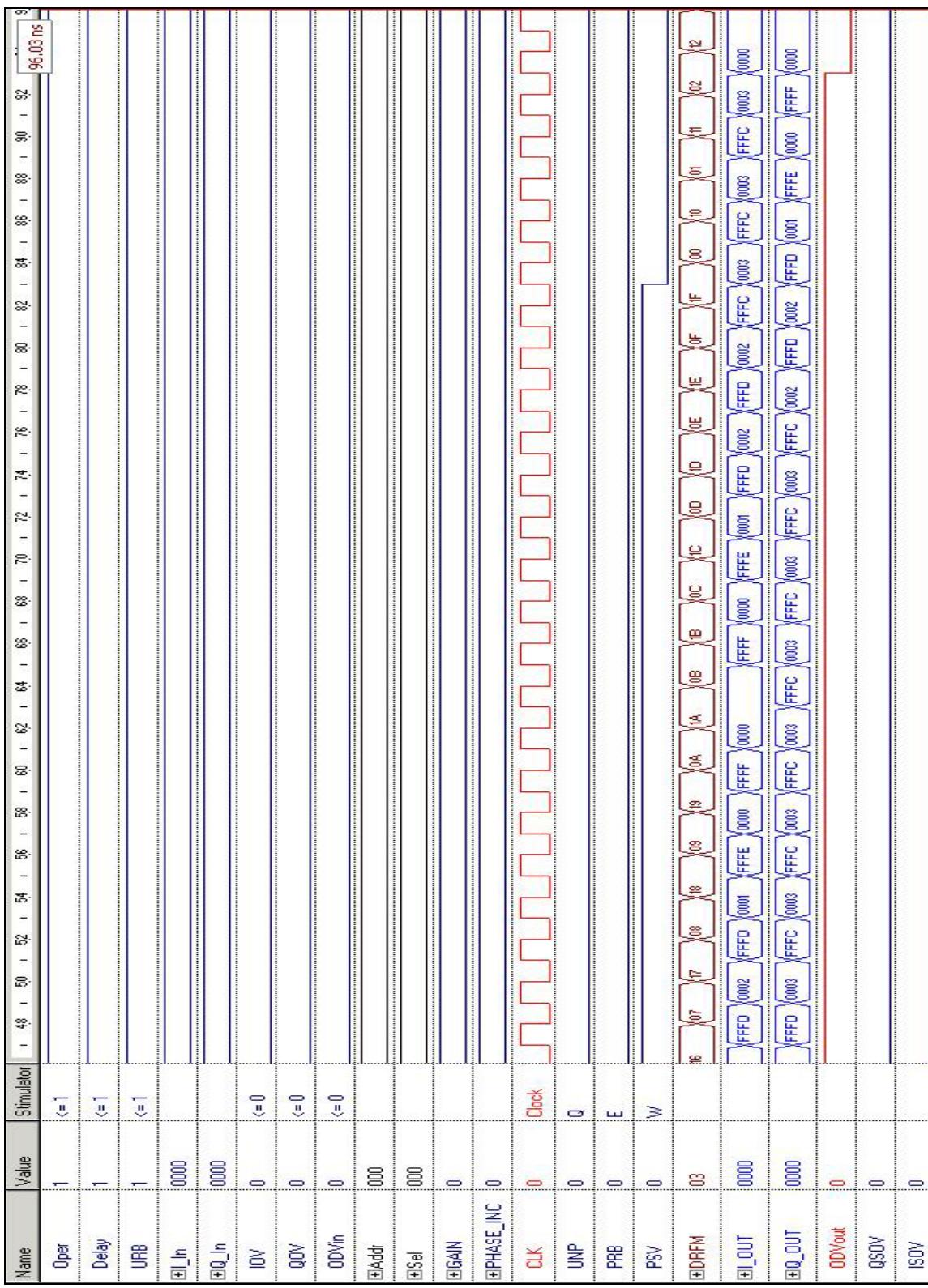


Figure 63. Simulation of a Single RBP



Simulation of a Single RBP, Continued

1 RBP		Simulation Results				C++ Outputs			
Gain = 0 PInc = 0									
Phase Samples (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out	
00	0003	0000	0	0	0003	0000	0	0	
10	FFFC	0000	0	0	FFFC	0000	0	0	
01	0003	0000	0	0	0003	0000	0	0	
11	FFFC	FFFF	0	0	FFFC	FFFF	0	0	
02	0003	0001	0	0	0003	0001	0	0	
12	FFFC	FFFE	0	0	FFFC	FFFE	0	0	
03	0003	0002	0	0	0003	0002	0	0	
13	FFFC	FFFD	0	0	FFFC	FFFD	0	0	
04	0002	0002	0	0	0002	0002	0	0	
14	FFFD	FFFD	0	0	FFFD	FFFD	0	0	
05	0002	0003	0	0	0002	0003	0	0	
15	FFFD	FFFC	0	0	FFFD	FFFC	0	0	
06	0001	0003	0	0	0001	0003	0	0	
16	FFFE	FFFC	0	0	FFFE	FFFC	0	0	
07	0000	0003	0	0	0000	0003	0	0	
17	FFFF	FFFC	0	0	FFFF	FFFC	0	0	
08	0000	0003	0	0	0000	0003	0	0	
18	0000	FFFC	0	0	0000	FFFC	0	0	
09	FFFF	0003	0	0	FFFF	0003	0	0	
19	0000	FFFC	0	0	0000	FFFC	0	0	
0A	FFFE	0003	0	0	FFFE	0003	0	0	
1A	0001	FFFC	0	0	0001	FFFC	0	0	
0B	FFFD	0003	0	0	FFFD	0003	0	0	
1B	0002	FFFC	0	0	0002	FFFC	0	0	
0C	FFFD	0002	0	0	FFFD	0002	0	0	
1C	0002	FFFD	0	0	0002	FFFD	0	0	
0D	FFFC	0002	0	0	FFFC	0002	0	0	
1D	0003	FFFD	0	0	0003	FFFD	0	0	
0E	FFFC	0001	0	0	FFFC	0001	0	0	
1E	0003	FFFE	0	0	0003	FFFE	0	0	
0F	FFFC	0000	0	0	FFFC	0000	0	0	
1F	0003	FFFF	0	0	0003	FFFF	0	0	

Table 17. Simulation Results and Comparison for a Single RBP

2. Simulation of 4 RBP s in Series

The simulation algorithm is as follows:

- Set Clock Rate, Clock_In = Stimulator → Clock → 2ns
- Set Clk_Prg_In, I_In0 through I_In15, Q0 through Q_In15, I_OF_In, Q_OF_In, ODV_In by Stimulator → Value → 0
- Set Delay='0' in all clock splitting circuits in every RBP using the design browser and by adding signal names into the waveform editor. (Delay signals are in the *entities* DJF_ClockTrue_1 and DJF_ClockComp_1)
- Set Oper_In, URB_In = '1' by Stimulator → Value → 1
- Set PSV_In=0, UNP_In=0, PRB_In=0
- Clock RPB for 11 times to clear the pipeline
- Set PRB_In = '1'
- Select the RBP to be programmed using the Sel_In0 through Sel_In8 inputs. Set Gain_In0 through Gain_In3='0', and PIInc_In0 through PIInc_In4='0' to the desired values for the RBP to be programmed. Clock the RBP once. Repeat for all RBP s.
 - Set PRB_In = '0', UNP_In='1'
 - Clock RBP once
 - Set UNP_In = '0'
 - Clock RBP until I_OF_Out, Q_OF_Out and ODV_Out are '0'
 - Set PSV_In ='1' and DRFM_In0 through DRFM_In4 to the desired phase sample values, clock RBP, repeat for every DRFM sample value
 - Set PSV_In= '0', clock RBP until ODV_Out = '0'
 - Watch and record the values for I_Out0 through I_Out15, Q_Out0 through Q_Out15, I_OF_Out (Overflow), Q_OF_Out (Overflow) and ODV_Out
 - Compare the results with the C++ outputs.

The waveform used in the simulation for 4 RBP s in series is shown in Figure 64. Table 18 shows the programming coefficients for the RBP s, the simulation results, and the comparison with the C++ outputs.

RBP	0	1	2	3
Gain\Hex	00	04	08	0C
PInc(Hex)	00	08	10	18
Simulation Results				C++ Outputs
Phase Samples (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out
00	0003	0000	0	0
10	FFFC	001F	0	0
01	FFC3	FFE0	0	0
11	0034	FE22	0	0
02	FFCA	01D0	0	0
12	0091	FE33	0	0
03	FF70	01BF	0	0
13	00E8	FE5B	0	0
04	FF1A	0197	0	0
14	0137	FE8E	0	0
05	FECF	0167	0	0
15	0177	FED2	0	0
06	FE8F	0124	0	0
16	01AB	FF21	0	0
07	FE5C	00D7	0	0
17	01CB	FF78	0	0
08	FE3E	0081	0	0
18	01E0	FFD6	0	0
09	FE2A	0027	0	0
19	01DC	0034	0	0
0A	FE2D	FFCA	0	0
1A	01CA	0091	0	0
0B	FE3E	FF70	0	0
1B	01A2	00E8	0	0
0C	FE66	FF1A	0	0
1C	016F	0137	0	0
0D	FE97	FECF	0	0
1D	012C	0177	0	0
0E	FEDA	FE8F	0	0
1E	00DD	01AB	0	0
0F	FF26	FE5C	0	0
1F	0085	01CB	0	0
-	FF80	FE3E	0	0
-	0025	0200	0	0
-	FF9C	FE0C	0	0

Table 18. Simulation Results and Comparison for 4 RBP s

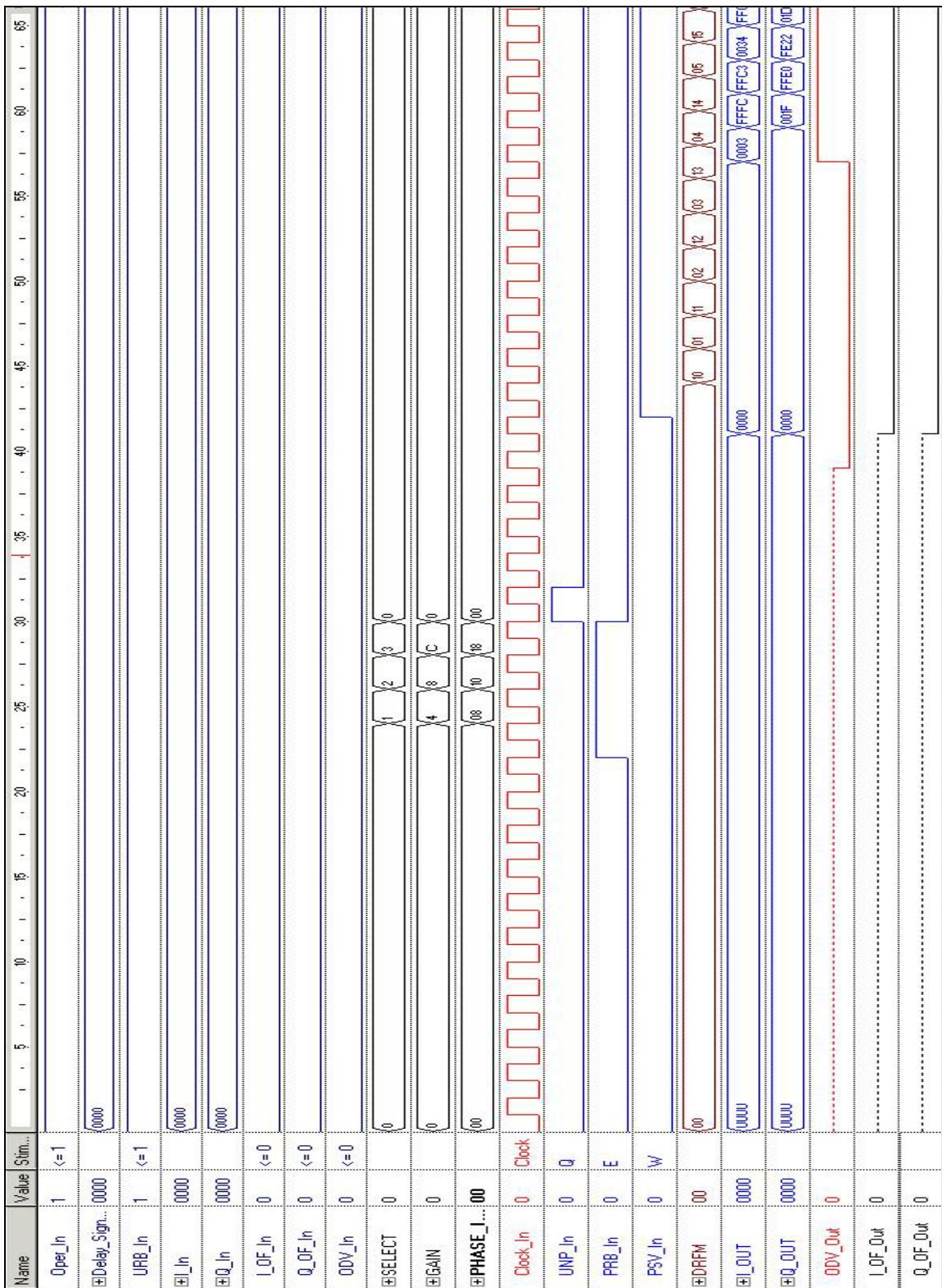


Figure 64.

Simulating Cascaded 4 RBP s



Simulation of Cascaded 4 RBP s, Continued

3. Simulation of 16 RBP s in Series

The simulation algorithm is as follows:

- Set Clock Rate, Clock_In = Stimulator → Clock → 2ns
- Set Clk_Prg_In, I_In0 through I_In15, Q_In0 through Q_In15, I_OF_In, Q_OF_In, ODV_In by Stimulator → Value → 0
- Set Delay='0' in all clock splitting circuits in every RBP using the design browser and by adding signal names into the waveform editor. (Delay signals are in the *entities* DJF_ClockTrue_1 and DJF_ClockComp_1)
- Set Oper_In, URB_In = '1' by Stimulator → Value → 1
- Set PSV_In=0, UNP_In=0, PRB_In=0
- Clock RPB for 23 times to clear the pipeline
- Set PRB_In = '1'
- Select the RBP to be programmed using the Sel_In0 through Sel_In8 inputs. Set Gain_In0 through Gain_In3='0', and PIInc_In0 through PIInc_In4='0' to the desired values for the RBP to be programmed. Clock the RBP once. Repeat for all RBPs.
 - Set PRB_In = '0', UNP_In='1'
 - Clock RBP once
 - Set UNP_In = '0'
 - Clock RBP until I_OF_Out, Q_OF_Out and ODV_Out are '0'
 - Set PSV_In ='1' and DRFM_In0 through DRFM_In4 to the desired phase sample values, clock RBP, repeat for every DRFM sample value
 - Set PSV_In= '0'
 - Clock RBP until ODV_Out = '0'
 - Watch and record the values for I_Out0 through I_Out15, Q_Out0 through Q_Out15, I_OF_Out (Overflow), Q_OF_Out (Overflow) and ODV_Out

Phase Samples (Hex)	Simulation Results				C++ Outputs			
	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)
-	F41D	0000	0	0	F41D	0000	0	0
-	F455	FDA9	0	0	F455	FDA9	0	0
-	F506	FB66	0	0	F506	FB66	0	0
-	F62A	F968	0	0	F62A	F968	0	0
-	F790	F790	0	0	F790	F790	0	0
-	F97B	F645	0	0	F97B	F645	0	0
-	FB4F	F4CD	0	0	FB4F	F4CD	0	0
-	FDCD	F503	0	0	FDCD	F503	0	0
-	0000	F497	0	0	0000	F497	0	0
-	0226	F542	0	0	0226	F542	0	0
-	0498	F508	0	0	0498	F508	0	0
-	058C	F7B8	0	0	058C	F7B8	0	0
-	0870	F790	0	0	0870	F790	0	0
-	06A0	FB90	0	0	06A0	FB90	0	0
-	0EA0	F9E0	0	0	0EA0	F9E0	0	0

Simulation Results and Comparison for 16 RBP s, Continued

After verification of 16 RBP s' functionality, a test was conducted to test the use of only 13 RBP s in a cascade of 16 RBP s. Some modifications were made to the simulation algorithm. URB_In was set to "0" for RBP s 13, 14 and 15. Thus, the 16 RBP cascade acted like 13 RBP s connected sequentially.

The simulation results and C++ outputs for 13 RBP s cascaded is given in Table 20, while the waveform is shown in Figure 66. The simulations with a single RBP, 4 RBP s, 16 RBPs and 13 RBPs serially connected were tested and the DIS was verified.

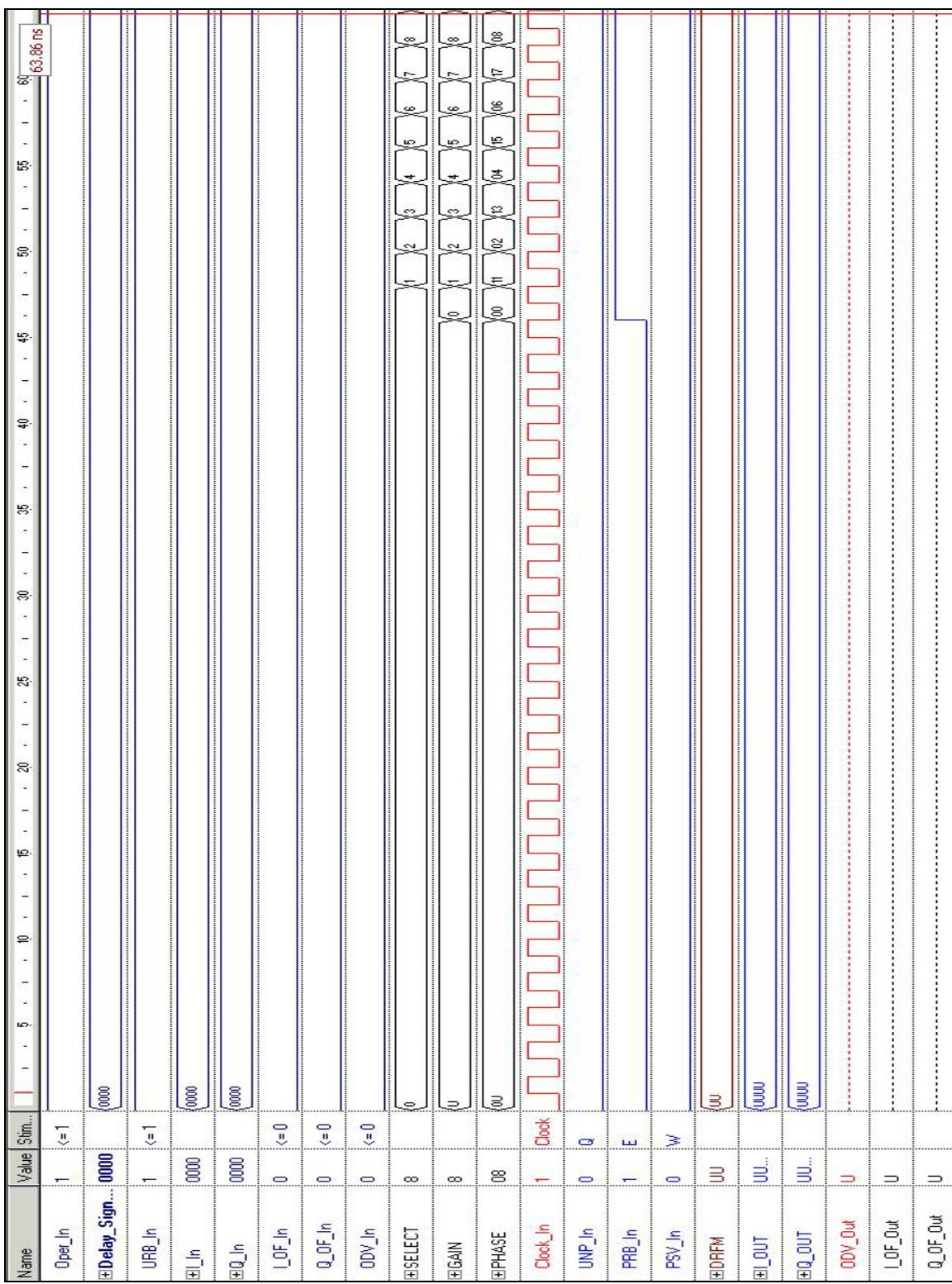
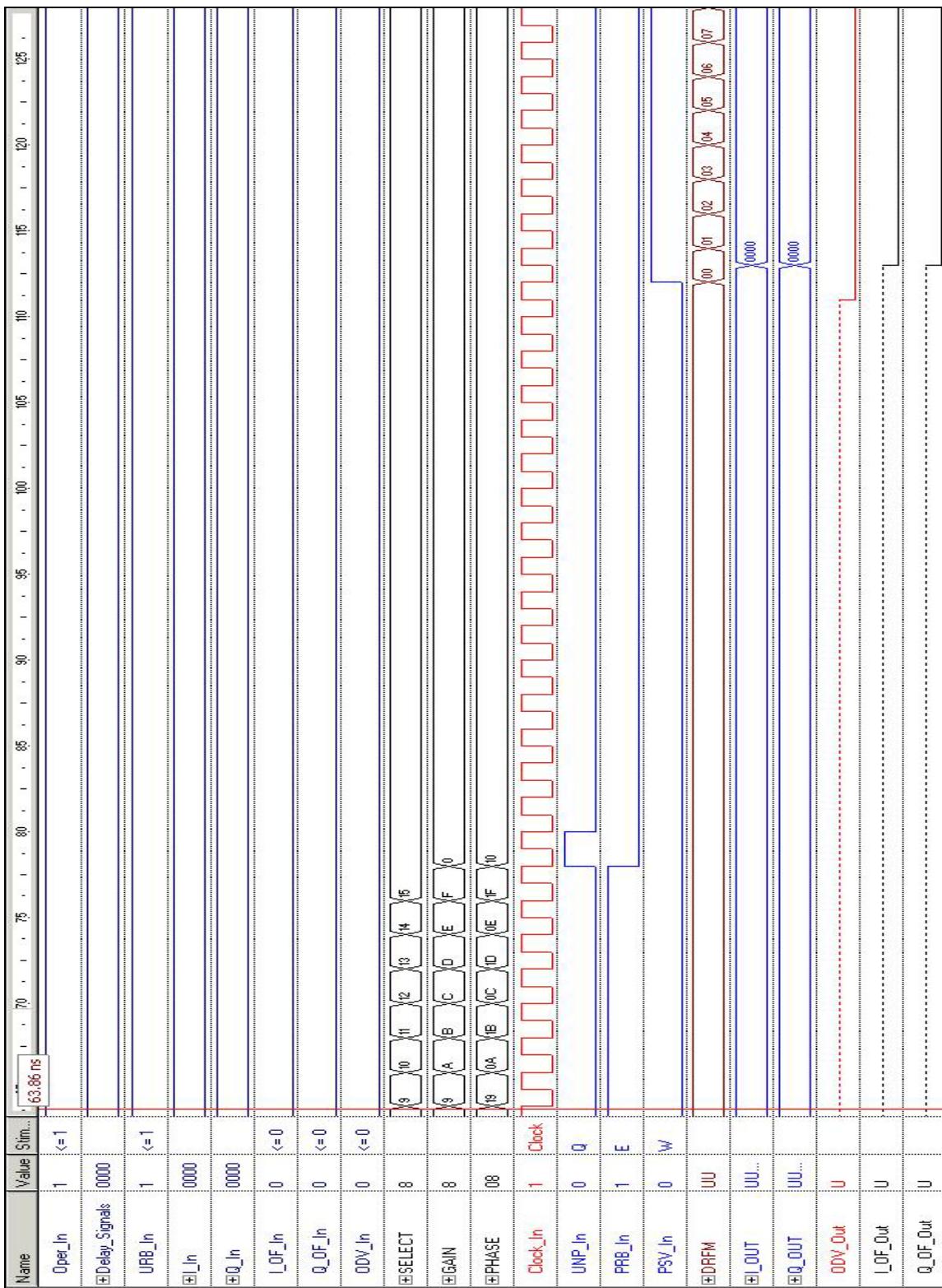


Figure 65. Simulation of Cascaded 16 RBP s



Simulation of Cascaded 16 RBP s, Continued

Name	Value	Sim...	127.2415	135	140	145	150	155	160	165	170	175	180	185
Opel_In	1	<= 1												
+Delay_Sign...	0000													
URB_In	1	<= 1												
+I_In	0000													
+Q_In	0000													
LOF_In	0	<= 0												
Q_OF_In	0	<= 0												
DIV_In	0	<= 0												
+SELECT	15													
+GAN	0													
+PHASE	0													
Clock_In	1	Clock												
UNP_In	0	Q												
PRB_In	0	E												
PSV_In	1	W												
+DRFM	07	07 08 09 0A 0C 0D 0E 0F 10 11 12 13 14 15 16 17 18 19 1A 1B 1C 1D 1E 1F												
+I_OUT	0000													
+Q_OUT	0000													
DIV_Out	0													
LOF_Out	0													
Q_OF_Out	0													

Simulation of Cascaded 16 RBP s, Continued

Name	Value	Sim...
Oper_In	1	<=1
+Delay_Signals	0000	249.06
URB_In	1	<=1
+I_In	0000	
+Q_In	0000	
LDF_In	0	<=0
Q_OF_In	0	<=0
DDV_In	0	<=0
+SELECT	15	
+GAIN	0	
+PHASE	10	
Clock_In	1	Clock
UNP_In	0	0
PRB_In	0	E
PSV_In	0	W
+DRFM	00	
+I_OUT	0000	0E9 \ 0A9 \ 0AE4 \ 0E3 \ 08E5 \ 08E6 \ 0490 \ 0352 \ 0000 \ FDA7 \ FEB8 \ F86 \ F736 \ F8B \ F88 \ F50F \ F45 \ F506 \ F624 \ F790 \ F37B \ FB4F \ 0000 \ 0226 \ 0498 \ 065C \ 0870 \ 0640 \ 0EA0 \ 0000
+Q_OUT	0000	0000 \ 0282 \ 0490 \ 068E \ 0885 \ 0886 \ 03E3 \ 03E4 \ 0AE4 \ 08E3 \ 0885 \ 08E6 \ 0490 \ 0282 \ 0000 \ FDA9 \ FB86 \ F588 \ F7B8 \ F790 \ F845 \ F4CD \ F803 \ F497 \ FRA2 \ FB08 \ F790 \ F850 \ 0000
DDV_Out	0	
LDF_Out	0	
Q_OF_Out	0	

Simulation of Cascaded 16 RBP s, Continued

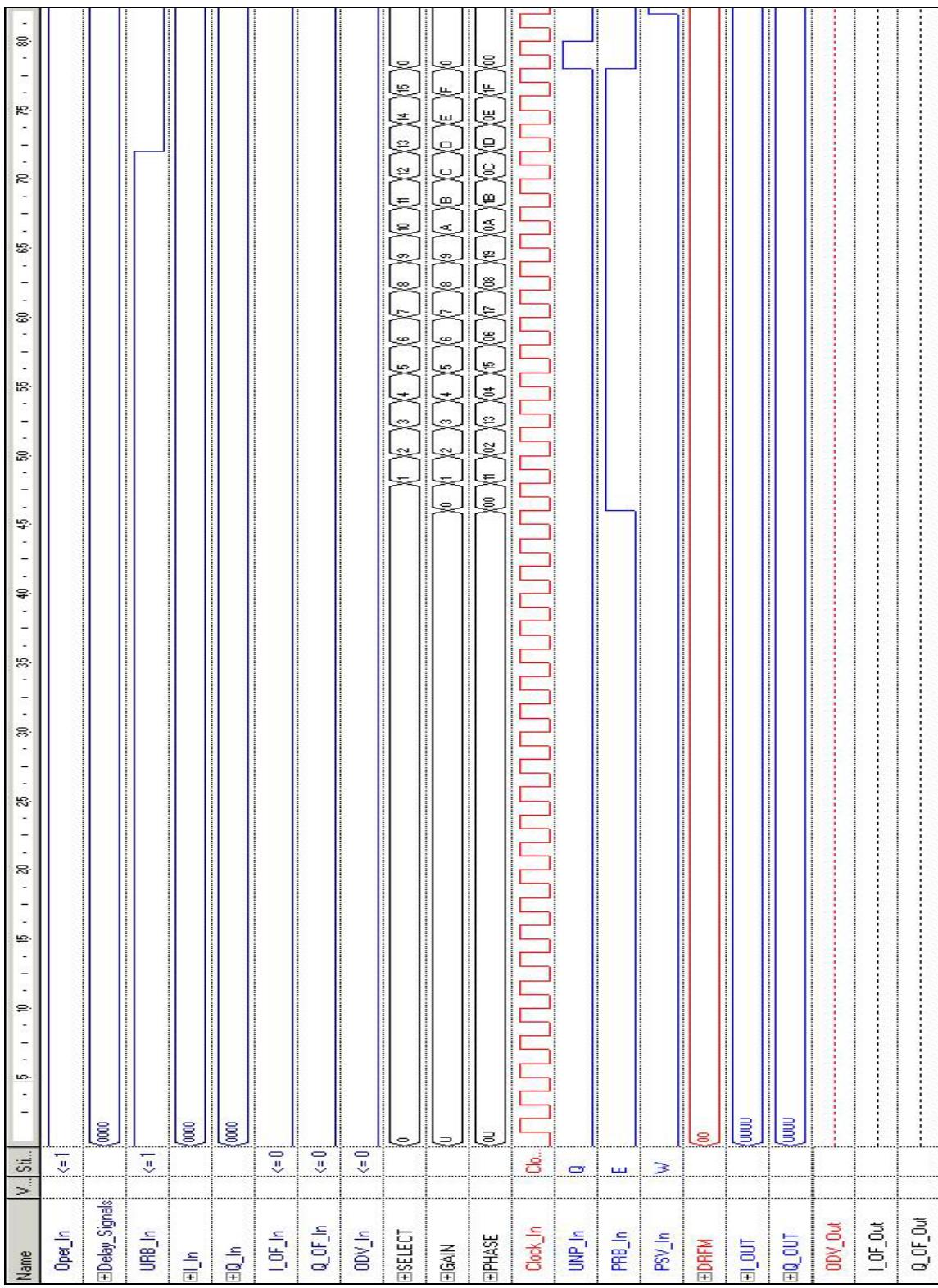
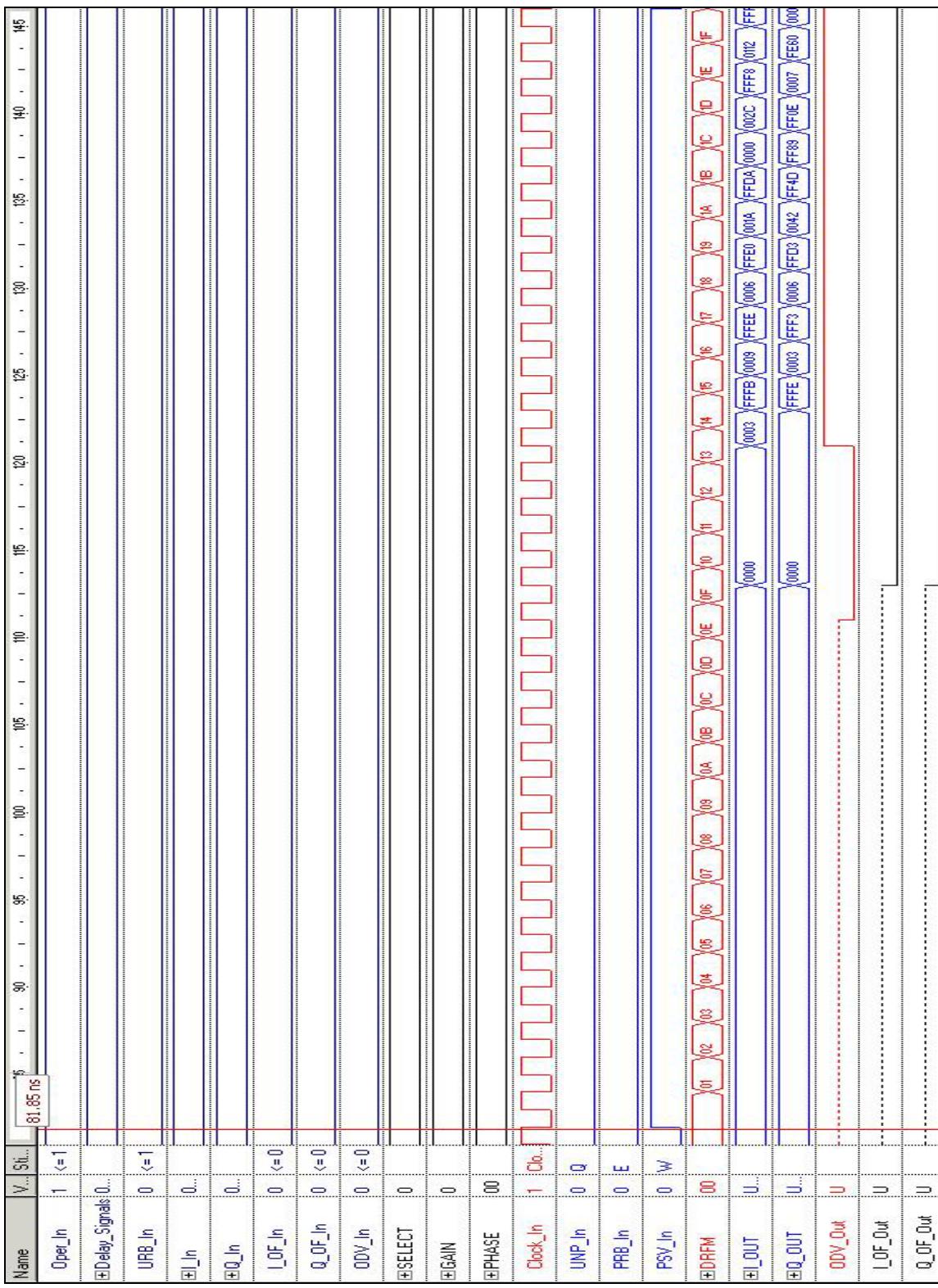
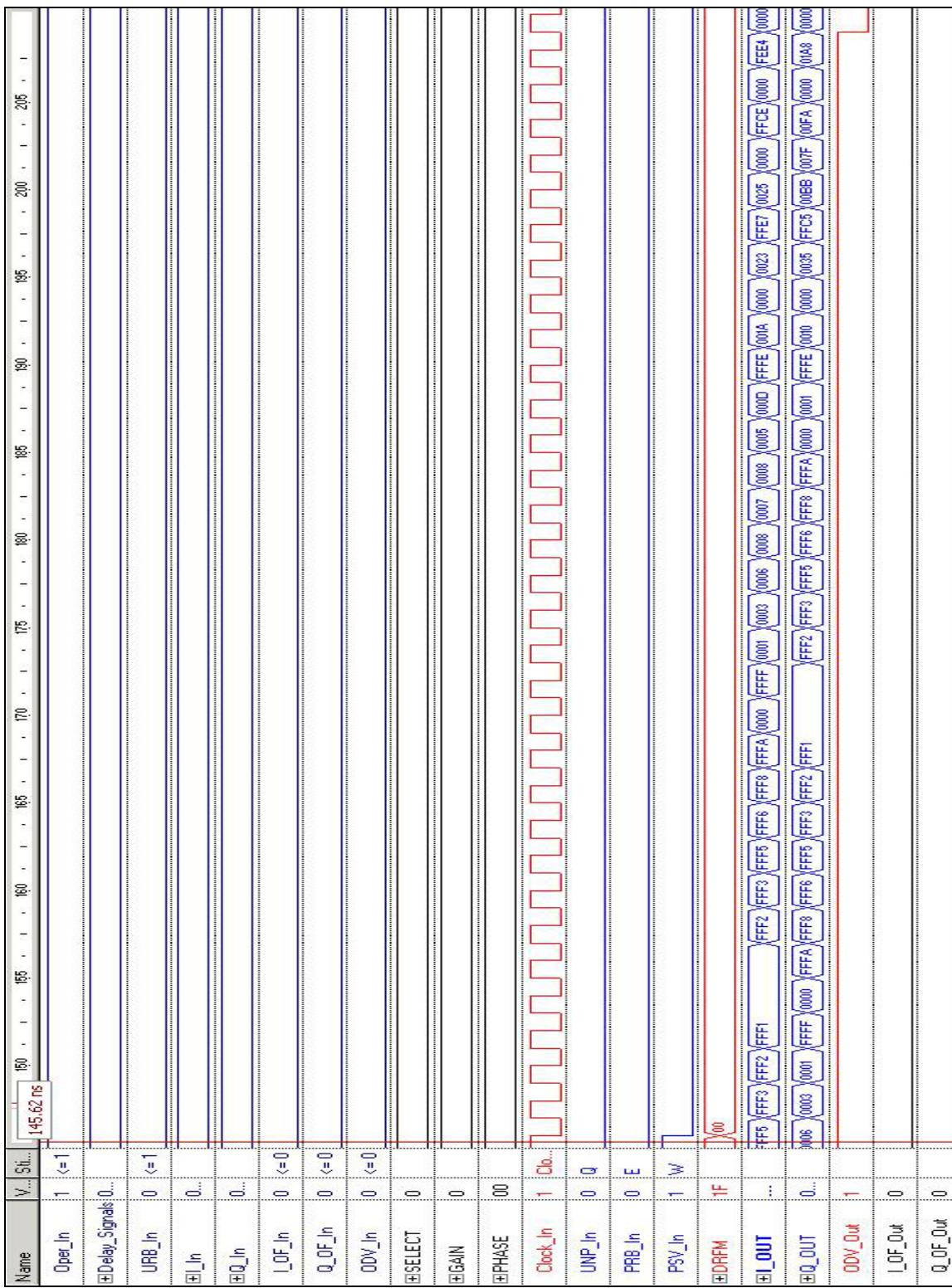


Figure 66. Simulation of Cascaded 13 RBP s



Simulation of Cascaded 13 RBP s, Continued



Simulation of Cascaded 13 RBP s, Continued

4. Simulation of the Self Test Circuit

The Self Test Circuit can generate 4095 random phase sample values for which the correct target signature is known. It is utilized for self-test of the DIS. The simulation algorithm to test the Self Test Circuit is as follows:

- Set Clock Rate, Clock_In = Stimulator → Clock → 2ns
- Set Start_Self_Test = '0'
- Clock the circuit once
- Set Start_Self_Test = '1'
- Clock the circuit for 4097 times to get all random test vectors generated. There is a 3-clock-cycle-delay between Start_Self_Test signal's "low" to "high" transition and the PSV output "low" to "high" transition.

The beginning and the end of the simulation shown on the waveform editors are in Figure 67 and Figure 68, while the resultant test vectors are listed in Appendix A.

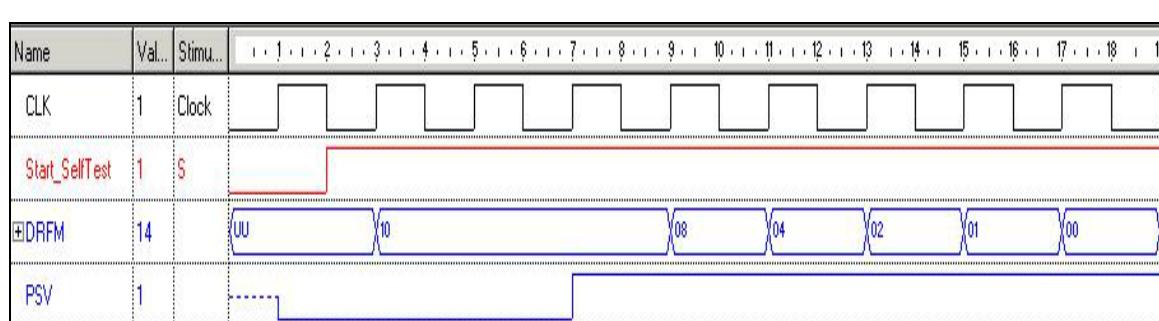


Figure 67. Simulation of Self Test Circuit, Beginning

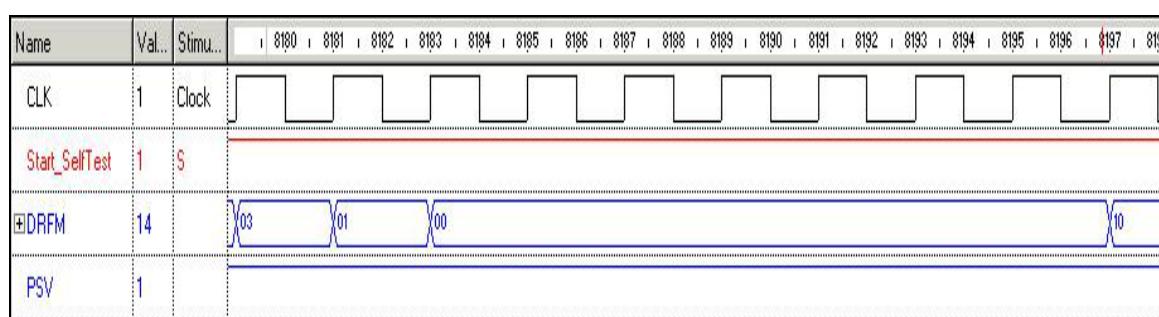


Figure 68. Simulation of Self Test Circuit, Ending

5. Simulation of the Phase Extraction Circuit

An exhaustive test was conducted to verify all possible input/output combinations. The simulation algorithm used is listed below.

- Set Clock Rate, $\text{Clock_In} = \text{Stimulator} \rightarrow \text{Clock} \rightarrow 0.5\text{ns}$
- Set Load = ‘1’ using Stimulator \rightarrow Value \rightarrow ‘1’ (In the DIS, this input is tied to Vdd, logic ‘1’)
- Set $I_{\text{In}0}$ through $I_{\text{In}7}$ and $Q_{\text{In}0}$ through $Q_{\text{In}7} = ‘0’$ and $\text{PSV_In} = ‘1’$.
- Clock the circuit for 16 times to initialize the pipeline registers.
- Set $\text{PSV_In} = ‘0’$ and clock the circuit for 16 times. Observe the “high” to low transition on PSV_Out .
- Set $\text{PSV_In} = ‘1’$
- Set $I_{\text{In}0}$ through $I_{\text{In}7}$ and $Q_{\text{In}0}$ through $Q_{\text{In}7}$ to desired value. Clock the circuit. Repeat for all possible input values. (To apply all possible inputs it is very helpful to use Stimulator \rightarrow Clock.)
- Set $\text{PSV_In} = ‘0’$, clock the circuit for 16 times to empty the pipeline.
- Document the outputs $\text{Phase_Out}0$ through $\text{Phase_Out}4$ and compare with C++ results.

The comparison between the simulation results and the C++ outputs, accomplished by Prof. Fouts, showed that the phase extractor works correctly. Initialization of the simulation is shown in a waveform editor in Figure 69, while Figure 70 points to the end of the simulation and clearing of the pipeline.

Since inputs range between –128 and 127 for both I and Q values, 65,536 different input combinations were used. Some of the values for comparison are shown in Table 21.

I_Value (DEC)	Q_Value (DEC)	Simulation Result Phase (HEX)	C++ Result Phase (HEX)	I_Value (DEC)	Q_Value (DEC)	Simulation Result Phase (HEX)	C++ Result Phase (HEX)
-128	-128	20	20	0	-128	24	24
-128	-105	19	19	0	-1	24	24
-128	-60	18	18	0	0	0	0
-128	-42	17	17	0	1	8	8
-128	-9	16	16	0	127	8	8
-128	0	16	16	1	-128	24	24
-128	10	15	15	1	0	0	0
-128	43	14	14	1	1	4	4
-128	61	13	13	1	2	5	5
-128	106	12	12	1	3	7	7
-128	127	12	12	1	13	8	8
-127	-128	20	20	1	127	8	8
-127	-105	19	19	127	-128	28	28
-127	-60	18	18	127	-105	29	29
-127	-42	17	17	127	-60	30	30
-127	-9	16	16	127	-42	31	31
-127	10	15	15	127	-9	0	0
-127	43	14	14	127	10	1	1
-127	61	13	13	127	43	2	2
-127	106	12	12	127	61	3	3
-127	127	12	12	127	106	4	4
-100	0	16	16	100	0	0	0
-100	120	12	12	100	120	4	4
-100	121	11	11	100	121	5	5
-99	-128	21	21	101	-128	27	27
-19	-128	23	23	19	-128	25	25
-19	-56	22	22	19	-57	26	26
-19	-40	21	21	19	-40	27	27
-19	0	16	16	19	0	0	0
-19	127	9	9	19	127	7	7

Table 21. Comparison of Simulation Results and C++ Outputs for Phase Extractor

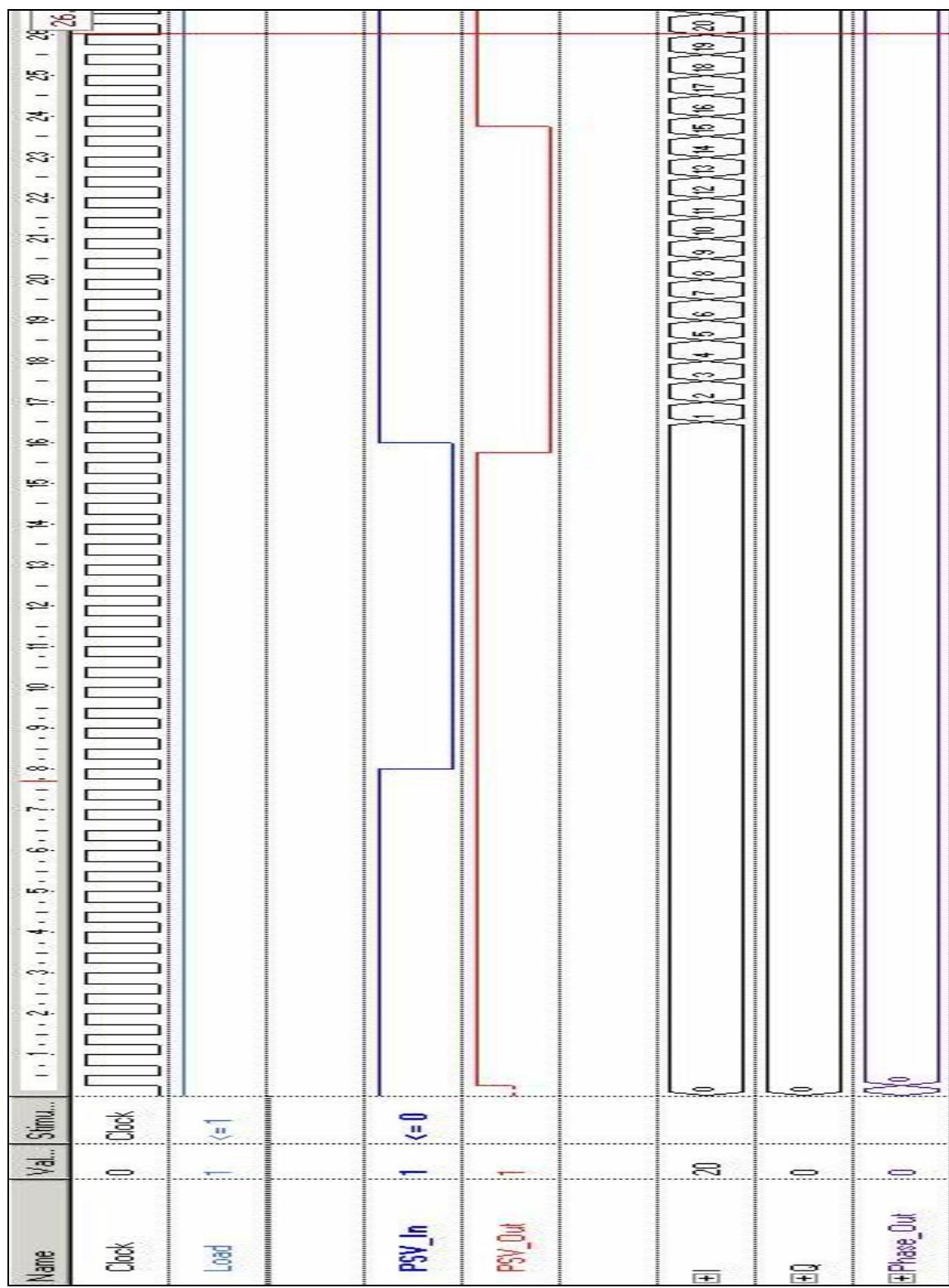


Figure 69. Simulation of Phase Extraction Circuit, Initialization

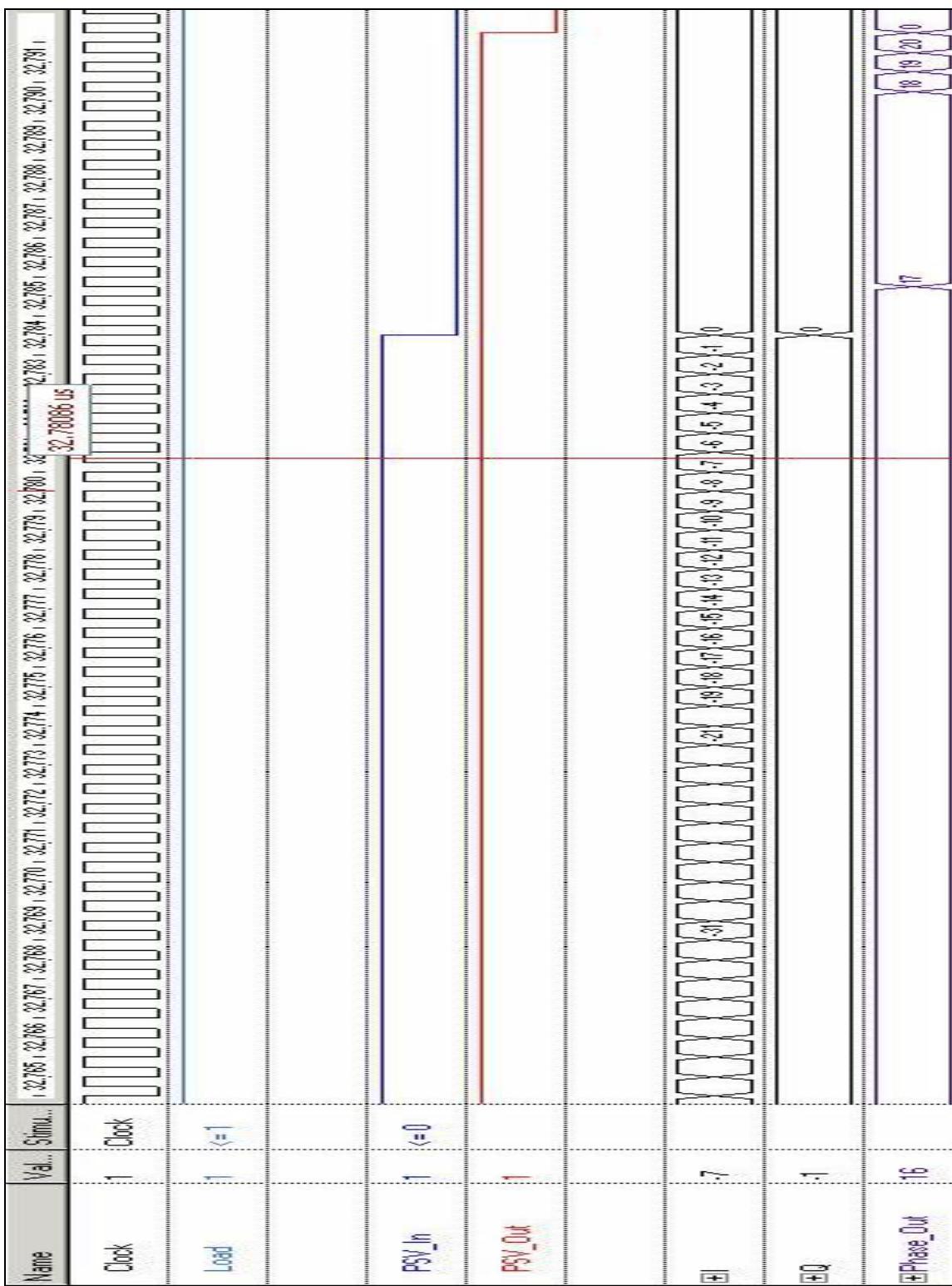


Figure 70. Simulation of Phase Extraction Circuit, Ending

6. Simulation of Path 1 – Off-Chip Phase Sample Values to RBP s

The simulation algorithm for Path 1, the flow from the off chip phase sample values to the four RBP s connected serially, is given below.

- Set Clock_In = Stimulator → Clock → 2ns.
- Set Delay signals inside RBP s ='0'
- Set Clock_Prog_In = '0', URB_In='0'
- Set ODV_In, PRB_In and UNP_In ='0'
- Set I0_0 through I0_5 ='0'
- Set I_In_0 through I_In_15, Q_In_0 through Q_In_15, I_OF_In, Q_OF_In, I0 through I7, Q0 through Q7, I1_0 through I1_5 ='0'
- Set Off_Chip_Count0 through Off_Chip_Count11, I/Q_Valid_In, Off_Chip_4to1MuxSLCT0, Off_Chip_4to1MuxSLCT1, Start_SelfTest ='0'
- Set Off_Chip_Oper/Maint_MuxIO ='1'
- Set Off_Chip_Oper/Maint_MuxSel ='0'
- Clock the DIS for 23 times to clear the pipeline inside RBP s.
- Set PRB_In ='1'
- Set Sel_In0 through Sel_In7 to the desired RBP number; set Gain_In_0 through Gain_In_3 and Phase_In_0 through Phase_In_4 to the proper coefficient values. Clock the DIS once. Repeat for every RBP to be programmed.
- Set PRB = '0', UNP='1', clock the DIS once
- Clock the DIS until ODV_Out becomes “low”
- Set I0_5 ='1' (This input is actually PSV_In to the RBP s after being steered by the 6-bit 4-to-1 multiplexer)
- Set I0_0 through I0_4 to the desired phase sample value. Clock the DIS once. Repeat for every off chip phase sample value.

- Set I0_5='0'
- Clock the DIS for 11 times to empty the pipeline, until ODV_Out becomes “low”
 - Observe MUX_Out0 through MUX_Out5 to verify the inputs are steered into the RBP s from the 6-bit 4-to-1 multiplexer.
 - Observe ODV_Out, I_Out_0 through I_Out_15, Q_Out_0 through Q_Out_15, I_OF_Out and Q_OF_Out.
 - Compare the results with the C++ simulation outputs.

The waveform editor used to simulate the DIS for the first data path is given in Figures 71, 72 and 73, showing initialization, input phase sample values, and the end of the simulation, one after the other.

Table 22 shows the RBP programming coefficients, phase sample input values to the first data path, signal values probed at the output of 6-bit 4-to-1 multiplexer and outputs of the DIS.

7. Simulation of Path 2 – Off-Chip Phase Sample Alternate Path

The simulation algorithm for Path 2, the flow from the alternate off chip phase sample values to the four RBP s connected serially, is very similar to the simulation of Path 1 and is given below.

- Set Clock_In = Stimulator → Clock → 2ns.
- Set Delay signals inside RBP s ='0'
- Set Clock_Prog_In = '0', URB_In='0'
- Set ODV_In, PRB_In and UNP_In ='0'
- Set I1_0 through I1_5 ='0'
- Set I_In_0 through I_In_15, Q_In_0 through Q_In_15, I_OF_In, Q_OF_In, I0 through I7, Q0 through Q7, I0_0 through I0_5 ='0'

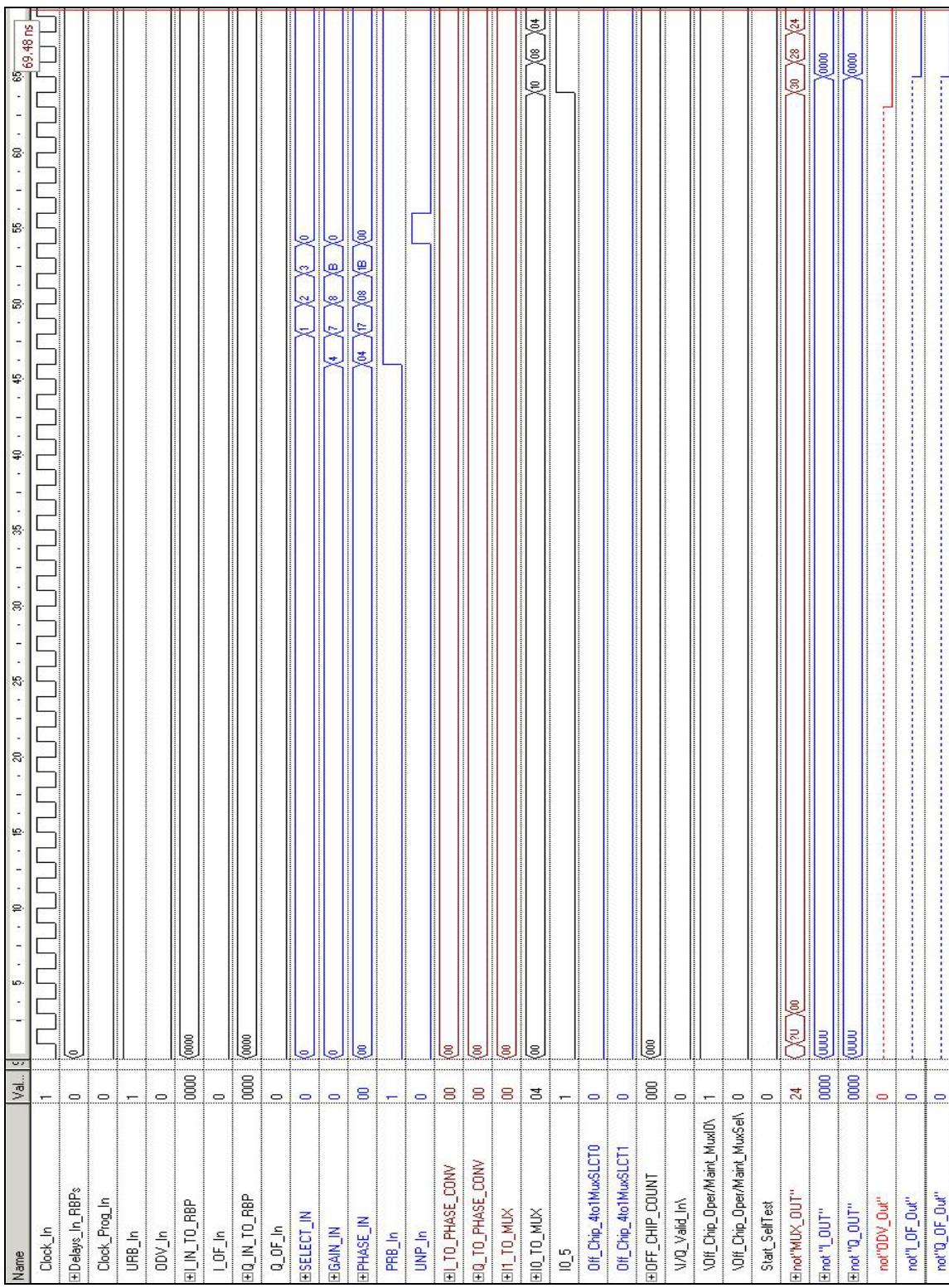


Figure 71. Simulation of the DIS – Path 1, Initialization

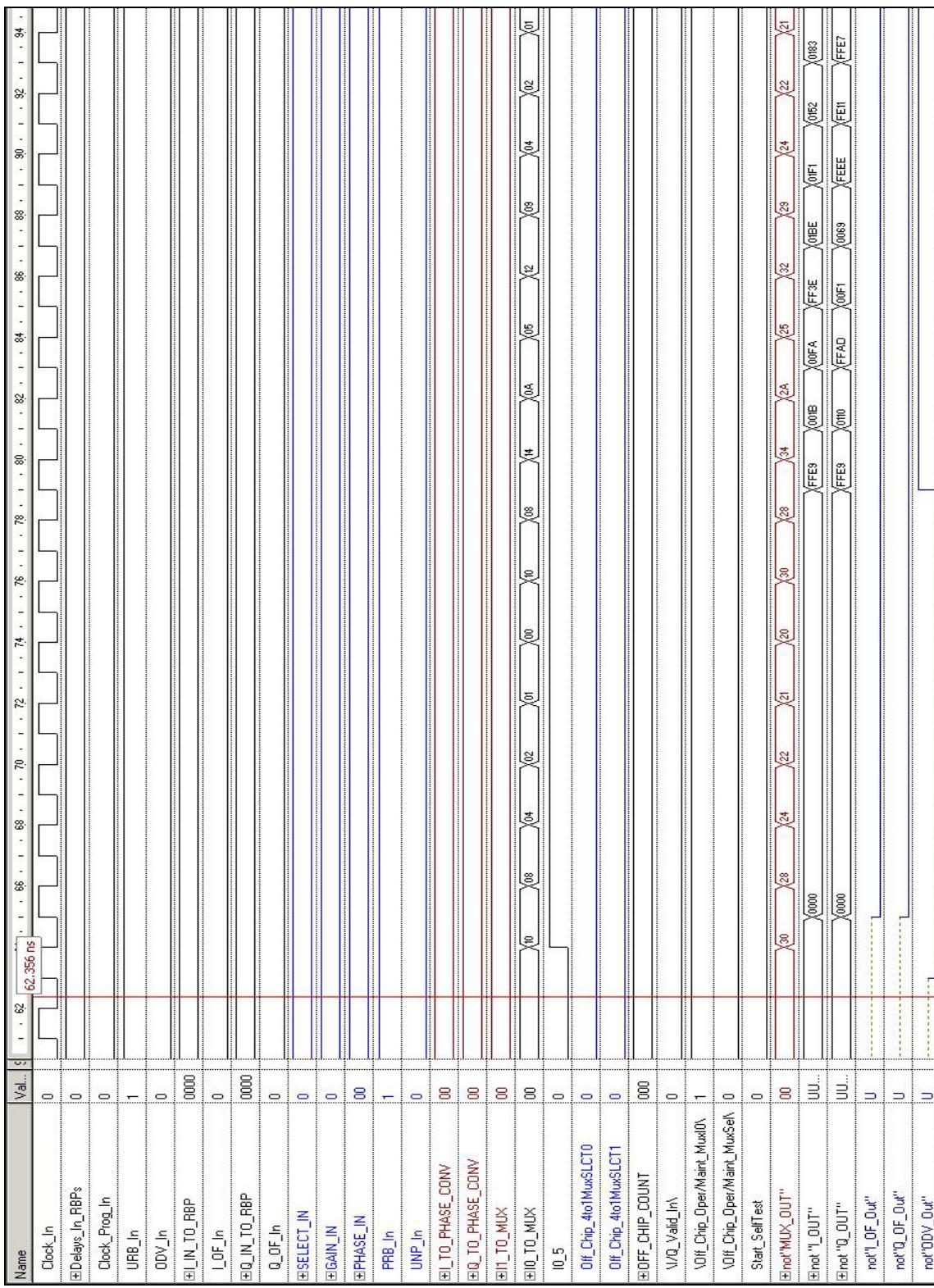


Figure 72.

Simulation of the DIS – Path 1, Inputting Phase Samples

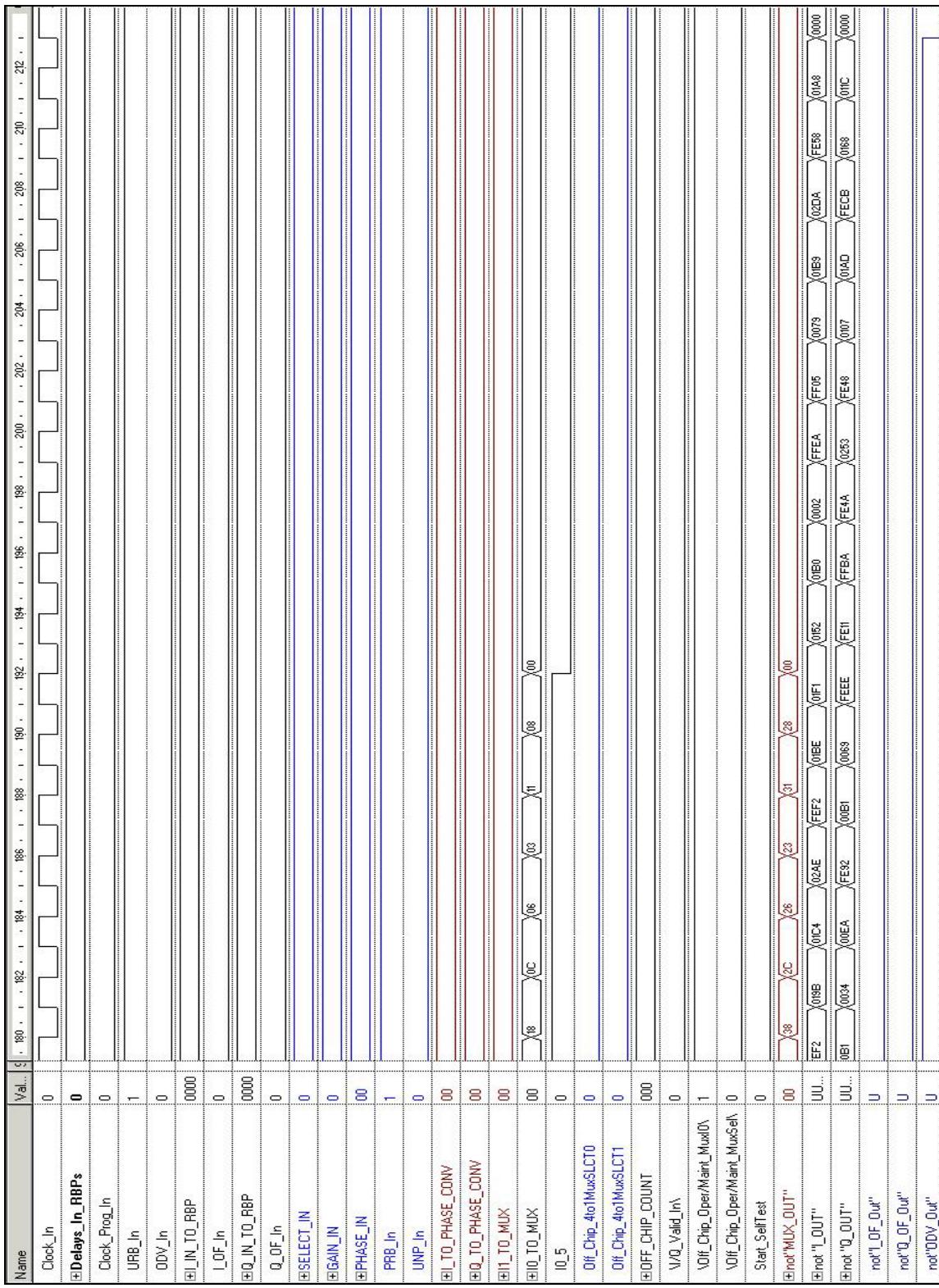


Figure 73.

Simulation of the DIS – Path 1, Ending

I0 Phase Samples (Hex)	Simulation Results					C++ Outputs				
	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)
0A	0A	FD25	FFD8	0	0	0A	FD25	FFD8	0	0
05	05	01EC	0201	0	0	05	01EC	0201	0	0
02	02	FE89	FF50	0	0	02	FE89	FF50	0	0
11	11	0107	00B6	0	0	11	0107	00B6	0	0
18	18	01F9	0121	0	0	18	01F9	0121	0	0
0C	0C	009A	FED7	0	0	0C	009A	FED7	0	0
06	06	FF9E	0213	0	0	06	FF9E	0213	0	0
03	03	FF05	FE48	0	0	03	FF05	FE48	0	0
11	11	0079	0107	0	0	11	0079	0107	0	0
08	08	01B9	01AD	0	0	08	01B9	01AD	0	0
04	04	02DA	FEEA	0	0	04	02DA	FEEA	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	019B	0034	0	0	-	019B	0034	0	0
-	-	01C4	00EA	0	0	-	01C4	00EA	0	0
-	-	02AE	FE92	0	0	-	02AE	FE92	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	01BE	0069	0	0	-	01BE	0069	0	0
-	-	01F1	FEEE	0	0	-	01F1	FEEE	0	0
-	-	0152	FE11	0	0	-	0152	FE11	0	0
-	-	01B0	FFBA	0	0	-	01B0	FFBA	0	0
-	-	0002	FE4A	0	0	-	0002	FE4A	0	0
-	-	FFEA	0253	0	0	-	FFEA	0253	0	0
-	-	FF05	FE48	0	0	-	FF05	FE48	0	0
-	-	0079	0107	0	0	-	0079	0107	0	0
-	-	01B9	01AD	0	0	-	01B9	01AD	0	0
-	-	02DA	FECB	0	0	-	02DA	FECB	0	0
-	-	FE58	0168	0	0	-	FE58	0168	0	0
-	-	01A8	011C	0	0	-	01A8	011C	0	0

Comparison of Simulation Results and C++ Outputs for Path 1, Continued

- Set Off_Chip_Count0 through Off_Chip_Count11, I/Q_Valid_In, Set Off_Chip_4to1MuxSLCT1, Start_SelfTest ='0'
- Set Off_Chip_4to1MuxSLCT0 = '1'
- Set Off_Chip_Oper/Maint_MuxIO ='1'
- Set Off_Chip_Oper/Maint_MuxSel ='0'
- Clock the DIS for 23 times to clear the pipeline inside RBP s.
- Set PRB_In ='1'

- Set Sel_In0 through Sel_In7 to the desired RBP number; set Gain_In_0 through Gain_In_3 and Phase_In_0 through Phase_In_4 to the proper coefficient values. Clock the DIS once. Repeat for every RBP to be programmed.
- Set PRB = ‘0’, UNP=’1’, clock the DIS once
- Clock the DIS until ODV_Out becomes “low”
- Set I1_5 =’1’ (This input is actually PSV_In to the RBP s after being steered by the 6-bit 4-to-1 multiplexer)
 - Set I1_0 through I1_4 to the desired phase sample value. Clock the DIS once. Repeat for every off chip phase sample value.
 - Set I1_5=’0’
 - Clock the DIS for 11 times to empty the pipeline, until ODV_Out becomes “low”
 - Observe MUX_Out0 through MUX_Out5 to verify the inputs are steered into the RBP s from the 6-bit 4-to-1 multiplexer.
 - Observe ODV_Out, I_Out_0 through I_Out_15, Q_Out_0 through Q_Out_15, I_OF_Out and Q_OF_Out.
 - Compare the results with the C++ simulation outputs.

The waveform editor used to simulate the DIS for the second data path is given in Figures 74, 75 and 76, showing initialization, input phase sample values and the end of simulation, one after the other.

Table 23 shows the RBP programming coefficients, phase sample input values to the second data path, signal values probed at the output of 6-bit 4-to-1 multiplexer and outputs of the DIS.

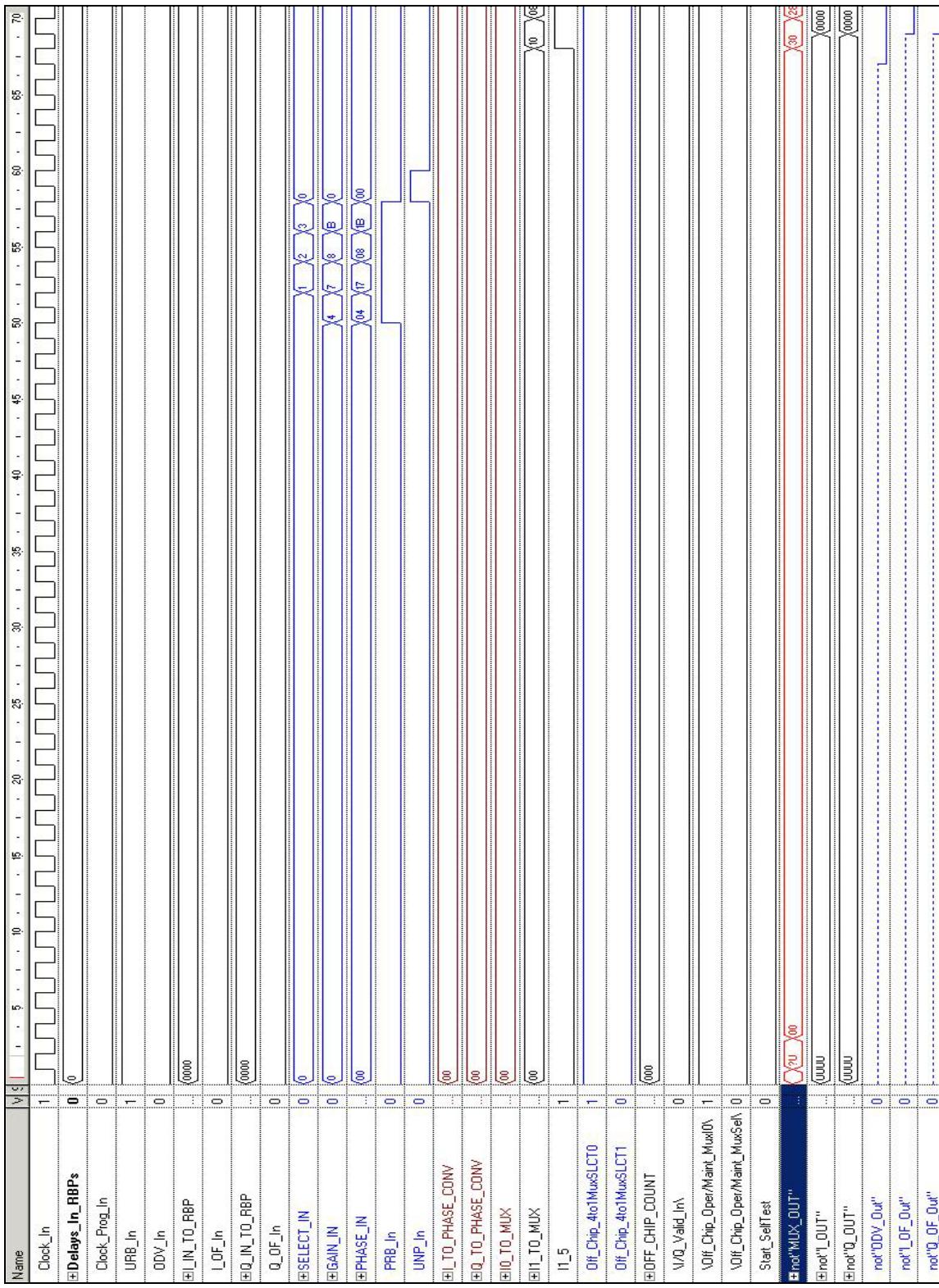


Figure 74. Simulation of the DIS – Path 2, Initialization

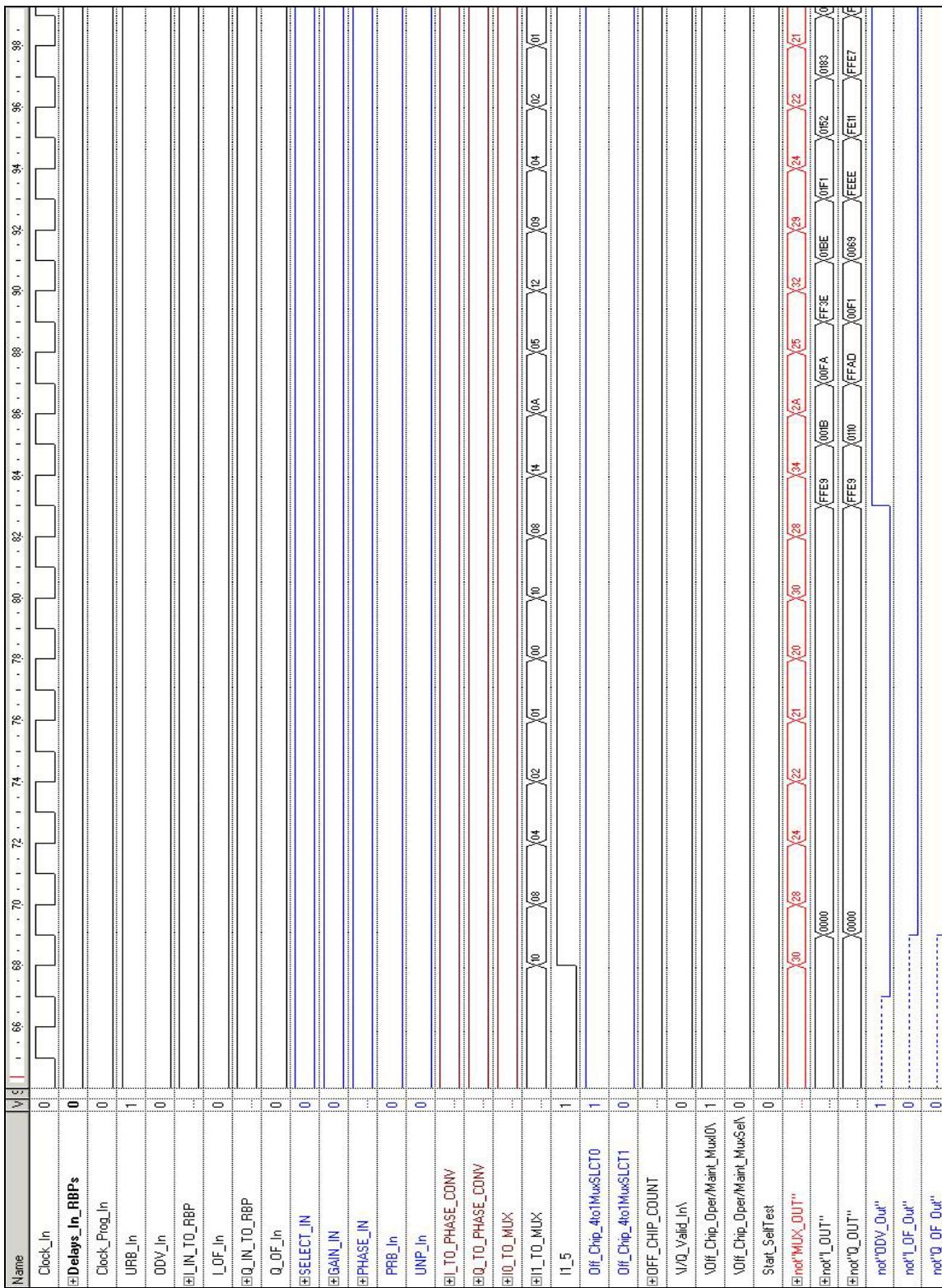


Figure 75. Simulation of the DIS – Path 2, Inputting Phase Samples

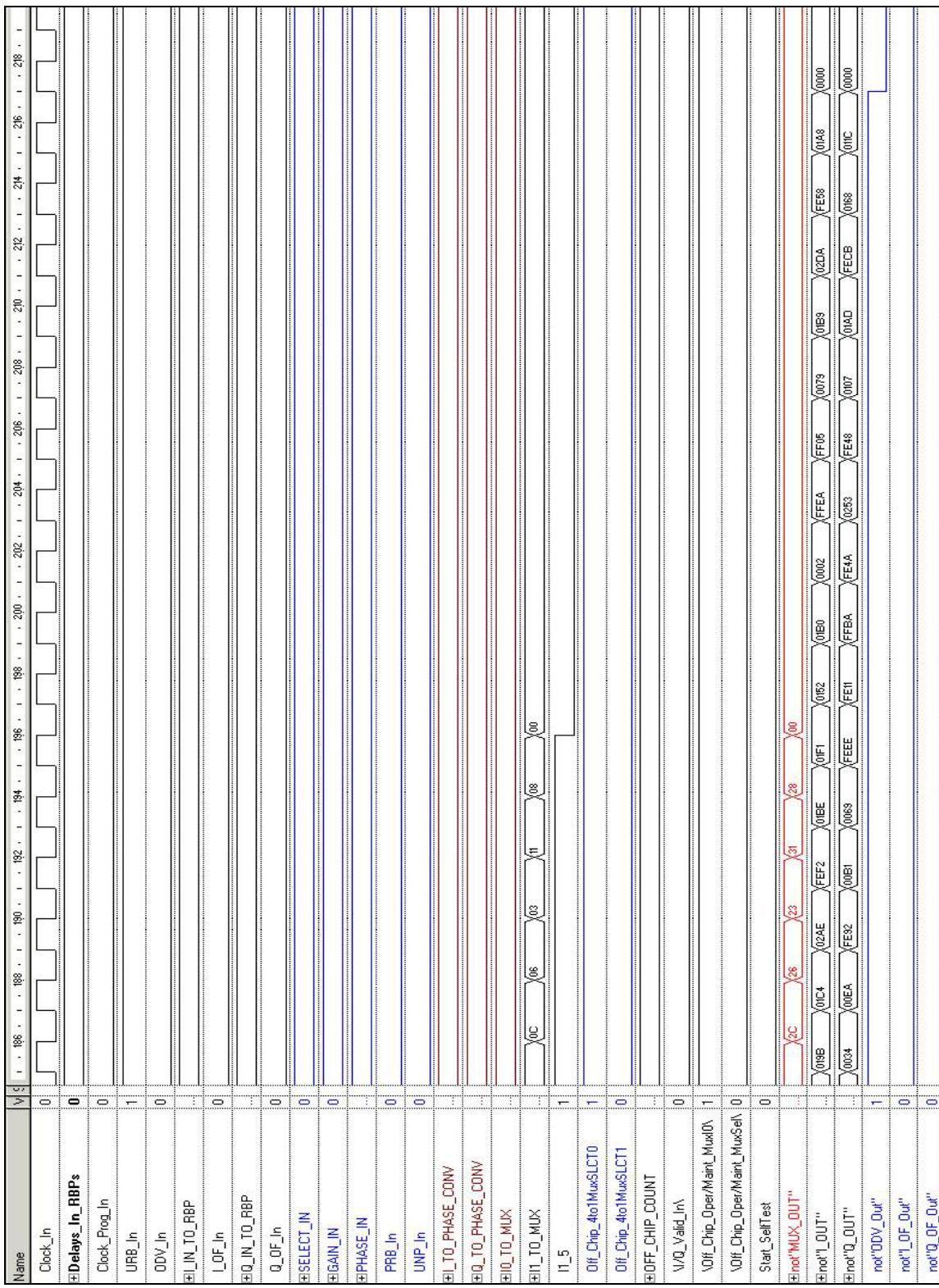


Figure 76.

Simulation of the DIS – Path 2, Ending

I1 Phase Samples (Hex)	Simulation Results					C++ Outputs				
	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)
05	05	01EC	0201	0	0	05	01EC	0201	0	0
02	02	FE89	FF50	0	0	02	FE89	FF50	0	0
11	11	0107	00B6	0	0	11	0107	00B6	0	0
18	18	01F9	0121	0	0	18	01F9	0121	0	0
0C	0C	009A	FED7	0	0	0C	009A	FED7	0	0
06	06	FF9E	0213	0	0	06	FF9E	0213	0	0
03	03	FF05	FE48	0	0	03	FF05	FE48	0	0
11	11	0079	0107	0	0	11	0079	0107	0	0
08	08	01B9	01AD	0	0	08	01B9	01AD	0	0
04	04	02DA	FEEA	0	0	04	02DA	FEEA	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	019B	0034	0	0	-	019B	0034	0	0
-	-	01C4	00EA	0	0	-	01C4	00EA	0	0
-	-	02AE	FE92	0	0	-	02AE	FE92	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	01BE	0069	0	0	-	01BE	0069	0	0
-	-	01F1	FEEE	0	0	-	01F1	FEEE	0	0
-	-	0152	FE11	0	0	-	0152	FE11	0	0
-	-	01B0	FFBA	0	0	-	01B0	FFBA	0	0
-	-	0002	FE4A	0	0	-	0002	FE4A	0	0
-	-	FFEA	0253	0	0	-	FFEA	0253	0	0
-	-	FF05	FE48	0	0	-	FF05	FE48	0	0
-	-	0079	0107	0	0	-	0079	0107	0	0
-	-	01B9	01AD	0	0	-	01B9	01AD	0	0
-	-	02DA	FECB	0	0	-	02DA	FECB	0	0
-	-	FE58	0168	0	0	-	FE58	0168	0	0
-	-	01A8	011C	0	0	-	01A8	011C	0	0

Comparison of Simulation Results and C++ Outputs for Path 2, Continued

8. Simulation of Path 3 - Self Test Logic Circuit to RBP s

The simulation algorithm for Path 3, the flow from the self test logic circuit phase sample test vectors to the four RBP s connected serially, is given below.

- Set Clock_In = Stimulator → Clock → 2ns.
- Set Delay signals inside RBP s ='0'
- Set Clock_Prog_In = '0', URB_In='0'
- Set ODV_In, PRB_In and UNP_In ='0'

- Set I_In_0 through I_In_15, Q_In_0 through Q_In_15, I_OF_In, Q_OF_In, I0 through I7, Q0 through Q7, I1_0 through I1_5 and I0_0 through I0_5 = '0'
- Set Off_Chip_Count0 through Off_Chip_Count11 = To the desired number of test vectors to be generated, in this simulation it is 64.
 - Set I/Q_Valid_In = '0'
 - Set Start_SelfTest = '0'
 - Set Off_Chip_4to1MuxSLCT0 = '0'
 - Set Off_Chip_4to1MuxSLCT1 = '1'
 - Set Off_Chip_Oper/Maint_MuxIO = '0'
 - Set Off_Chip_Oper/Maint_MuxSel = '1'
 - Clock the DIS for 23 times to clear the pipeline inside the RBP s.
 - Set PRB_In = '1'
 - Set Sel_In0 through Sel_In7 to the desired RBP number; set Gain_In_0 through Gain_In_3 and Phase_In_0 through Phase_In_4 to the proper coefficient values. Clock the DIS once. Repeat for every RBP to be programmed.
 - Set PRB = '0', UNP = '1', clock the DIS once
 - Set Start_SelfTest = '1'
 - Clock the DIS for as many as the number of the test vectors, until the I_Out and Q_Out values “freeze”
 - Observe MUX_Out0 through MUX_Out5 to verify the inputs are steered into the RBP s from the 6-bit 4-to-1 multiplexer.
 - Observe ODV_Out, I_Out_0 through I_Out_15, Q_Out_0 through Q_Out_15, I_OF_Out and Q_OF_Out.
 - Compare the results with the C++ simulation outputs.

Table 24 shows the RBP programming coefficients, phase sample input values to the first data path, signal values probed at the output of 6-bit 4-to-1 multiplexer and outputs of the DIS.

The waveform editor used to simulate the DIS for the first data path is given in Figures 77 and 78, showing initialization and the end of simulation, respectively.

RBP		0		1		2		3		
Gain\Hex)		04		07		08		0B		
PInc(Hex)		04		17		08		1B		
		Simulation Results					C++ Outputs			
Self Test Outputs (Hex)	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)
10	10	FFE9	FFE9	0	0	10	FFE9	FFE9	0	0
08	08	001B	0110	0	0	08	001B	0110	0	0
04	04	00FA	FFAD	0	0	04	00FA	FFAD	0	0
02	02	FF3E	00F1	0	0	02	FF3E	00F1	0	0
01	01	01BE	0069	0	0	01	01BE	0069	0	0
00	00	01F1	FEEE	0	0	00	01F1	FEEE	0	0
10	10	0152	FE11	0	0	10	0152	FE11	0	0
08	08	0183	FFE7	0	0	08	0183	FFE7	0	0
14	14	0216	FDC6	0	0	14	0216	FDC6	0	0
0A	0A	FDF8	0288	0	0	0A	FDF8	0288	0	0
05	05	02C8	0140	0	0	05	02C8	0140	0	0
12	12	FE78	FF79	0	0	12	FE78	FF79	0	0
09	09	009A	02D6	0	0	09	009A	02D6	0	0
04	04	0312	FFE4	0	0	04	0312	FFE4	0	0
02	02	FEB3	0058	0	0	02	FEB3	0058	0	0
01	01	017E	00B5	0	0	01	017E	00B5	0	0
10	10	01C4	FEC1	0	0	10	01C4	FEC1	0	0
08	08	01B6	0032	0	0	08	01B6	0032	0	0
14	14	0262	FE06	0	0	14	0262	FE06	0	0
0A	0A	FDF8	0288	0	0	0A	FDF8	0288	0	0
15	15	02D5	0101	0	0	15	02D5	0101	0	0
0A	0A	FCFF	010B	0	0	0A	FCFF	010B	0	0
05	05	0244	01D5	0	0	05	0244	01D5	0	0
12	12	FE70	FF15	0	0	12	FE70	FF15	0	0
09	09	009A	02D6	0	0	09	009A	02D6	0	0
04	04	0312	FFE4	0	0	04	0312	FFE4	0	0
02	02	FEB3	0058	0	0	02	FEB3	0058	0	0

Table 24. Comparison of Simulation Results and C++ Outputs for Path 3

Self Test Outputs (Hex)	Simulation Results					C++ Outputs				
	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out (Hex)	Q_OF_Out (Hex)
11	11	015B	0080	0	0	11	015B	0080	0	0
08	08	01C4	00EA	0	0	08	01C4	00EA	0	0
04	04	02AE	FE92	0	0	04	02AE	FE92	0	0
12	12	FED9	0076	0	0	12	FED9	0076	0	0
09	09	012E	0254	0	0	09	012E	0254	0	0
14	14	030A	FF41	0	0	14	030A	FF41	0	0
1A	1A	FDA8	01D6	0	0	1A	FDA8	01D6	0	0
1D	1D	00BA	010F	0	0	1D	00BA	010F	0	0
0E	0E	FD74	FFBB	0	0	0E	FD74	FFBB	0	0
17	17	FFA6	FF46	0	0	17	FFA6	FF46	0	0
0B	0B	FEDD	FE31	0	0	0B	FEDD	FE31	0	0
15	15	00CA	0229	0	0	15	00CA	0229	0	0
0A	0A	FD25	FFD8	0	0	0A	FD25	FFD8	0	0
05	05	01EC	0201	0	0	05	01EC	0201	0	0
02	02	FE89	FF50	0	0	02	FE89	FF50	0	0
11	11	0107	00B6	0	0	11	0107	00B6	0	0
18	18	01F9	0121	0	0	18	01F9	0121	0	0
0C	0C	009A	FED7	0	0	0C	009A	FED7	0	0
06	06	FF9E	0213	0	0	06	FF9E	0213	0	0
03	03	FF05	FE48	0	0	03	FF05	FE48	0	0
11	11	0079	0107	0	0	11	0079	0107	0	0
08	08	01B9	01AD	0	0	08	01B9	01AD	0	0
04	04	02DA	FEEA	0	0	04	02DA	FEEA	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	019B	0034	0	0	-	019B	0034	0	0
-	-	01C4	00EA	0	0	-	01C4	00EA	0	0
-	-	02AE	FE92	0	0	-	02AE	FE92	0	0
-	-	FEF2	00B1	0	0	-	FEF2	00B1	0	0
-	-	01BE	0069	0	0	-	01BE	0069	0	0
-	-	01F1	FEEE	0	0	-	01F1	FEEE	0	0
-	-	0152	FE11	0	0	-	0152	FE11	0	0
-	-	01B0	FFBA	0	0	-	01B0	FFBA	0	0
-	-	0002	FE4A	0	0	-	0002	FE4A	0	0
-	-	FFEA	0253	0	0	-	FFEA	0253	0	0

Comparison of Simulation Results and C++ Outputs for Path 3, Continued

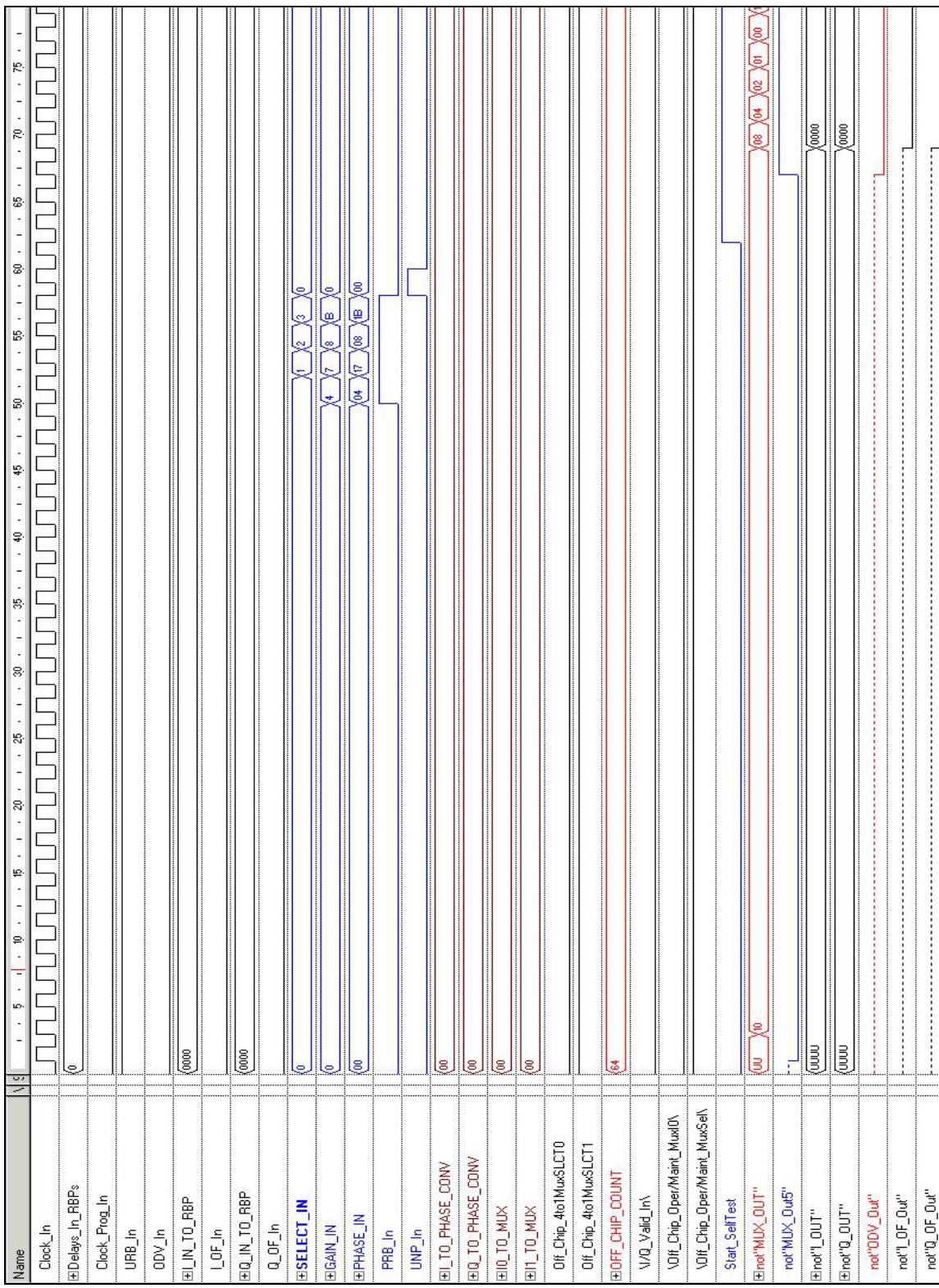


Figure 77. Simulation of the DIS – Path 3, Initialization

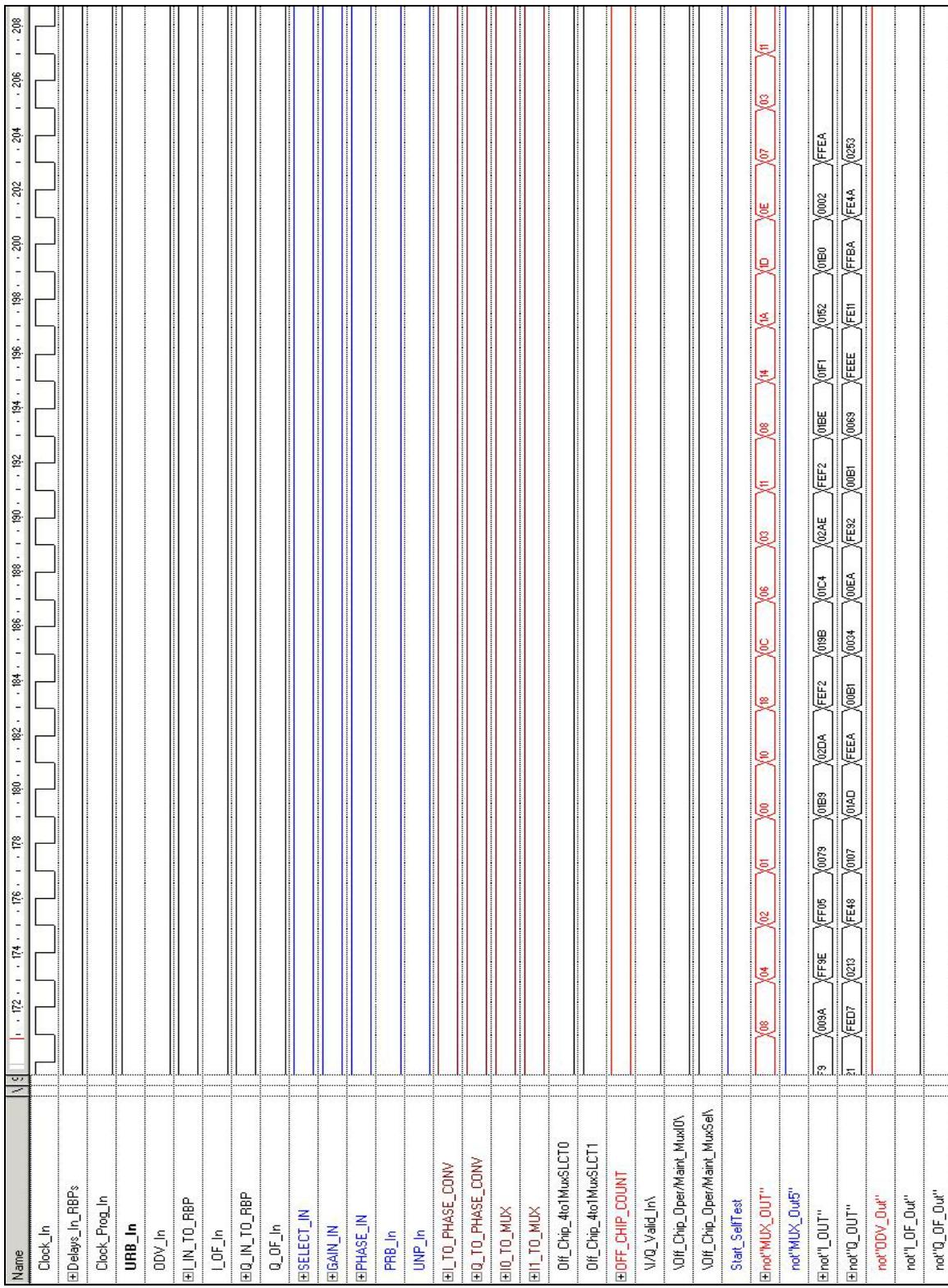


Figure 78.

Simulation of the DIS – Path 3, Ending

9. Simulation of Path 4 - Phase Extraction Circuit to RBP s

The simulation algorithm for Path 4, the flow from the phase extraction circuit to the four RBP s connected serially, is given below.

- Set Clock_In = Stimulator → Clock → 2ns.
- Set Delay signals inside RBP s ='0'
- Set Clock_Prog_In = '0', URB_In='0'
- Set ODV_In, PRB_In and UNP_In ='0'
- Set I_In_0 through I_In_15, Q_In_0 through Q_In_15, I_OF_In, Q_OF_In, I0 through I7, Q0 through Q7, I1_0 through I1_5 and I0_0 through I0_5 ='0'
- Set Off_Chip_Count0 through Off_Chip_Count11 = '0'
- Set I/Q_Valid_In ='0'
- Set Start_SelfTest ='0'
- Set Off_Chip_4to1MuxSLCT0='1'
- Set Off_Chip_4to1MuxSLCT1 ='1'
- Set Off_Chip_Oper/Maint_MuxIO ='1'
- Set Off_Chip_Oper/Maint_MuxSel ='0'
- Clock the DIS for 23 times to clear the pipeline inside the RBP s.
- Set PRB_In ='1'
- Set Sel_In0 through Sel_In7 to the desired RBP number; set Gain_In_0 through Gain_In_3 and Phase_In_0 through Phase_In_4 to the proper coefficient values. Clock the DIS once. Repeat for every RBP to be programmed.

- Set PRB = '0', UNP='1', clock the DIS once
- Clock the DIS until ODV_Out becomes “low”
- Set I/Q_Valid_In ='1'

- Set the I/Q sample value by modifying I0 through I7 and Q0 through Q7. Clock the DIS once. Repeat for every phase sample value.
 - Observe MUX_Out0 through MUX_Out5 to verify the inputs are steered into the RBP s from the 6-bit 4-to-1 multiplexer.
 - Observe ODV_Out, I_Out_0 through I_Out_15, Q_Out_0 through Q_Out_15, I_OF_Out and Q_OF_Out.
 - Compare the results with the C++ simulation outputs.

Table 25 shows the RBP programming coefficients, phase sample input values to the fourth data path, signal values probed at the output of 6-bit 4-to-1 multiplexer and the outputs of the DIS.

The waveform editor used to simulate the DIS for the first data path is given in Figures 79 and 80, showing initialization and the end of simulation, respectively.

RBP	0		1		2		3	
Gain(Hex)	04		07		08		0B	
PInc(Hex)	04		17		08		1B	
		Simulation Results				C++ Outputs		
I values to Phase Extractor	Q values to Phase Extractor	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out	MUX_Out (Hex)	I_Out (Hex)	Q_Out (Hex)
80	FC	FFE9	FFE9	0	0	10	FFE9	FFE9
FF	1F	001B	0110	0	0	08	001B	0110
03	03	00FA	FFAD	0	0	04	00FA	FFAD
06	02	FF3E	00F1	0	0	02	FF3E	00F1
05	01	01BE	0069	0	0	01	01BE	0069
01	00	01F1	FEEE	0	0	00	01F1	FEEE
06	FC	0152	FE11	0	0	10	0152	FE11
80	1F	0183	FFE7	0	0	08	0183	FFE7
FF	FF	0216	FDC6	0	0	14	0216	FDC6
FF	05	FDF8	0288	0	0	0A	FDF8	0288
FE	03	02C8	0140	0	0	05	02C8	0140
02	CC	FE78	FF79	0	0	12	FE78	FF79
80	0D	009A	02D6	0	0	09	009A	02D6
FE	03	0312	FFE4	0	0	04	0312	FFE4
03	02	FEB3	0058	0	0	02	FEB3	0058
06	01	017E	00B5	0	0	01	017E	00B5
05	FC	01C4	FEC1	0	0	10	01C4	FEC1

Table 25. Comparison of Simulation Results and C++ Outputs for Path 4

		Simulation Results					C++ Outputs			
I values to Phase Extractor	Q values to Phase Extractor	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out	MUX Out (Hex)	I_Out (Hex)	Q_Out (Hex)	I_OF_Out	Q_OF_Out
80	1F	01B6	0032	0	0	08	01B6	0032	0	0
FF	FF	0262	FE06	0	0	14	0262	FE06	0	0
FE	05	FDF8	0288	0	0	0A	FDF8	0288	0	0
FE	FD	02D5	0101	0	0	15	02D5	0101	0	0
FE	05	FCFF	010B	0	0	0A	FCFF	010B	0	0
02	03	0244	01D5	0	0	05	0244	01D5	0	0
80	CC	FE70	FF15	0	0	12	FE70	FF15	0	0
FE	0D	009A	02D6	0	0	09	009A	02D6	0	0
03	03	0312	FFE4	0	0	04	0312	FFE4	0	0
06	02	FEB3	0058	0	0	02	FEB3	0058	0	0
FC	FF	015B	0080	0	0	11	015B	0080	0	0
FF	1F	01C4	00EA	0	0	08	01C4	00EA	0	0
03	03	02AE	FE92	0	0	04	02AE	FE92	0	0
80	CC	FED9	0076	0	0	12	FED9	0076	0	0
FE	0D	012E	0254	0	0	09	012E	0254	0	0
FF	FF	030A	FF41	0	0	14	030A	FF41	0	0
06	F3	FDA8	01D6	0	0	1A	FDA8	01D6	0	0
03	FE	00BA	010F	0	0	1D	00BA	010F	0	0
80	33	FD74	FFBB	0	0	0E	FD74	FFBB	0	0
FE	F2	FFA6	FF46	0	0	17	FFA6	FF46	0	0
FE	03	FEDD	FE31	0	0	0B	FEDD	FE31	0	0
FE	FD	00CA	0229	0	0	15	00CA	0229	0	0
FE	05	FD25	FFD8	0	0	0A	FD25	FFD8	0	0
02	03	01EC	0201	0	0	05	01EC	0201	0	0
06	02	FE89	FF50	0	0	02	FE89	FF50	0	0
FC	FF	0107	00B6	0	0	11	0107	00B6	0	0
02	DF	01F9	0121	0	0	18	01F9	0121	0	0
FF	01	009A	FED7	0	0	0C	009A	FED7	0	0
0B	1D	FF9E	0213	0	0	06	FF9E	0213	0	0
03	02	FF05	FE48	0	0	03	FF05	FE48	0	0
FC	FF	0079	0107	0	0	11	0079	0107	0	0
FF	1F	01B9	01AD	0	0	08	01B9	01AD	0	0
03	03	02DA	FEEA	0	0	04	02DA	FEEA	0	0
-	-	FEE6	0094	0	0	-	FEE6	0094	0	0
-	-	017B	0149	0	0	-	017B	0149	0	0
-	-	01F4	FF9C	0	0	-	01F4	FF9C	0	0

Comparison of Simulation Results and C++ Outputs for Path 4, Continued

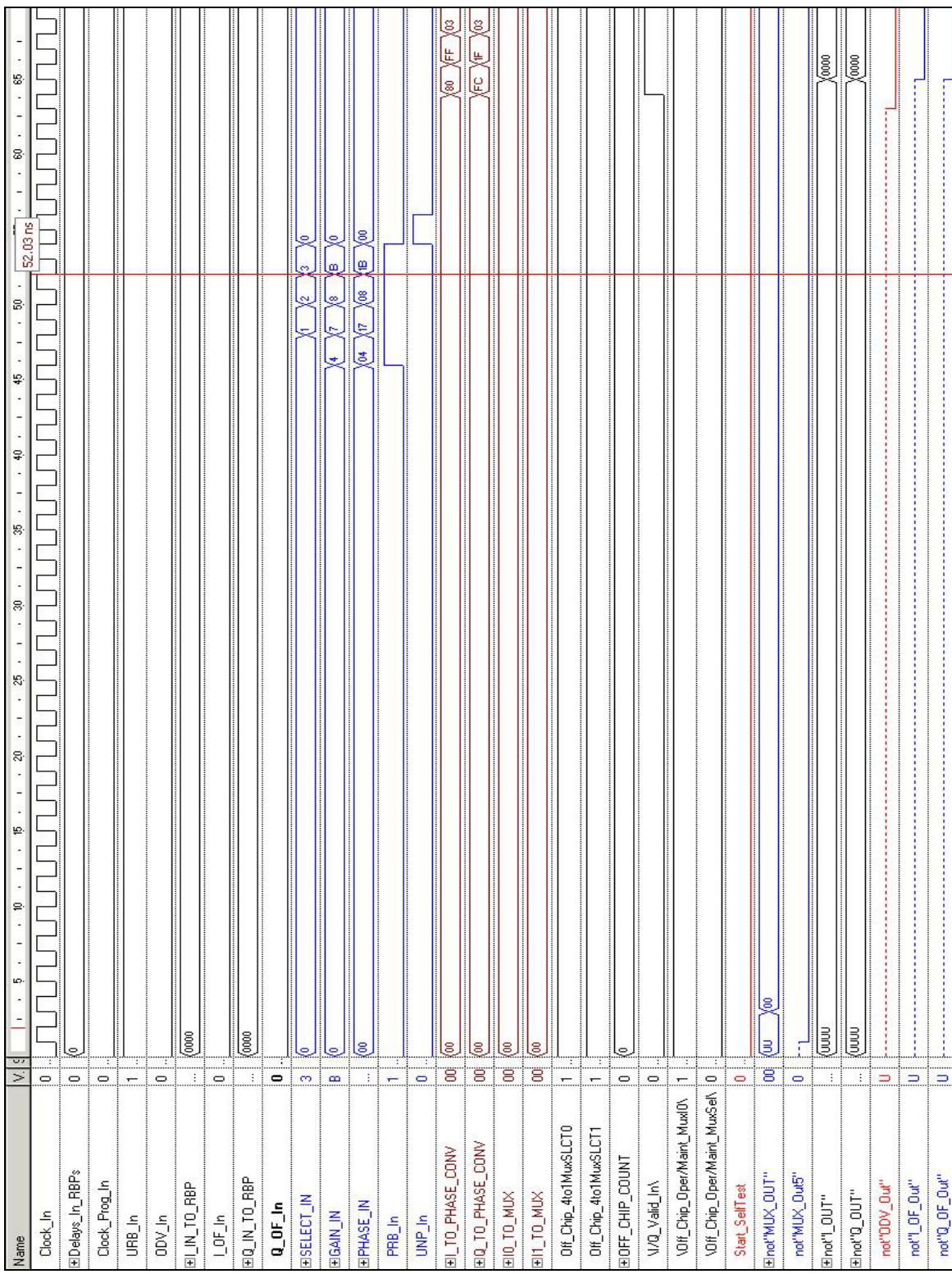


Figure 79. Simulation of the DIS – Path 4, Initialization

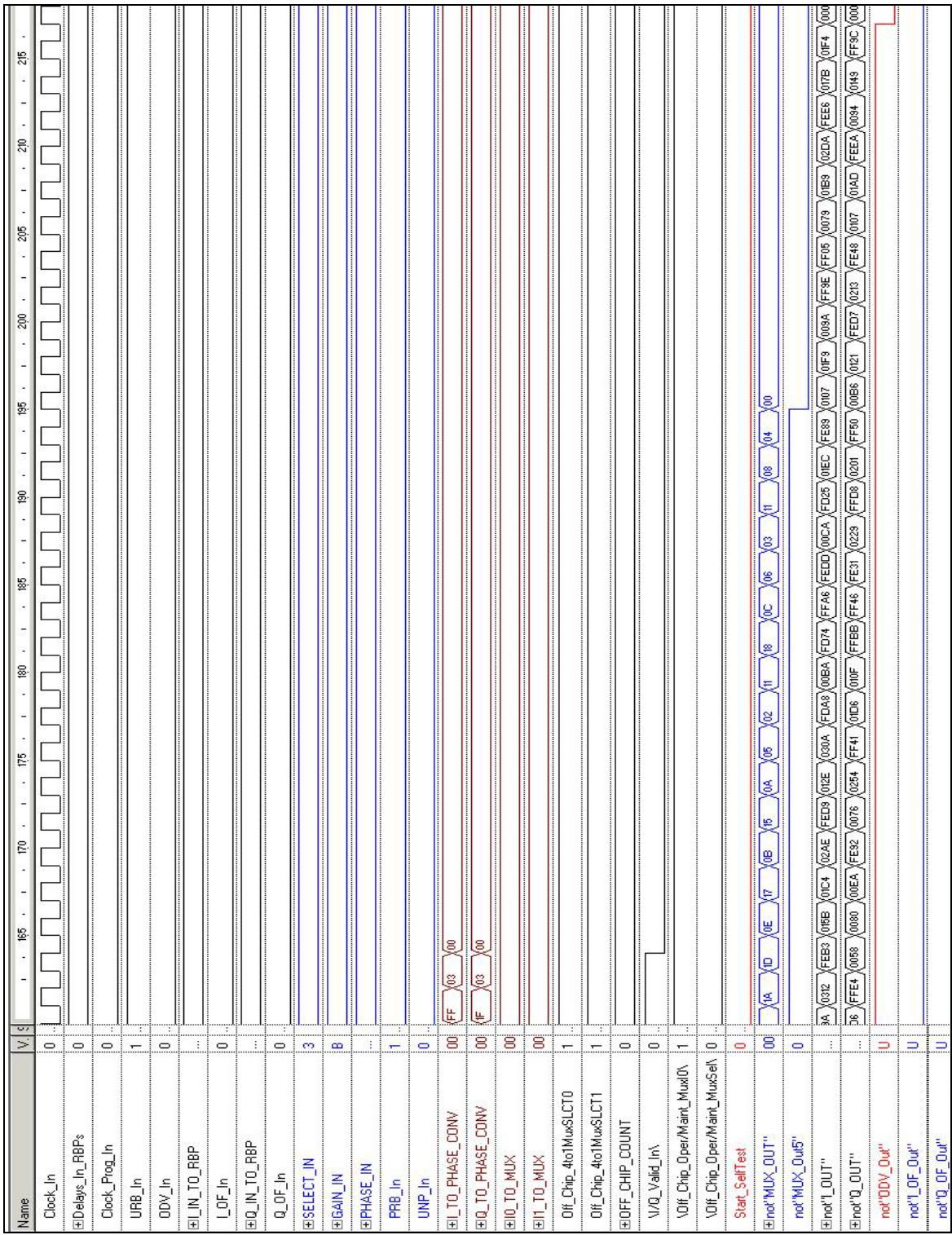


Figure 80.

Simulation of the DIS – Path 4, Ending

Simulations performed in this chapter shows that the DIS operates correctly. Main functional blocks and data paths were tested and verified to operate. Chapter VI provides conclusions about the results obtained during this thesis and summarizes the future research opportunities in the DIS project.

VI. CONCLUSION

A. RESULTS AND CONCLUSION

The main purpose of the research for this thesis was to model, test and verify a Digital Image Synthesizer (DIS) implemented on a full-custom Application Specific Integrated Circuit (ASIC) to counter Inverse Synthetic Aperture Radars (ISARs).

Due to difficulties in other methods of verification for large electronic systems, testing and verification of the system was performed in a hardware description language environment, VHDL. The VHDL code, since it is automatically generated, was not optimum in size. Some problems with the simulation software were encountered. Although the research group tried to address the software defects, even the vendor of the simulation tool was unable to fix the “bugs” in time. This fact hindered testing of the DIS with 512 Range Bin Processors (RBPs). However, since the RBPs are identical, testing and verification of the DIS with 4 RBP s was found a safe method to implement.

Testing and verification efforts were conducted in parallel with the design process. It provided almost instant feedback to the design team and saved time. Furthermore, the testing algorithms for different components were made easier with the help of the design team.

VHDL simulations for low-level components were tested and verified for proper operation. This provided a starting point for larger components and allowed a straightforward testing and verification plan.

Larger components and basic data flow paths in the DIS were confirmed to operate correctly. Some components were defined in their behavioral descriptions.

Finally, functionality of the DIS chip was tested and verified.

B. FUTURE WORK

The 512 RBP s and the control circuitry can be tested if the simulation software is upgraded and fixed to accommodate larger size circuits.

The DIS chip is to be fabricated in the summer of 2003. More functional testing and timing analysis should be conducted on the actual hardware implementation.

The chip should also be tested with the other hardware components such as the Digital Radio Frequency Memory (DRFM).

APPENDIX A – TEST VECTORS

This appendix contains the Phase Sample Value Vectors created by the Self Test Circuit. It can create up to 4095 pseudo-random test sequence to test the DIS. Chapter II has more information about the Self Test Logic, while Chapter V presents the methodology followed to use the Self Test Circuitry with the control inputs.

The table on the subsequent pages gives a complete list of generated test vectors.

| NO / Value |
|------------|------------|------------|------------|------------|------------|------------|------------|
| 3465 0x14 | 3510 0x13 | 3555 0x17 | 3600 0x00 | 3645 0x17 | 3690 0x0E | 3735 0x0F | |
| 3466 0x1A | 3511 0x19 | 3556 0x0B | 3601 0x00 | 3646 0x1B | 3691 0x07 | 3736 0x07 | |
| 3467 0x0D | 3512 0x0C | 3557 0x05 | 3602 0x00 | 3647 0x1D | 3692 0x13 | 3737 0x03 | |
| 3468 0x06 | 3513 0x06 | 3558 0x02 | 3603 0x00 | 3648 0x0E | 3693 0x19 | 3738 0x11 | |
| 3469 0x03 | 3514 0x03 | 3559 0x11 | 3604 0x10 | 3649 0x17 | 3694 0x0C | 3739 0x18 | |
| 3470 0x01 | 3515 0x01 | 3560 0x08 | 3605 0x08 | 3650 0x1B | 3695 0x16 | 3740 0x1C | |
| 3471 0x10 | 3516 0x00 | 3561 0x04 | 3606 0x04 | 3651 0x1D | 3696 0x0B | 3741 0x1E | |
| 3472 0x18 | 3517 0x10 | 3562 0x02 | 3607 0x12 | 3652 0x0E | 3697 0x15 | 3742 0x1F | |
| 3473 0x1C | 3518 0x18 | 3563 0x11 | 3608 0x09 | 3653 0x07 | 3698 0x0A | 3743 0x0F | |
| 3474 0x0E | 3519 0x0C | 3564 0x08 | 3609 0x04 | 3654 0x13 | 3699 0x15 | 3744 0x17 | |
| 3475 0x17 | 3520 0x06 | 3565 0x04 | 3610 0x12 | 3655 0x19 | 3700 0x1A | 3745 0x1B | |
| 3476 0x1B | 3521 0x13 | 3566 0x12 | 3611 0x09 | 3656 0x0C | 3701 0x1D | 3746 0x1D | |
| 3477 0x1D | 3522 0x09 | 3567 0x09 | 3612 0x14 | 3657 0x06 | 3702 0x0E | 3747 0x0E | |
| 3478 0x0E | 3523 0x04 | 3568 0x04 | 3613 0x1A | 3658 0x13 | 3703 0x17 | 3748 0x07 | |
| 3479 0x07 | 3524 0x12 | 3569 0x12 | 3614 0x0D | 3659 0x09 | 3704 0x0B | 3749 0x03 | |
| 3480 0x13 | 3525 0x19 | 3570 0x19 | 3615 0x06 | 3660 0x04 | 3705 0x15 | 3750 0x01 | |
| 3481 0x09 | 3526 0x1C | 3571 0x0C | 3616 0x03 | 3661 0x12 | 3706 0x0A | 3751 0x10 | |
| 3482 0x04 | 3527 0x1E | 3572 0x16 | 3617 0x01 | 3662 0x19 | 3707 0x15 | 3752 0x08 | |
| 3483 0x02 | 3528 0x1F | 3573 0x0B | 3618 0x10 | 3663 0x0C | 3708 0x0A | 3753 0x14 | |
| 3484 0x11 | 3529 0x1F | 3574 0x05 | 3619 0x08 | 3664 0x16 | 3709 0x15 | 3754 0x0A | |
| 3485 0x08 | 3530 0x0F | 3575 0x02 | 3620 0x14 | 3665 0x1B | 3710 0x1A | 3755 0x15 | |
| 3486 0x04 | 3531 0x17 | 3576 0x11 | 3621 0x0A | 3666 0x1D | 3711 0x0D | 3756 0x0A | |
| 3487 0x02 | 3532 0x1B | 3577 0x08 | 3622 0x15 | 3667 0x0E | 3712 0x06 | 3757 0x15 | |
| 3488 0x11 | 3533 0x1D | 3578 0x14 | 3623 0x1A | 3668 0x17 | 3713 0x13 | 3758 0x1A | |
| 3489 0x18 | 3534 0x0E | 3579 0x0A | 3624 0x1D | 3669 0x0B | 3714 0x19 | 3759 0x0D | |
| 3490 0x1C | 3535 0x17 | 3580 0x05 | 3625 0x1E | 3670 0x15 | 3715 0x1C | 3760 0x06 | |
| 3491 0x1E | 3536 0x1B | 3581 0x02 | 3626 0x0F | 3671 0x1A | 3716 0x0E | 3761 0x03 | |
| 3492 0x0F | 3537 0x0D | 3582 0x01 | 3627 0x07 | 3672 0x1D | 3717 0x07 | 3762 0x11 | |
| 3493 0x07 | 3538 0x16 | 3583 0x10 | 3628 0x03 | 3673 0x1E | 3718 0x03 | 3763 0x18 | |
| 3494 0x13 | 3539 0x0B | 3584 0x18 | 3629 0x01 | 3674 0x1F | 3719 0x01 | 3764 0x0C | |
| 3495 0x09 | 3540 0x15 | 3585 0x0C | 3630 0x10 | 3675 0x1F | 3720 0x00 | 3765 0x06 | |
| 3496 0x14 | 3541 0x1A | 3586 0x16 | 3631 0x18 | 3676 0x0F | 3721 0x00 | 3766 0x03 | |
| 3497 0x0A | 3542 0x0D | 3587 0x1B | 3632 0x0C | 3677 0x17 | 3722 0x00 | 3767 0x11 | |
| 3498 0x15 | 3543 0x16 | 3588 0x1D | 3633 0x06 | 3678 0x1B | 3723 0x10 | 3768 0x08 | |
| 3499 0x0A | 3544 0x0B | 3589 0x0E | 3634 0x03 | 3679 0x1D | 3724 0x18 | 3769 0x14 | |
| 3500 0x15 | 3545 0x15 | 3590 0x07 | 3635 0x01 | 3680 0x1E | 3725 0x0C | 3770 0x0A | |
| 3501 0x0A | 3546 0x1A | 3591 0x13 | 3636 0x10 | 3681 0x1F | 3726 0x06 | 3771 0x15 | |
| 3502 0x05 | 3547 0x1D | 3592 0x09 | 3637 0x08 | 3682 0x1F | 3727 0x13 | 3772 0x0A | |
| 3503 0x12 | 3548 0x0E | 3593 0x14 | 3638 0x14 | 3683 0x0F | 3728 0x09 | 3773 0x05 | |
| 3504 0x09 | 3549 0x17 | 3594 0x1A | 3639 0x1A | 3684 0x17 | 3729 0x14 | 3774 0x02 | |
| 3505 0x14 | 3550 0x1B | 3595 0x1D | 3640 0x0D | 3685 0x0B | 3730 0x1A | 3775 0x11 | |
| 3506 0x1A | 3551 0x1D | 3596 0x0E | 3641 0x16 | 3686 0x05 | 3731 0x1D | 3776 0x08 | |
| 3507 0x1D | 3552 0x1E | 3597 0x07 | 3642 0x1B | 3687 0x12 | 3732 0x1E | 3777 0x04 | |
| 3508 0x0E | 3553 0x1F | 3598 0x03 | 3643 0x1D | 3688 0x19 | 3733 0x1F | 3778 0x12 | |
| 3509 0x07 | 3554 0x0F | 3599 0x01 | 3644 0x0E | 3689 0x1C | 3734 0x1F | 3779 0x09 | |

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